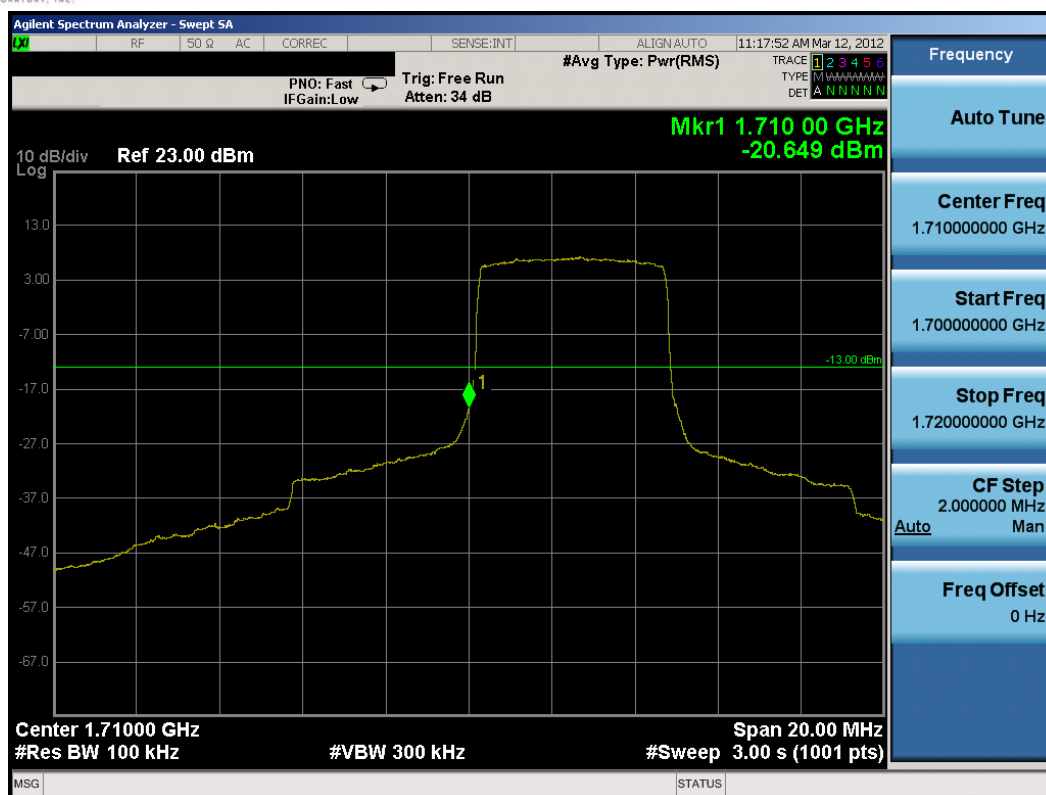
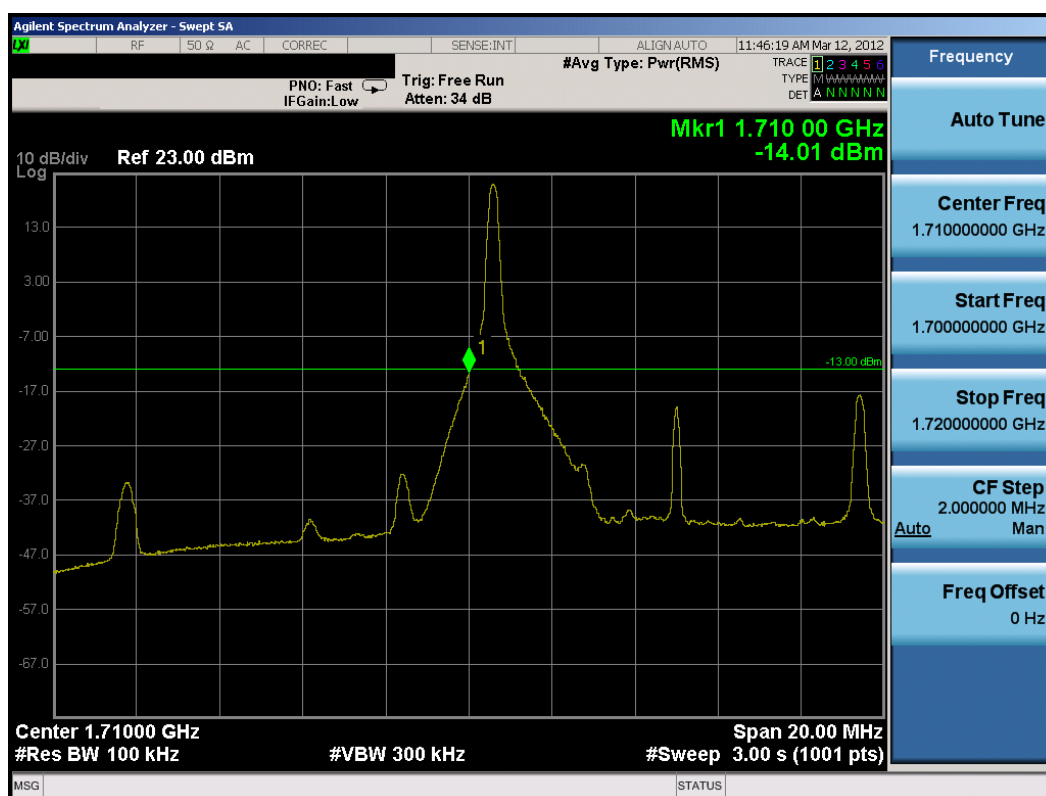


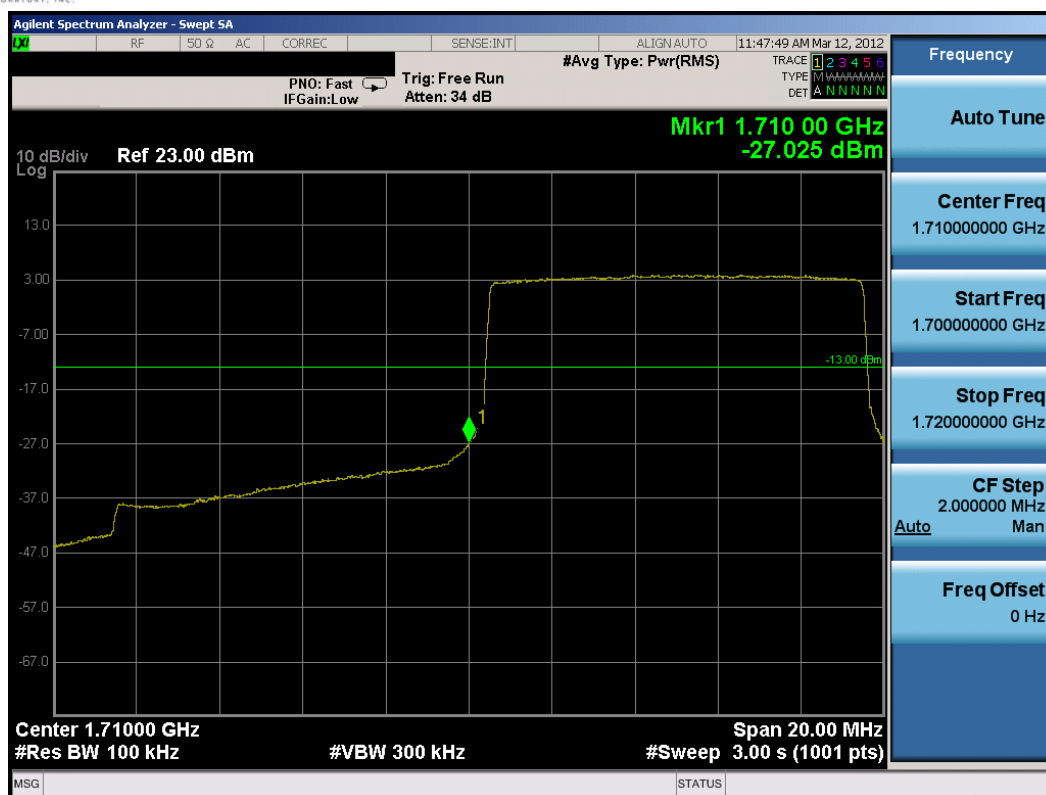


Plot 9-2. Lower Band Edge Plot (5MHz QPSK – RB Size 25, Offset 0)

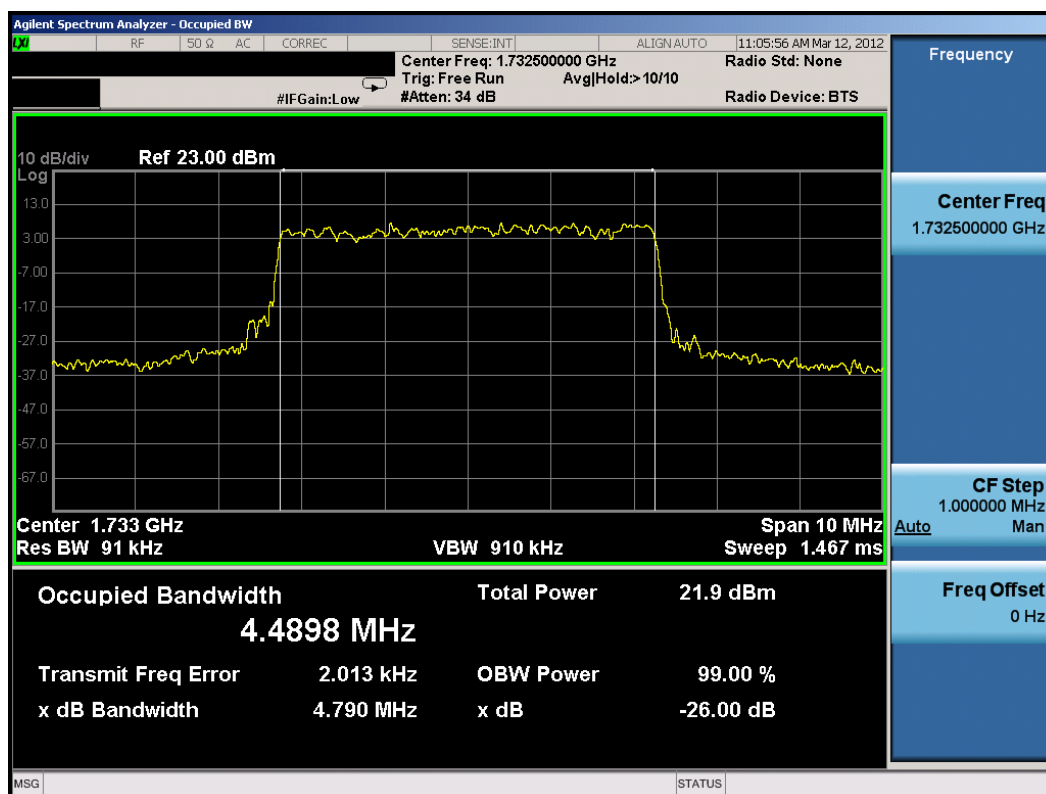


Plot 9-3. Lower Band Edge Plot (10MHz QPSK – RB Size 1, Offset 0)

FCC ID: A3LSCHI405U	 FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION) 		Reviewed by: Quality Manager
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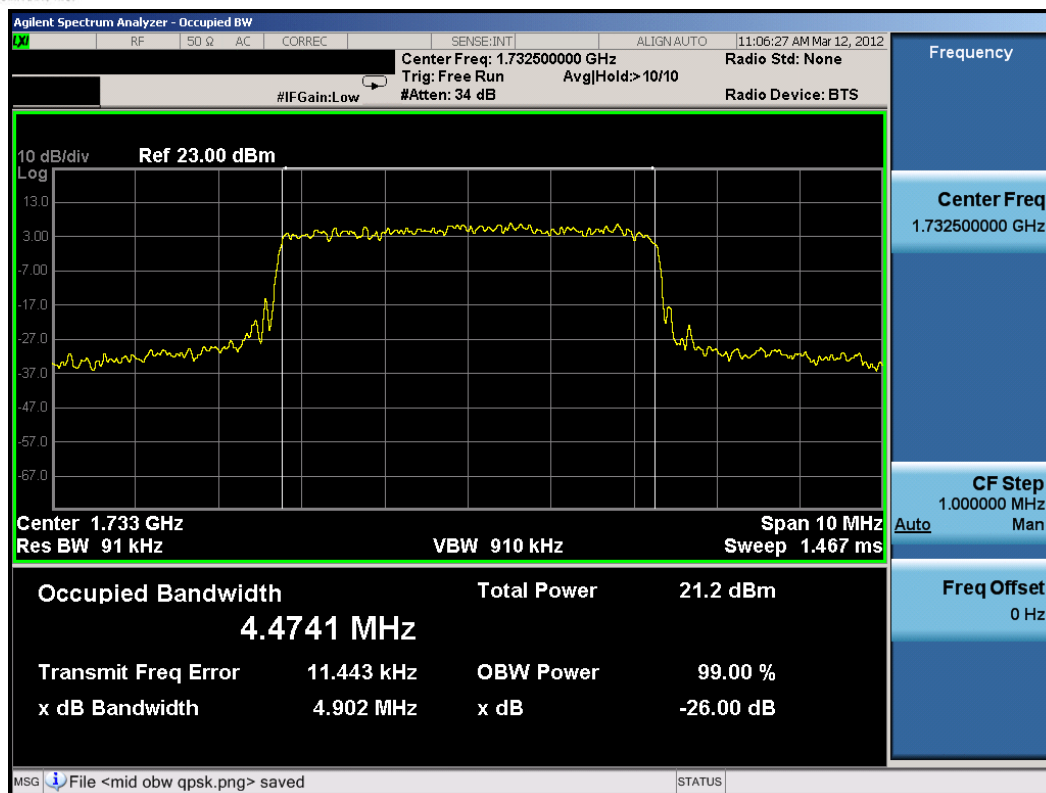


Plot 9-4. Lower Band Edge Plot (10MHz QPSK – RB Size 50, Offset 0)

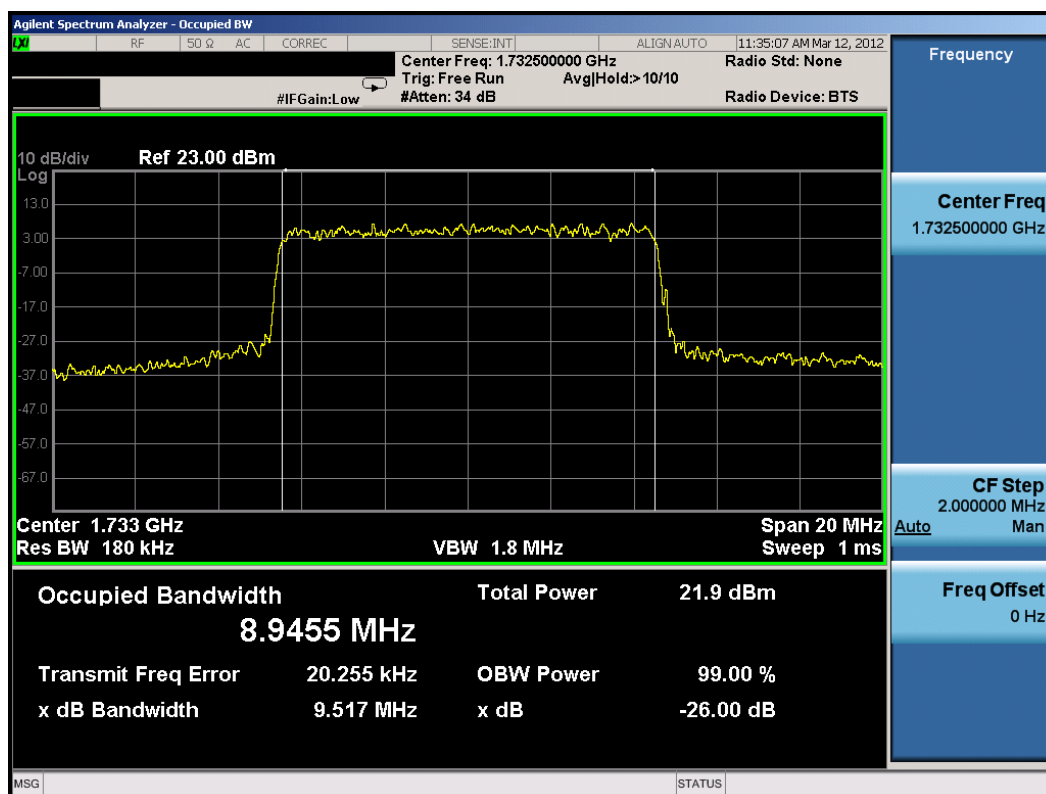


Plot 9-5. Occupied Bandwidth Plot (5MHz QPSK – RB Size 25)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 87 of 134

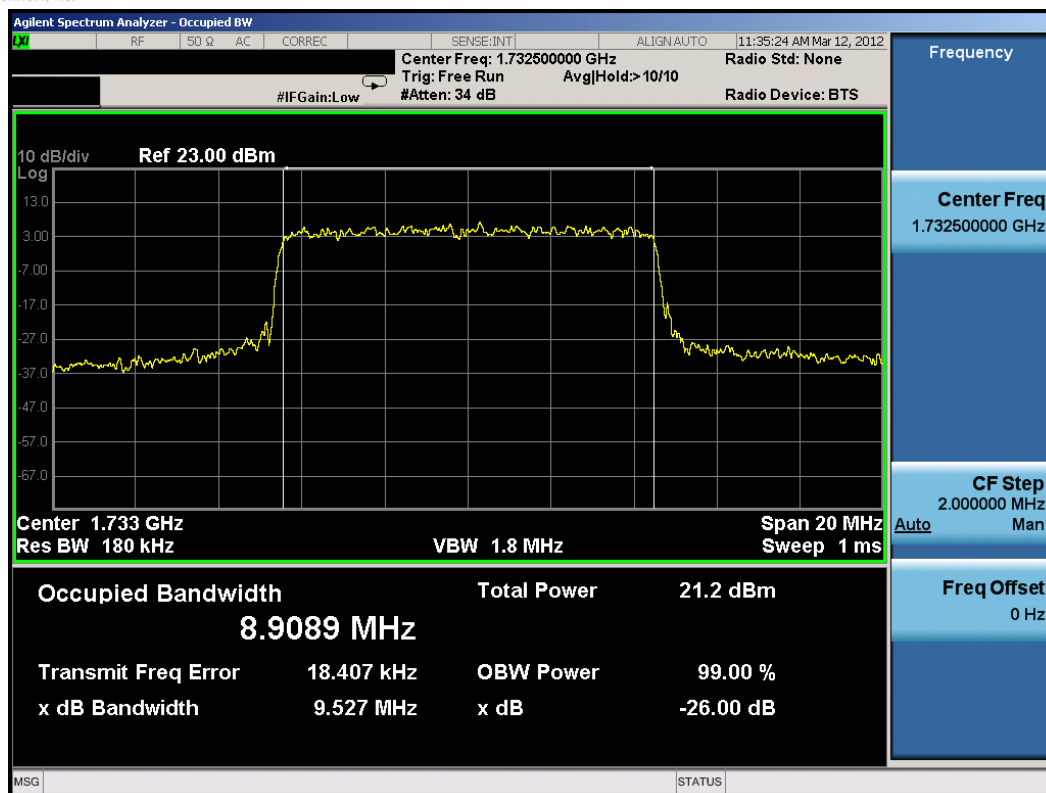


Plot 9-6. Occupied Bandwidth Plot (5MHz 16-QAM – RB Size 25)

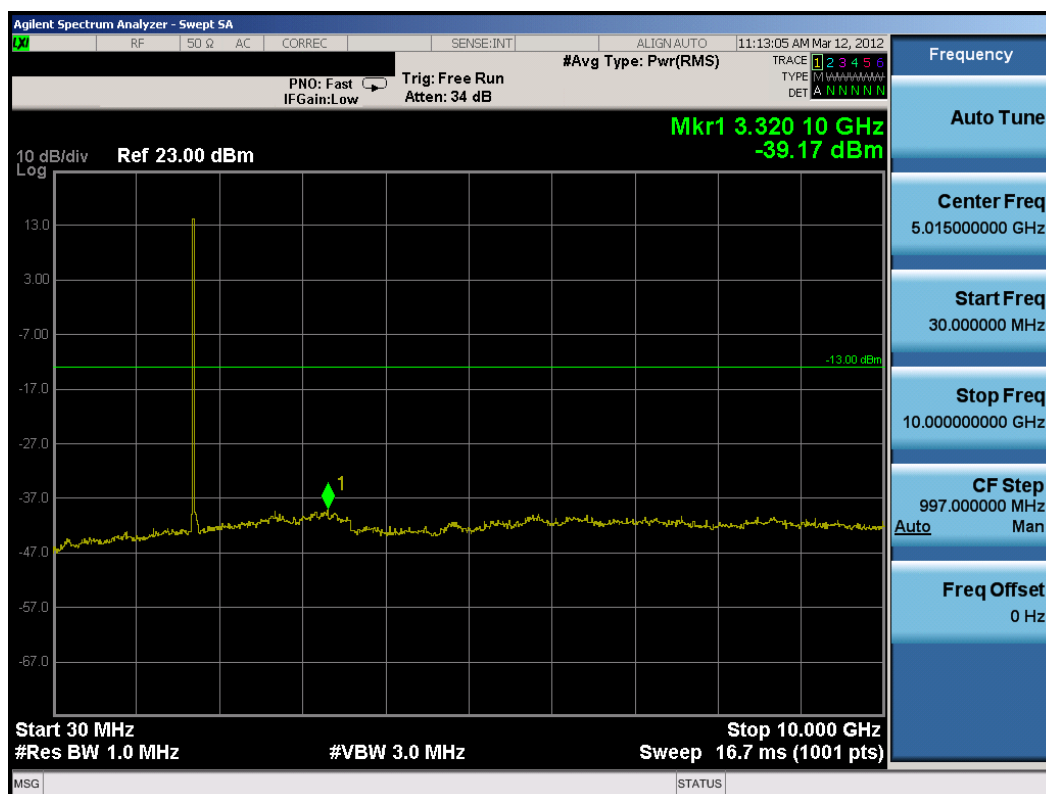


Plot 9-7. Occupied Bandwidth Plot (10MHz QPSK – RB Size 50)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 88 of 134

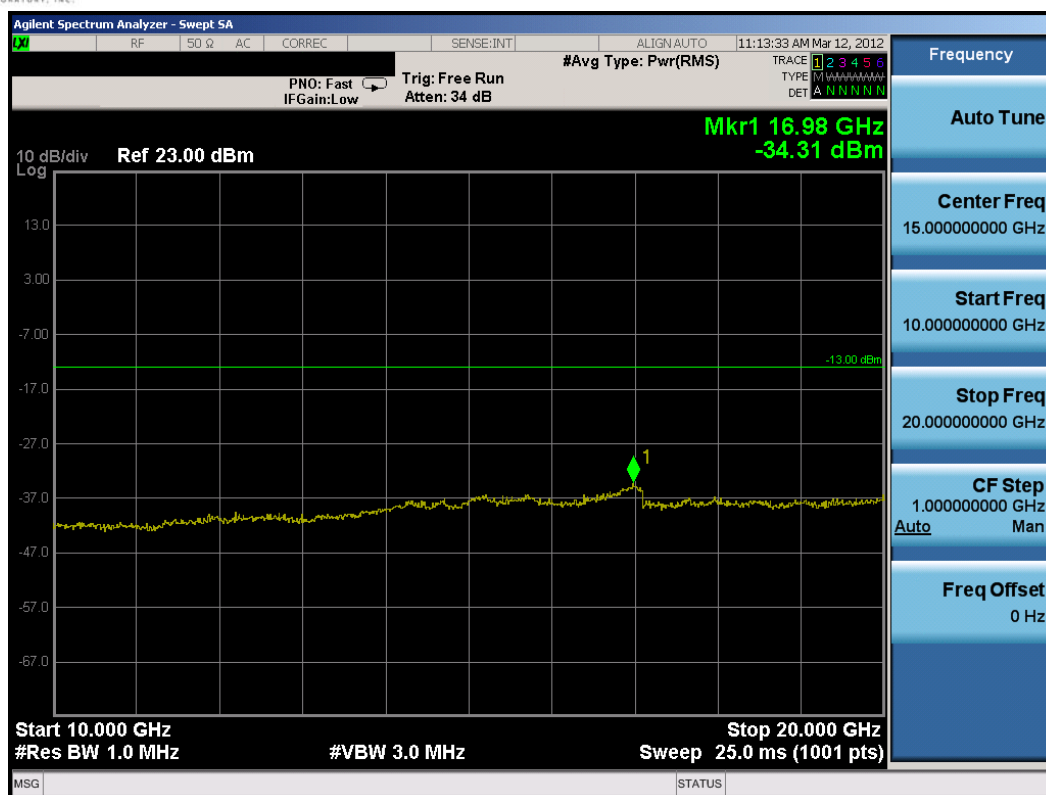


Plot 9-8. Occupied Bandwidth Plot (10MHz 16-QAM – RB Size 50)

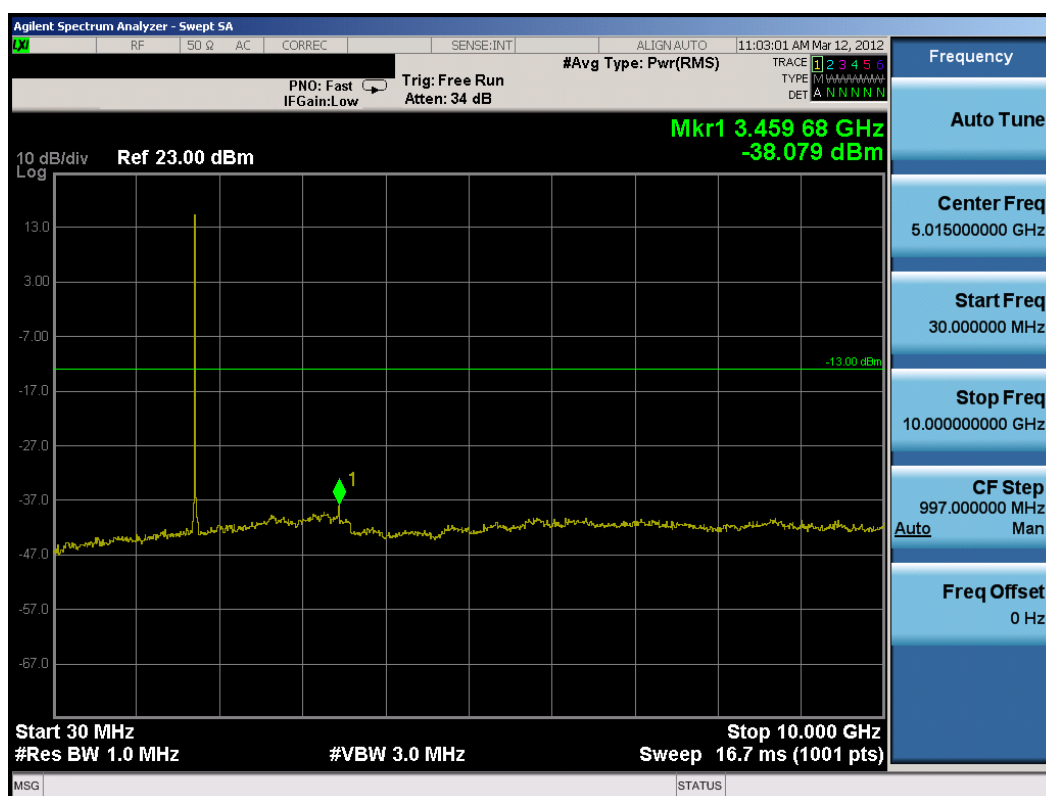


Plot 9-9. Conducted Spurious Plot (5MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 89 of 134

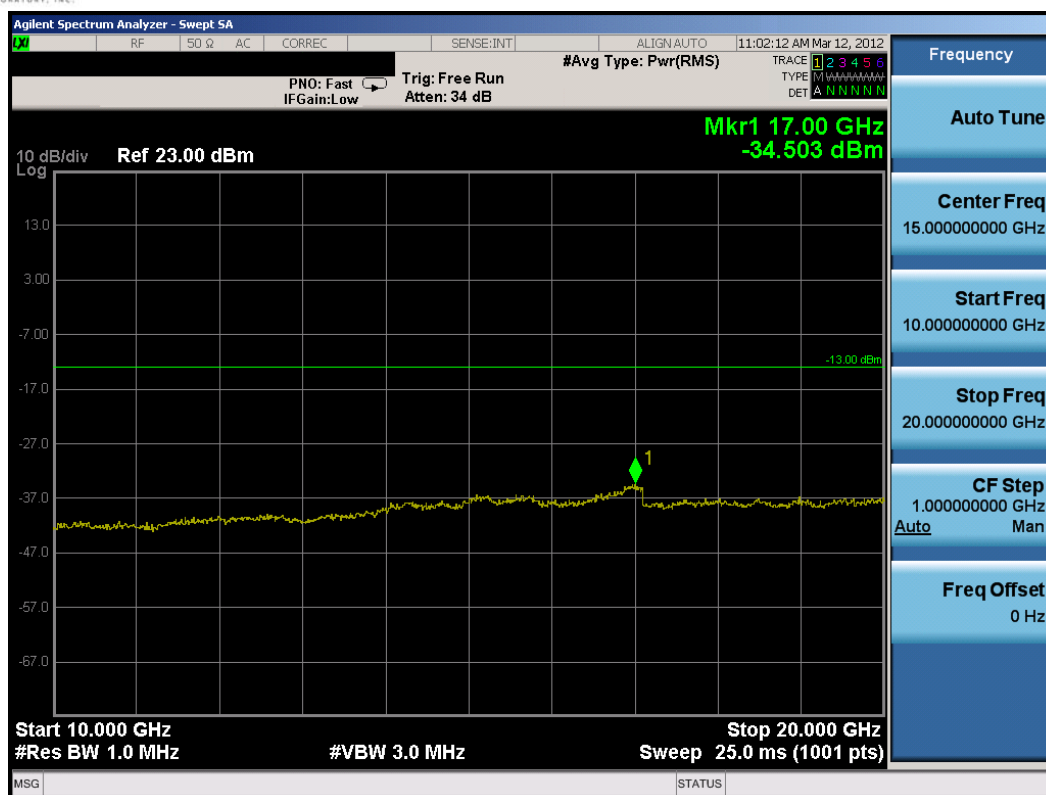


Plot 9-10. Conducted Spurious Plot (5MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

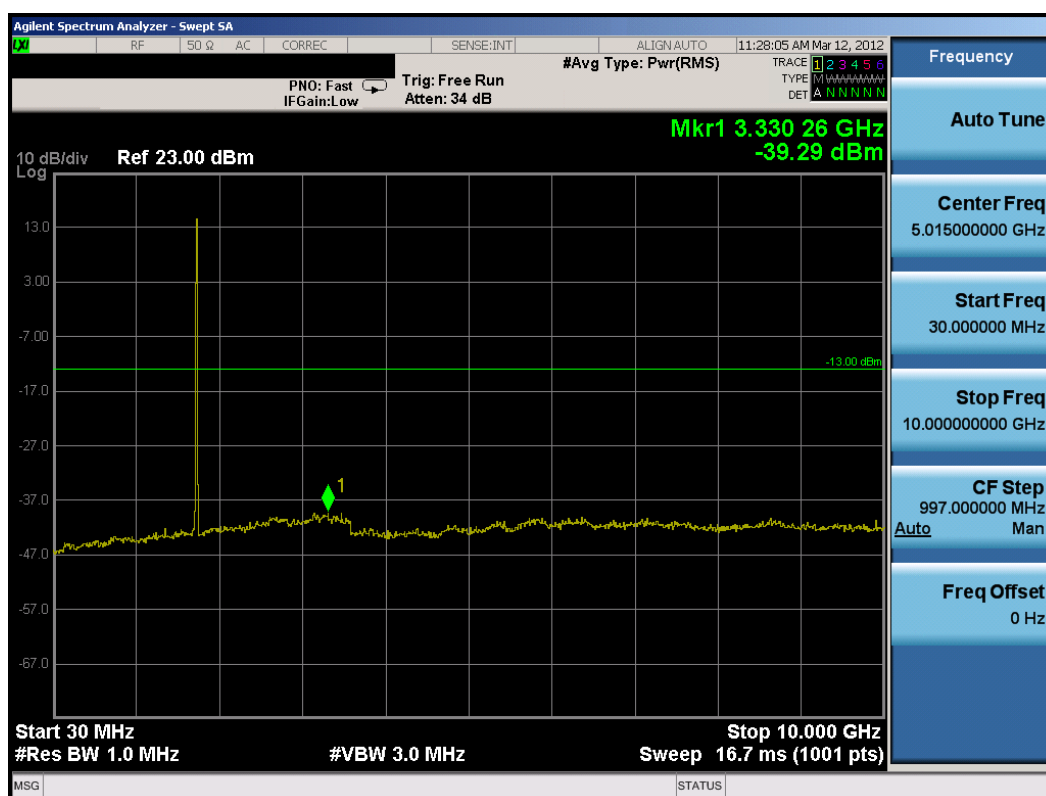


Plot 9-11. Conducted Spurious Plot (5MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSCHI405U	 FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION) 		Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset	Page 90 of 134

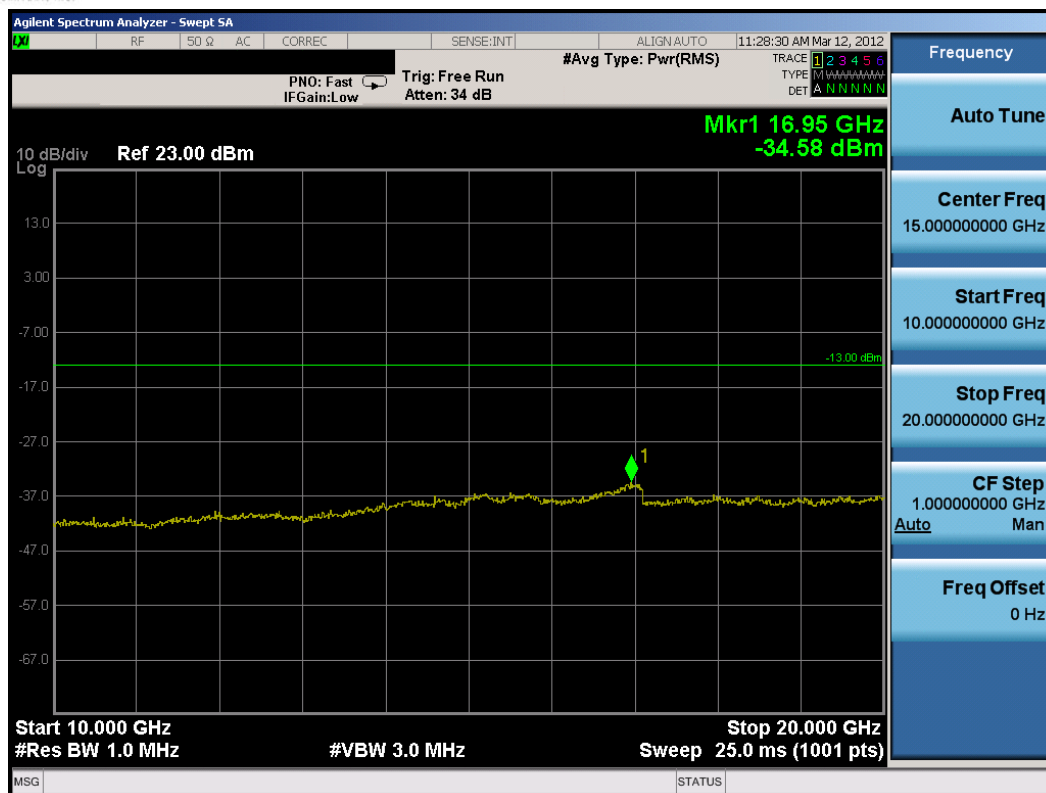


Plot 9-12. Conducted Spurious Plot (5MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

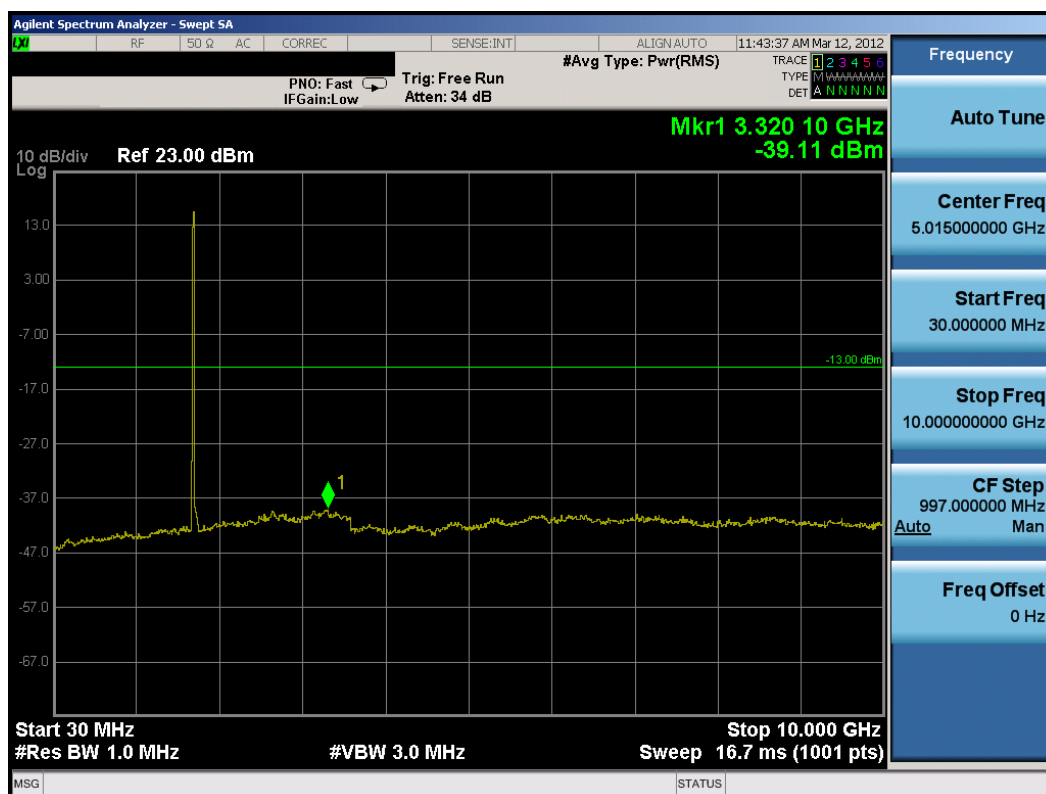


Plot 9-13. Conducted Spurious Plot (5MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSCHI405U	 FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION) 		Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset	Page 91 of 134

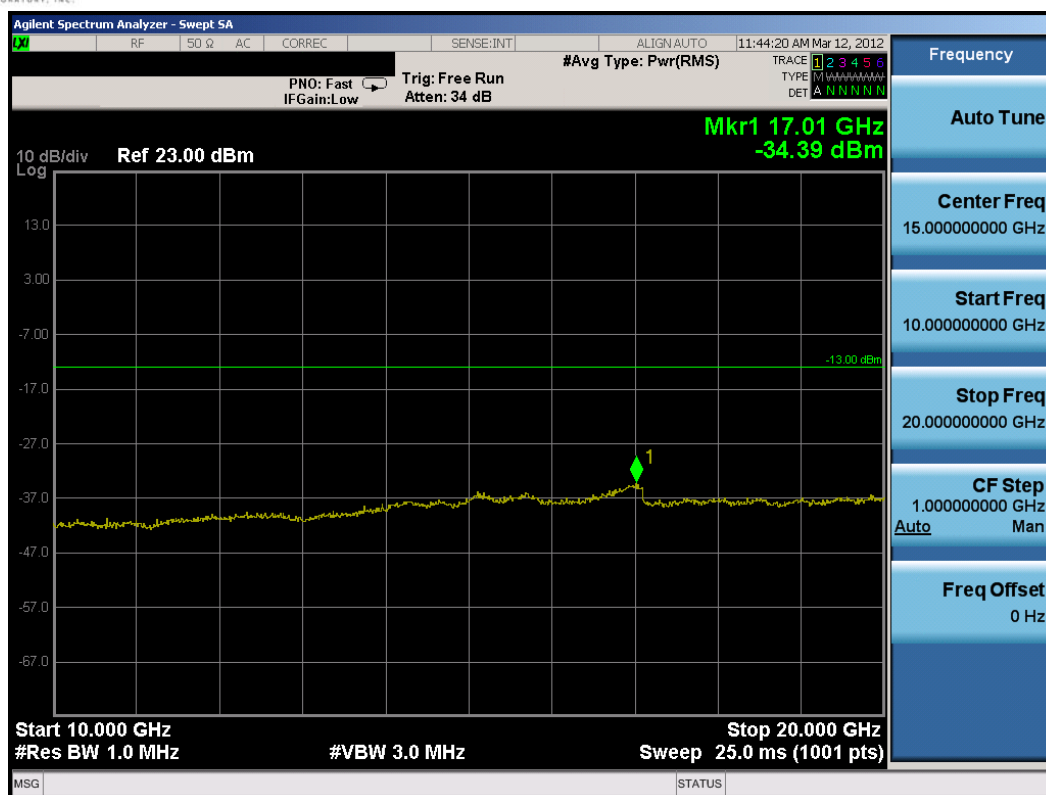


Plot 9-14. Conducted Spurious Plot (5MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

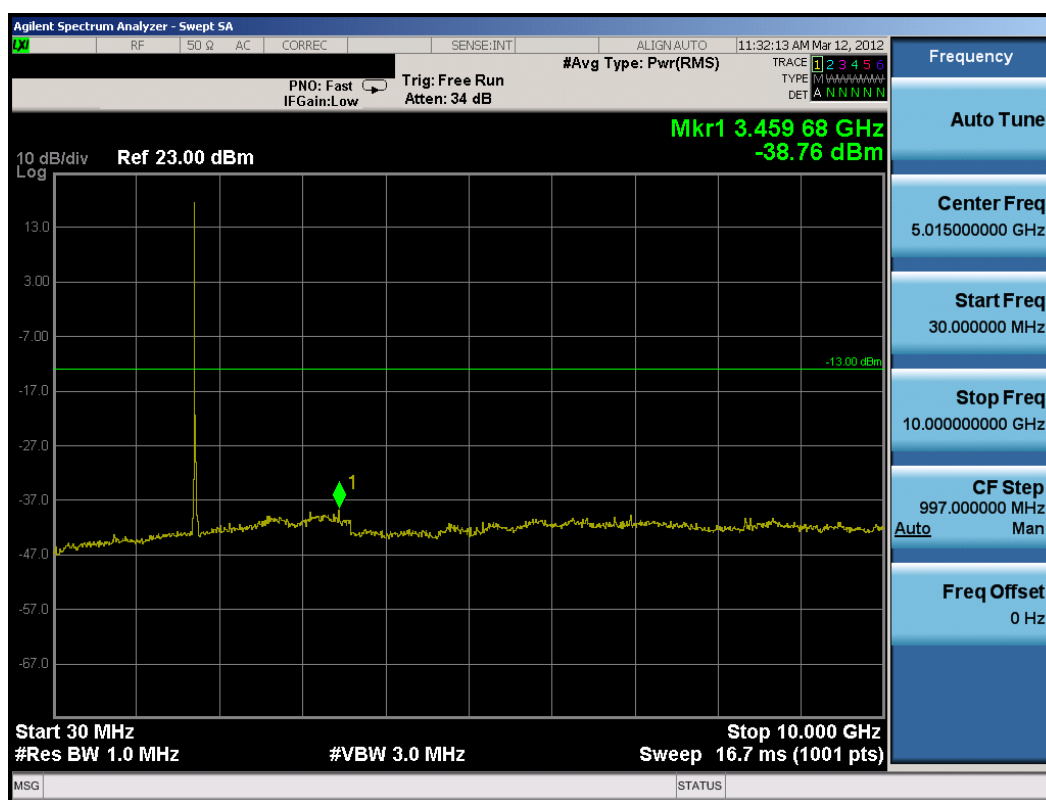


Plot 9-15. Conducted Spurious Plot (10MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 92 of 134

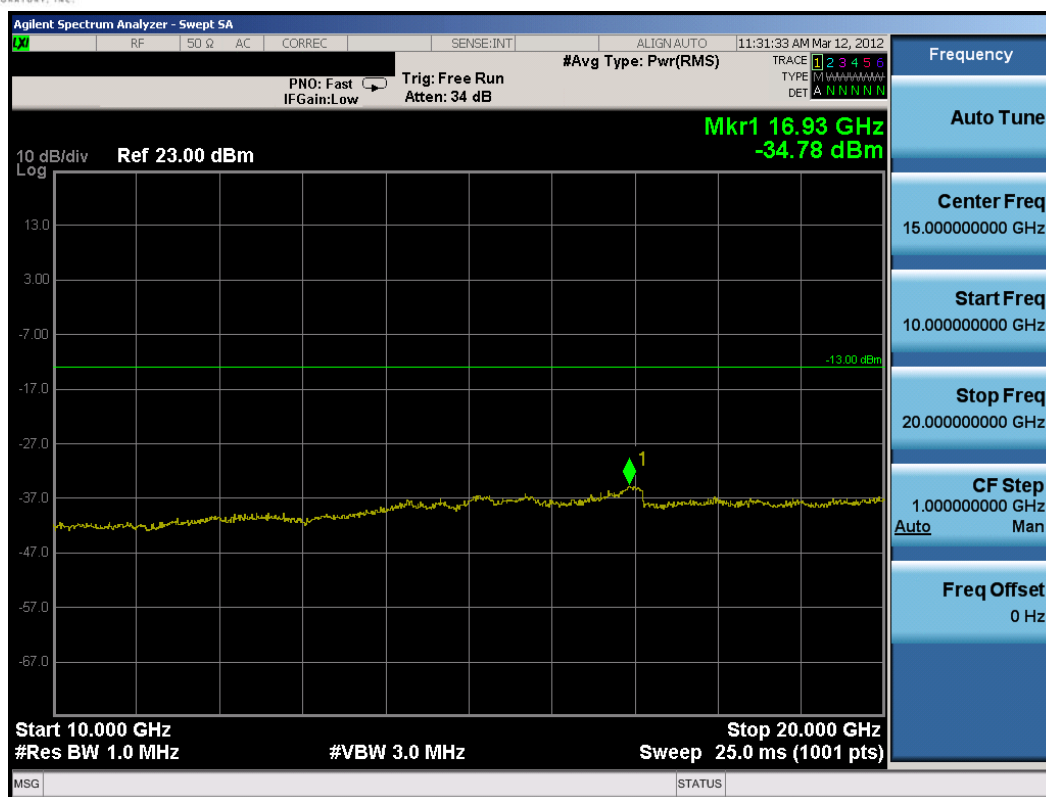


Plot 9-16. Conducted Spurious Plot (10MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

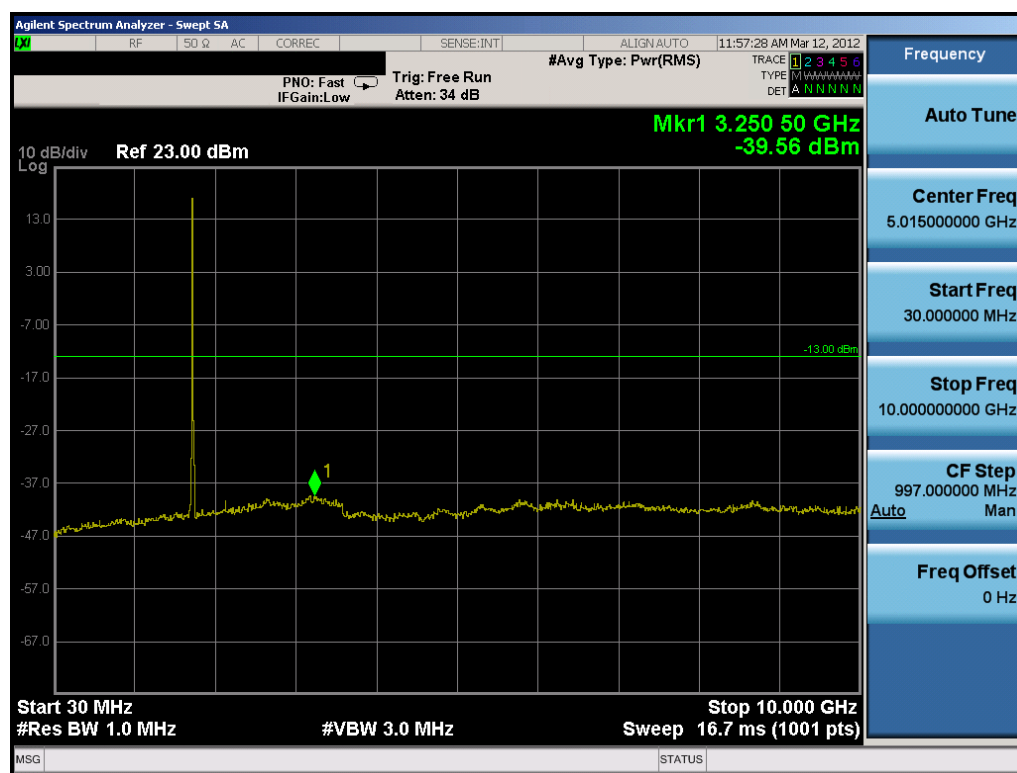


Plot 9-17. Conducted Spurious Plot (10MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 93 of 134

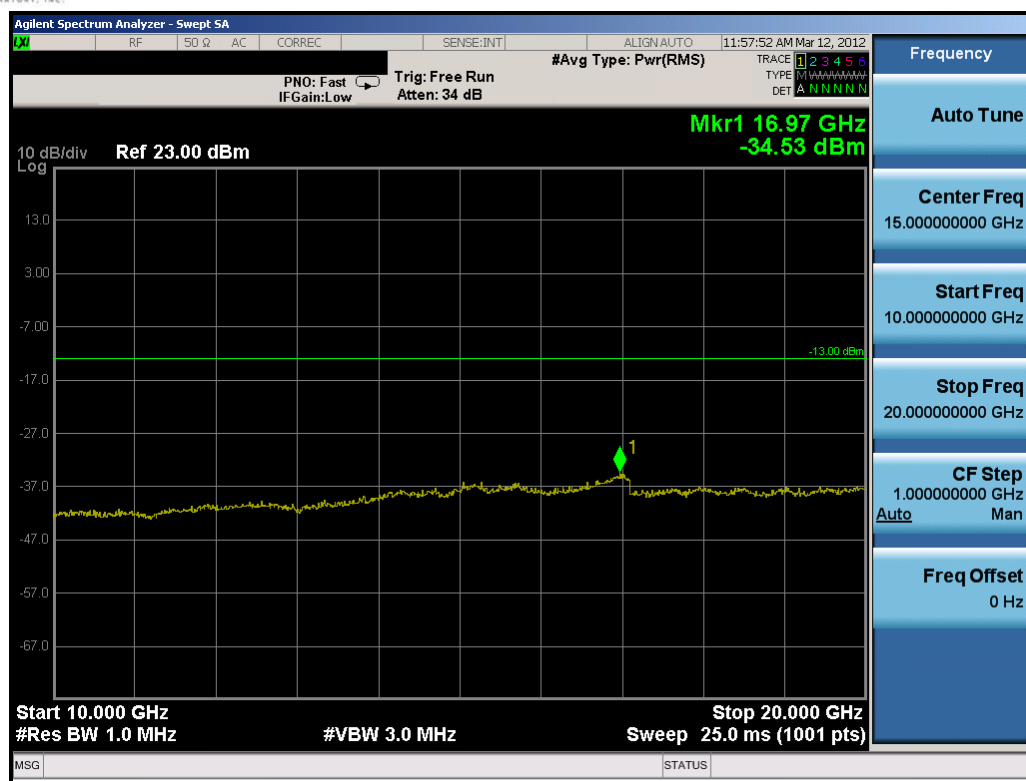


Plot 9-18. Conducted Spurious Plot (10MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

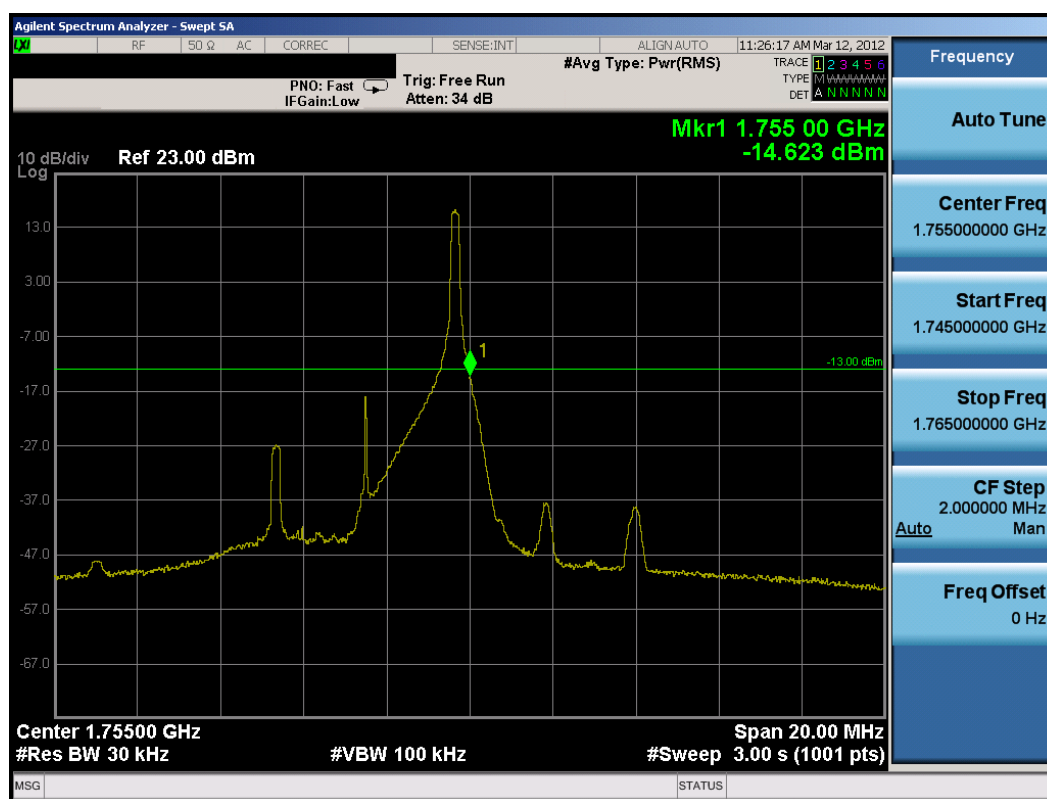


Plot 9-19. Conducted Spurious Plot (10MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 94 of 134

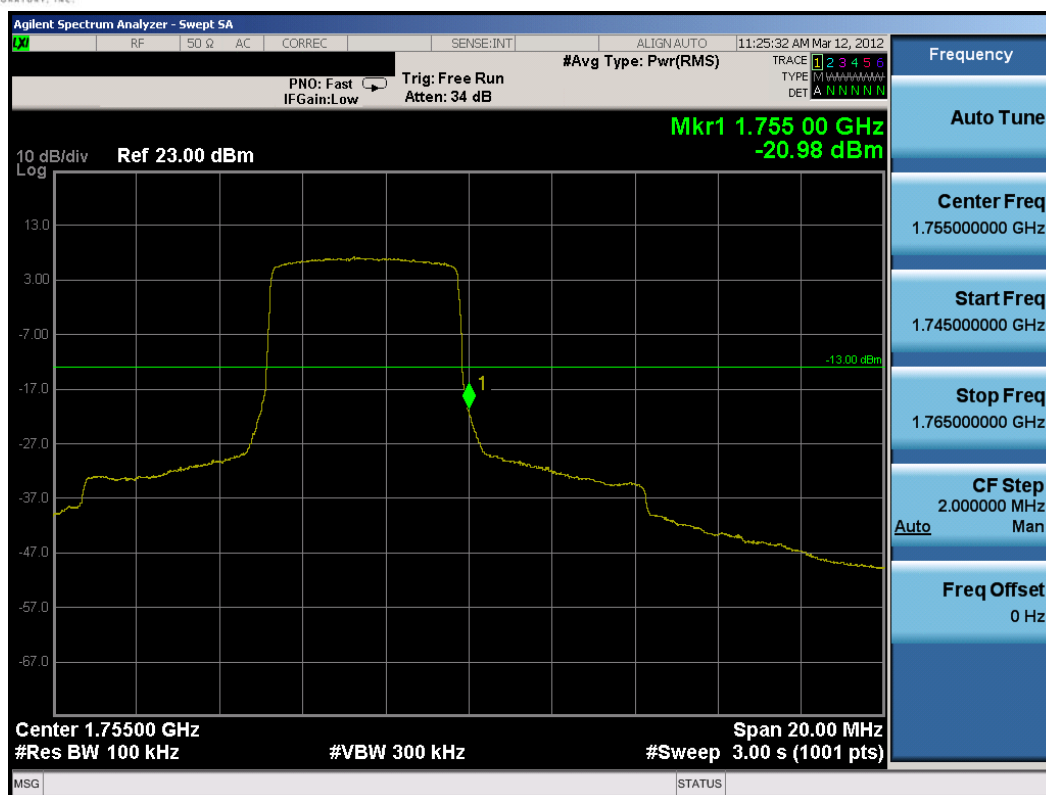


Plot 9-20. Conducted Spurious Plot (10MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

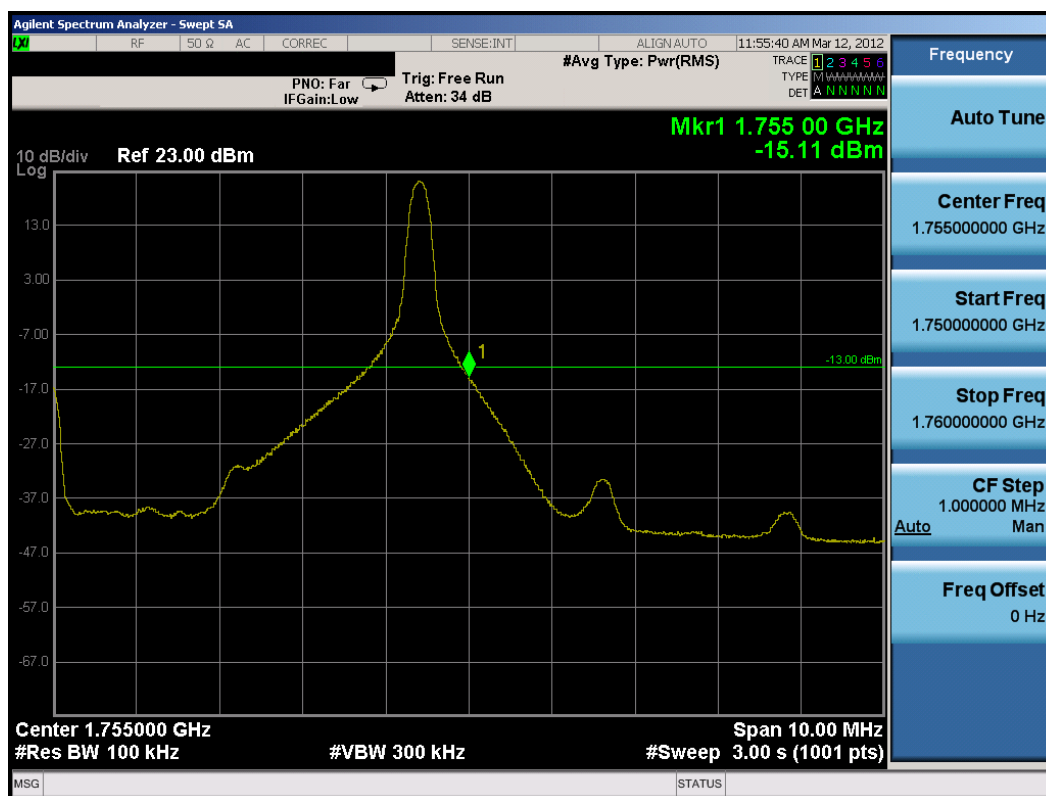


Plot 9-21. Upper Band Edge Plot (5MHz QPSK – RB Size 1, Offset 24)

FCC ID: A3LSCHI405U	 FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION) 		Reviewed by: Quality Manager
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Plot 9-22. Upper Band Edge Plot (5MHz QPSK – RB Size 25, Offset 0)

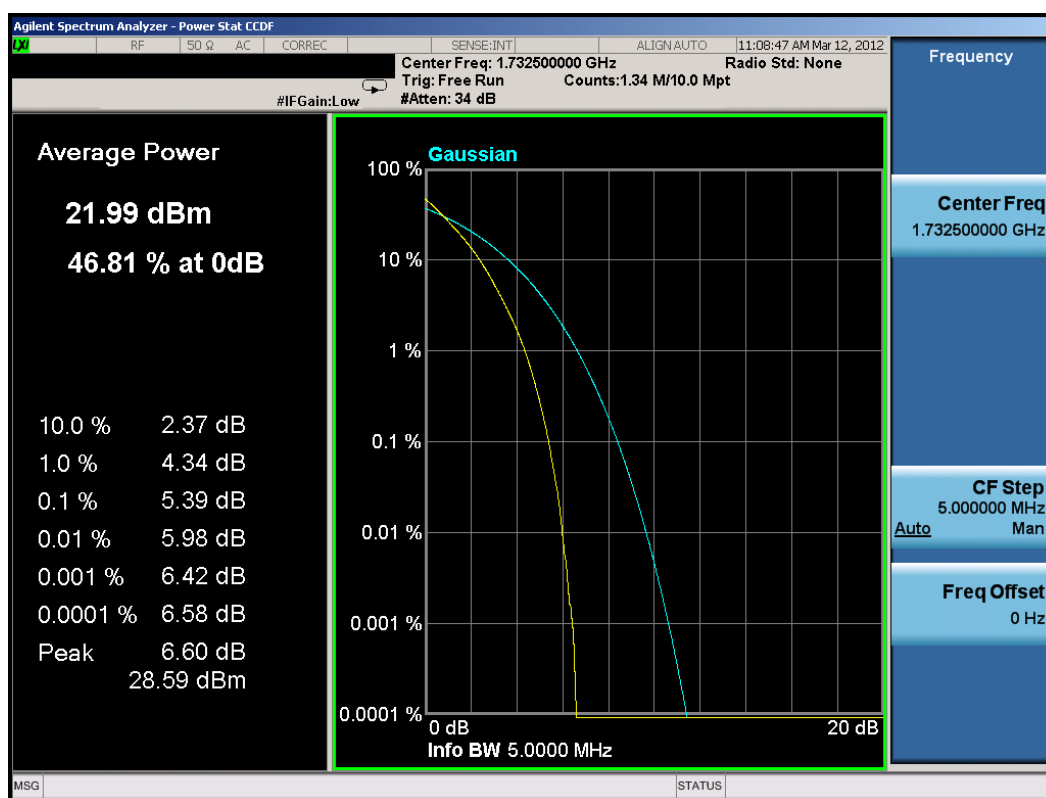


Plot 9-23. Upper Band Edge Plot (10MHz QPSK – RB Size 1, Offset 49)

FCC ID: A3LSCHI405U	 FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION) 		Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset	Page 96 of 134

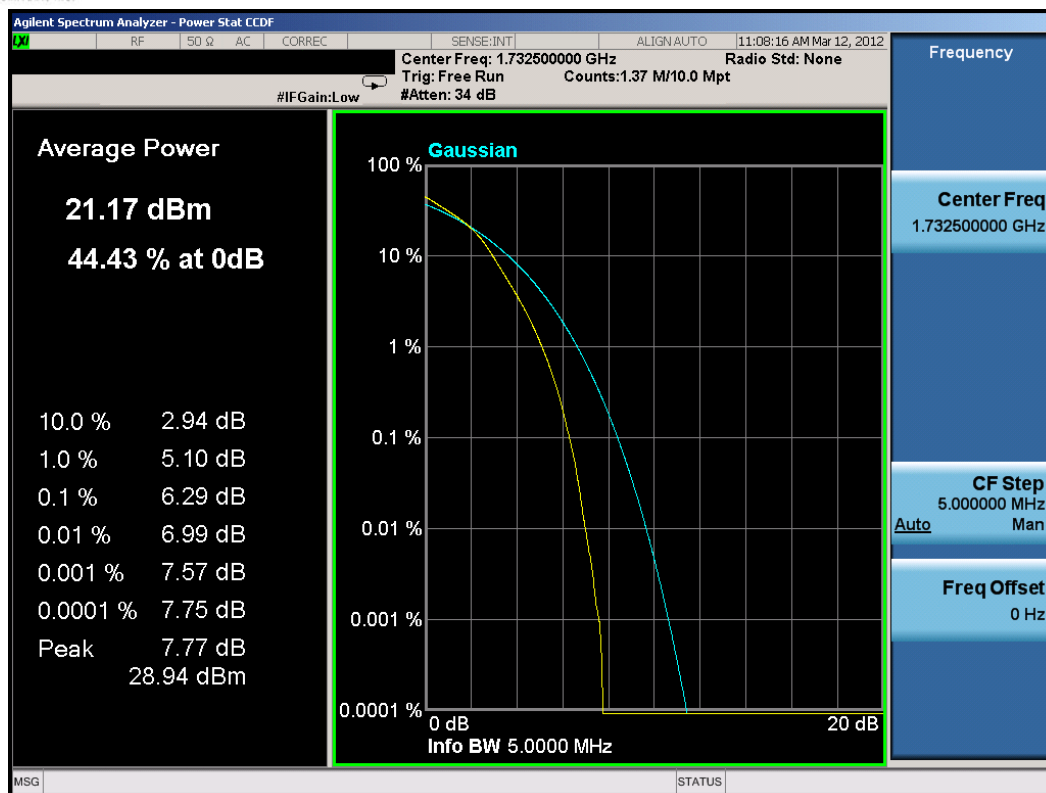


Plot 9-24. Upper Band Edge Plot (10MHz QPSK – RB Size 50, Offset 0)

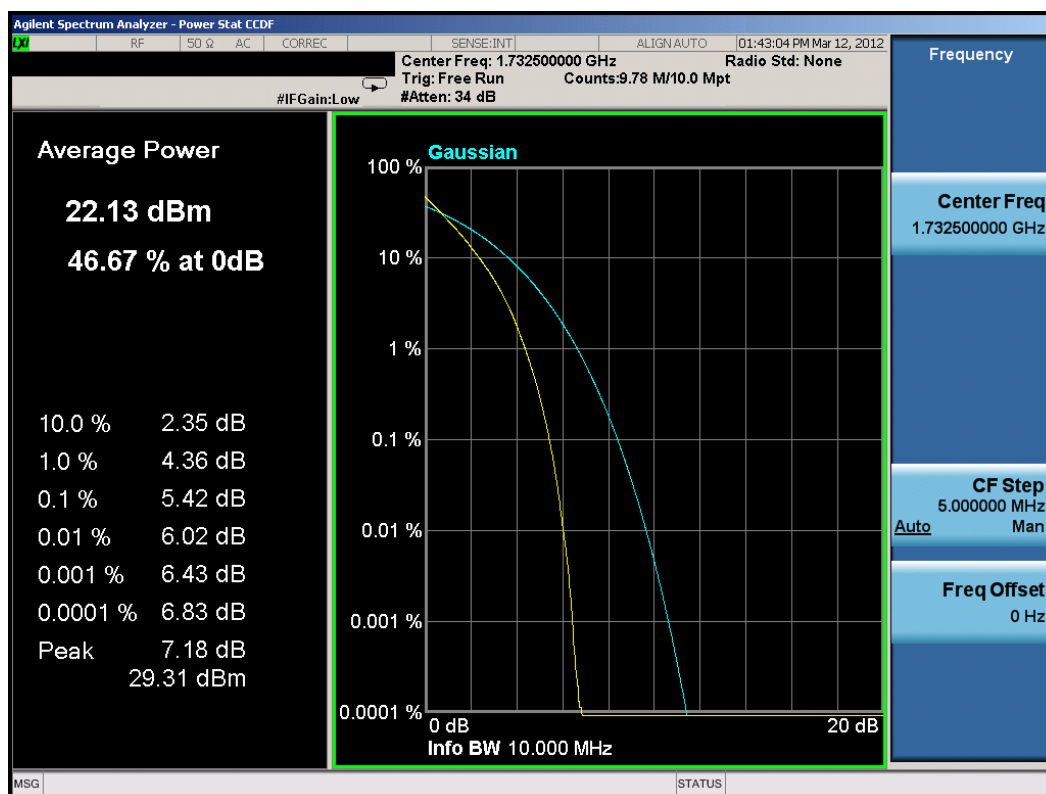


Plot 9-25. PAR Plot (5MHz QPSK – RB Size 25)

FCC ID: A3LSCHI405U	 FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION) 		Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset	Page 97 of 134

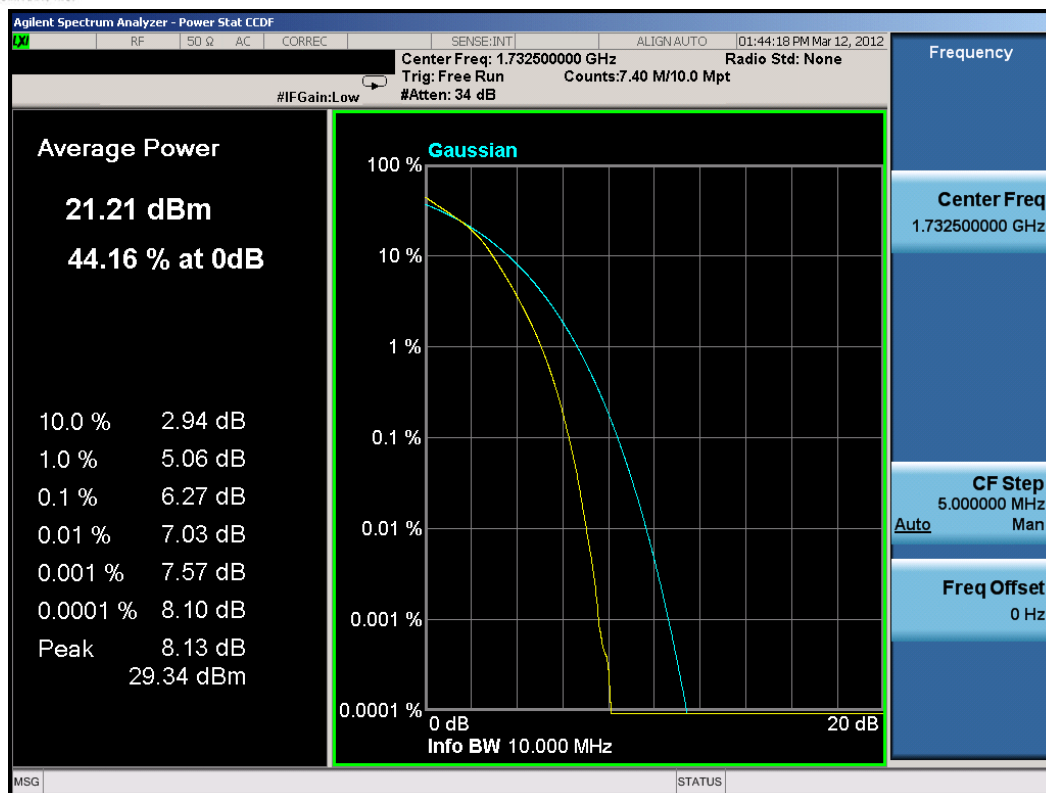


Plot 9-26. PAR Plot (5MHz 16QAM – RB Size 25)

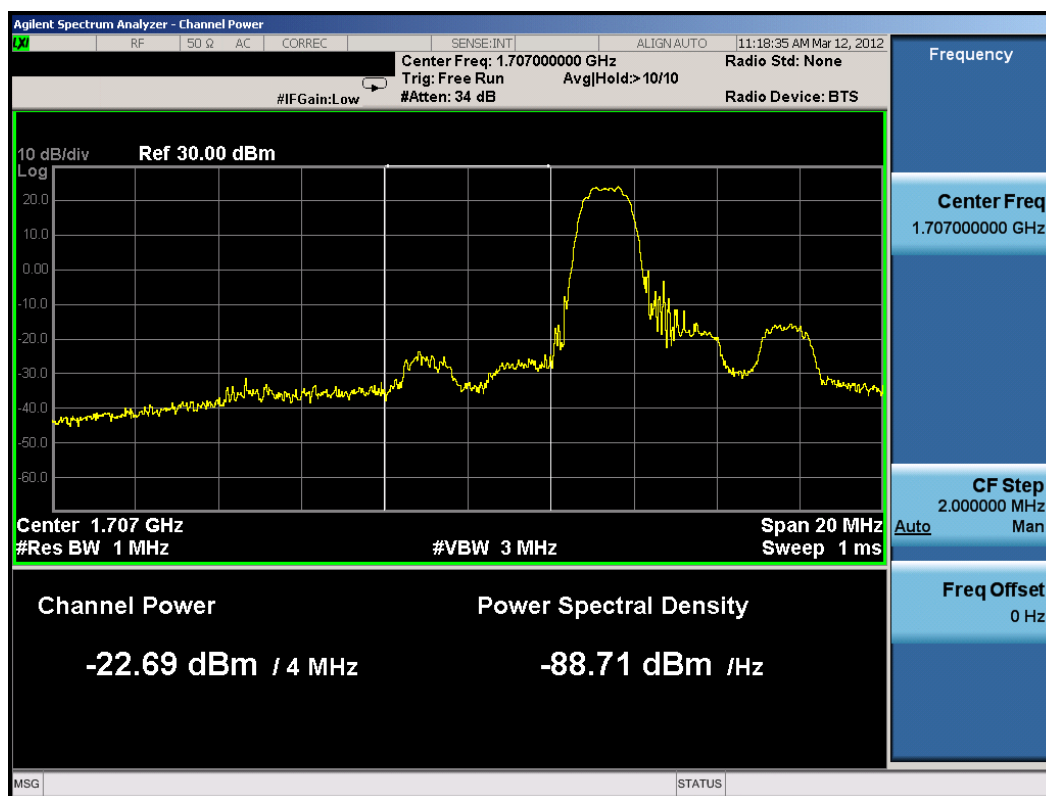


Plot 9-27. PAR Plot (10MHz QPSK – RB Size 50)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 98 of 134

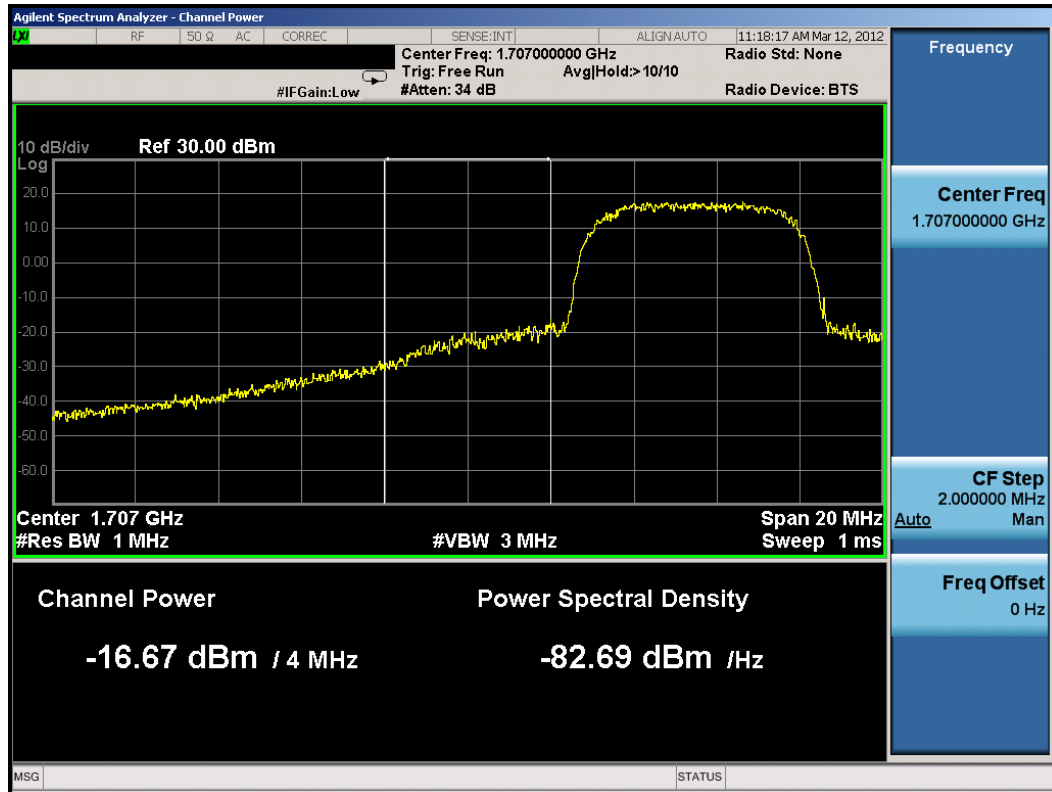


Plot 9-28. PAR Plot (10MHz 16QAM – RB Size 50)

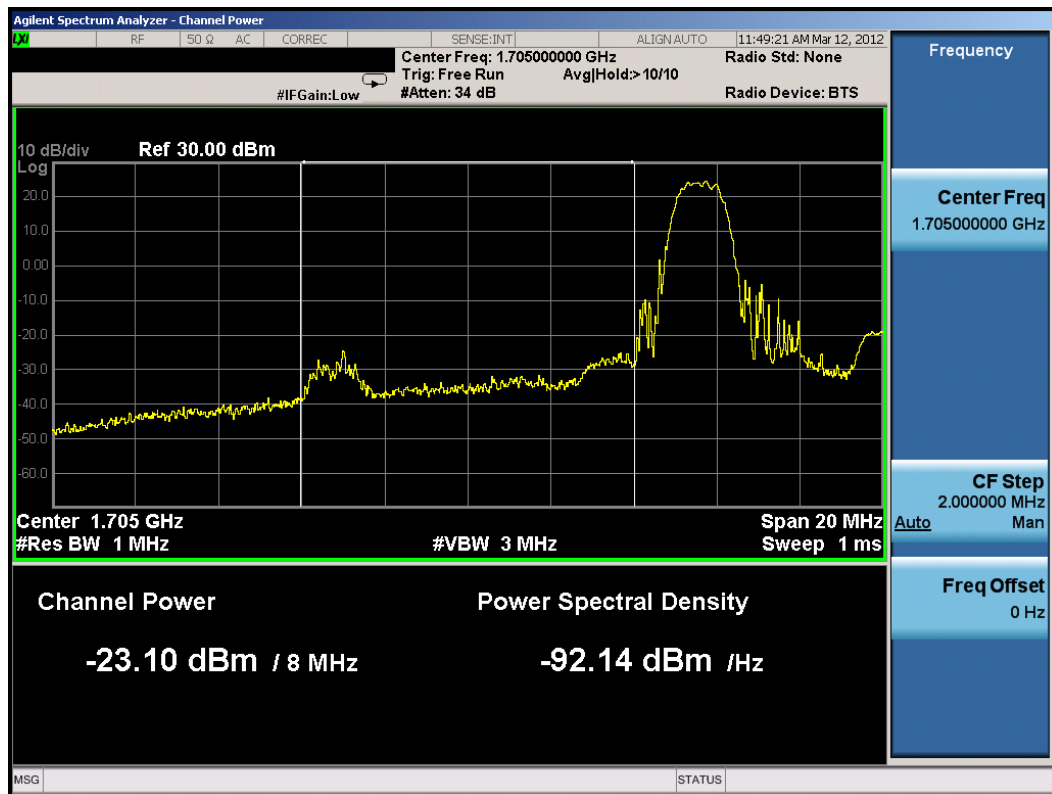


Plot 9-29. Lower Extended Band Edge Plot (5MHz QPSK– RB Size 1, Offset 0)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 99 of 134

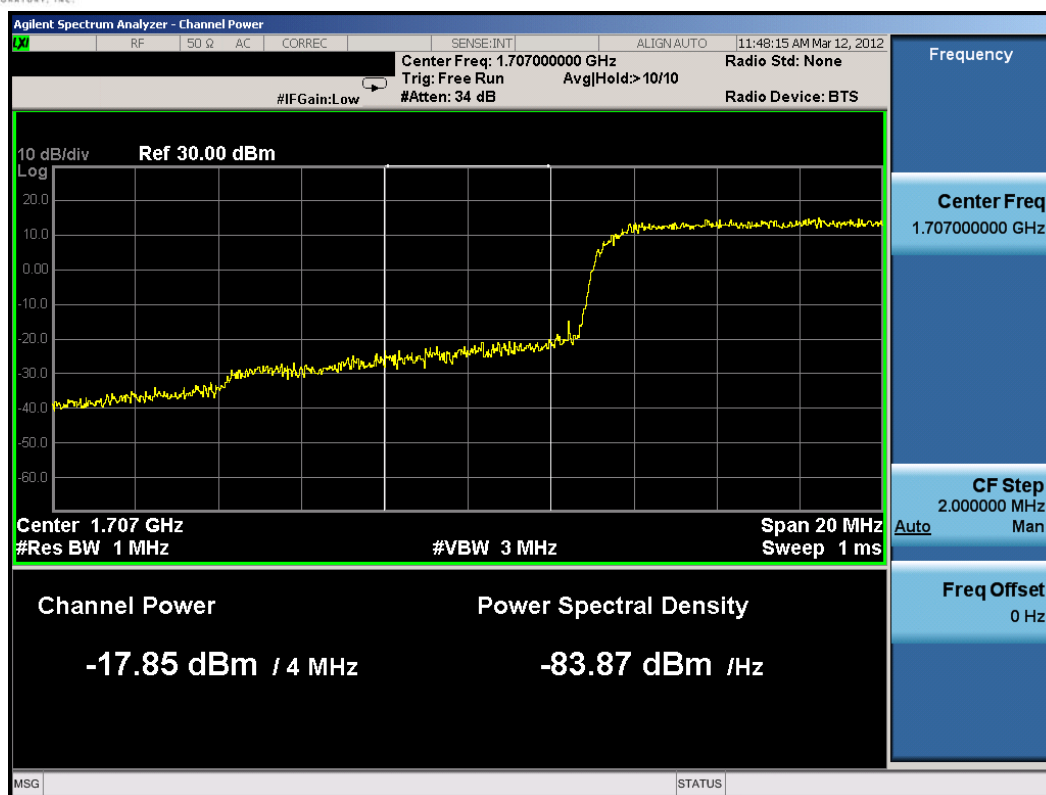


Plot 9-30. Lower Extended Band Edge Plot (5MHz QPSK– RB Size 25,Offset 0)

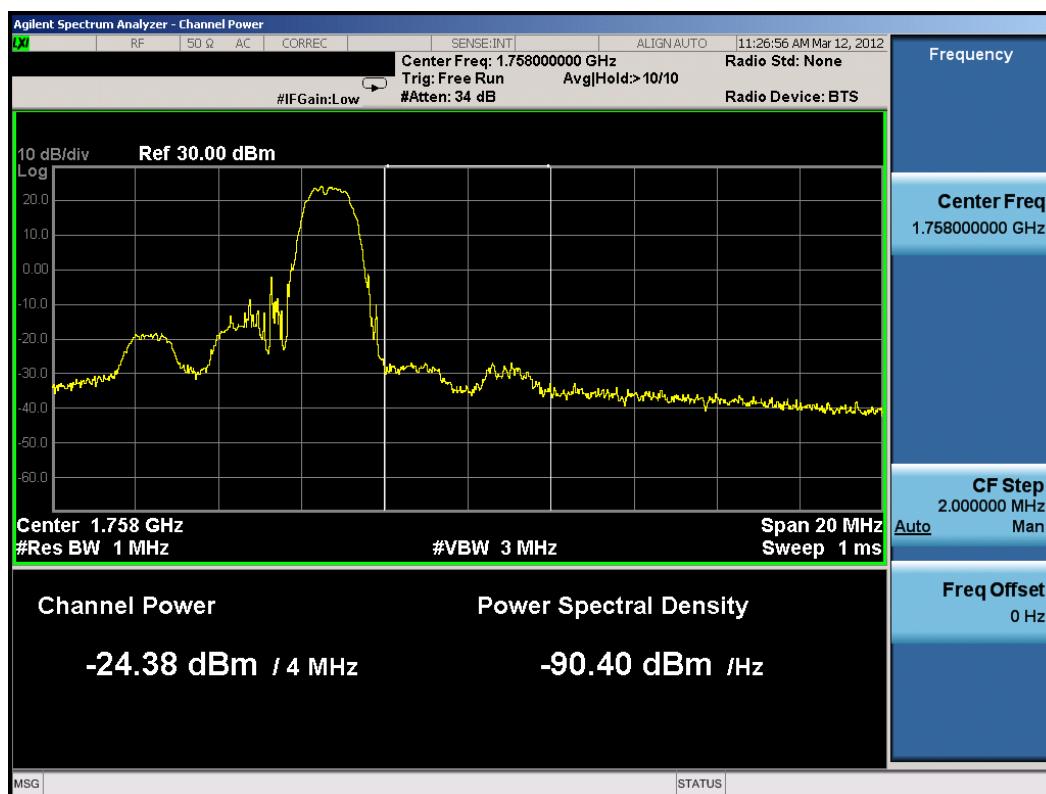


Plot 9-31. Lower Extended Band Edge Plot (10MHz QPSK– RB Size 1,Offset 0)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 100 of 134



Plot 9-32. Lower Extended Band Edge Plot (10MHz QPSK– RB Size 50, Offset 0)

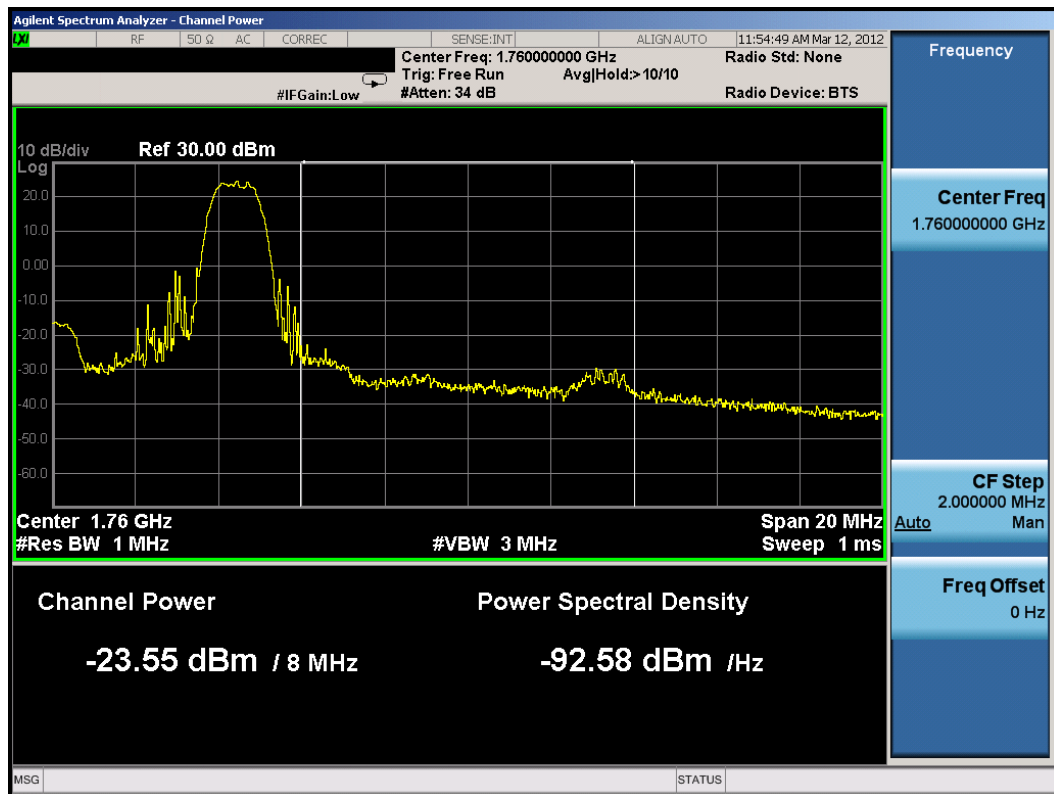


Plot 9-33. Upper Extended Band Edge Plot (5MHz QPSK– RB Size 1, Offset 24)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 101 of 134



Plot 9-34. Upper Extended Band Edge Plot (5MHz QPSK– RB Size 25, Offset 0)



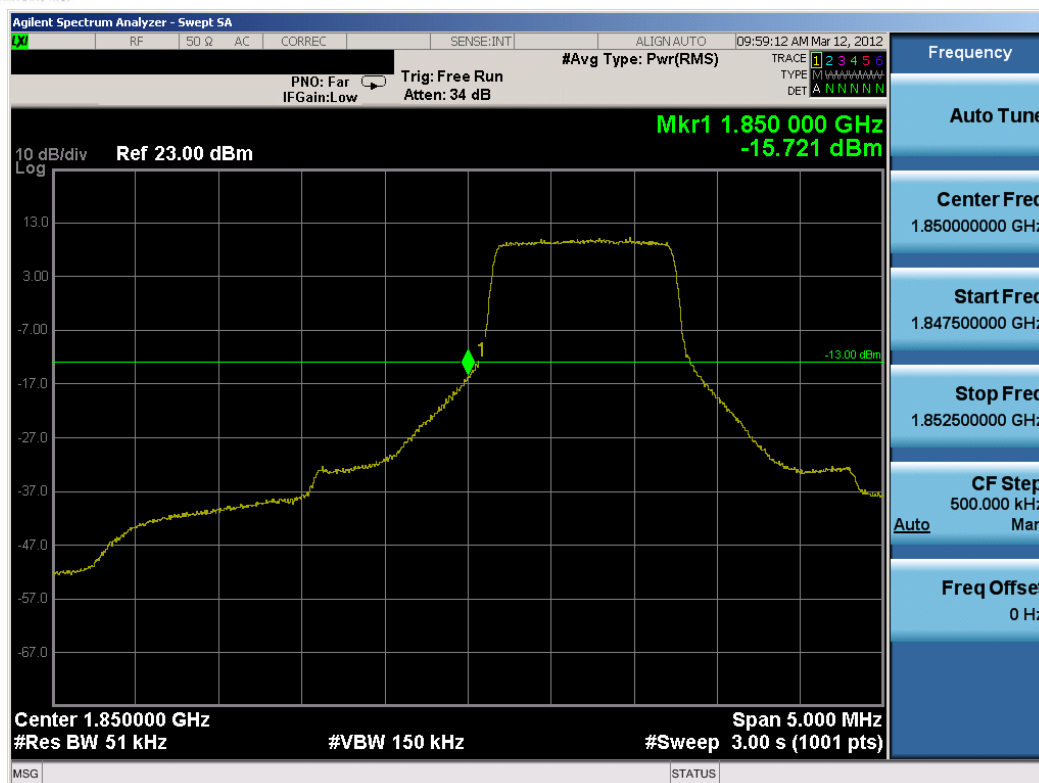
Plot 9-35. Upper Extended Band Edge Plot (10MHz QPSK– RB Size 1, Offset 49)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 102 of 134

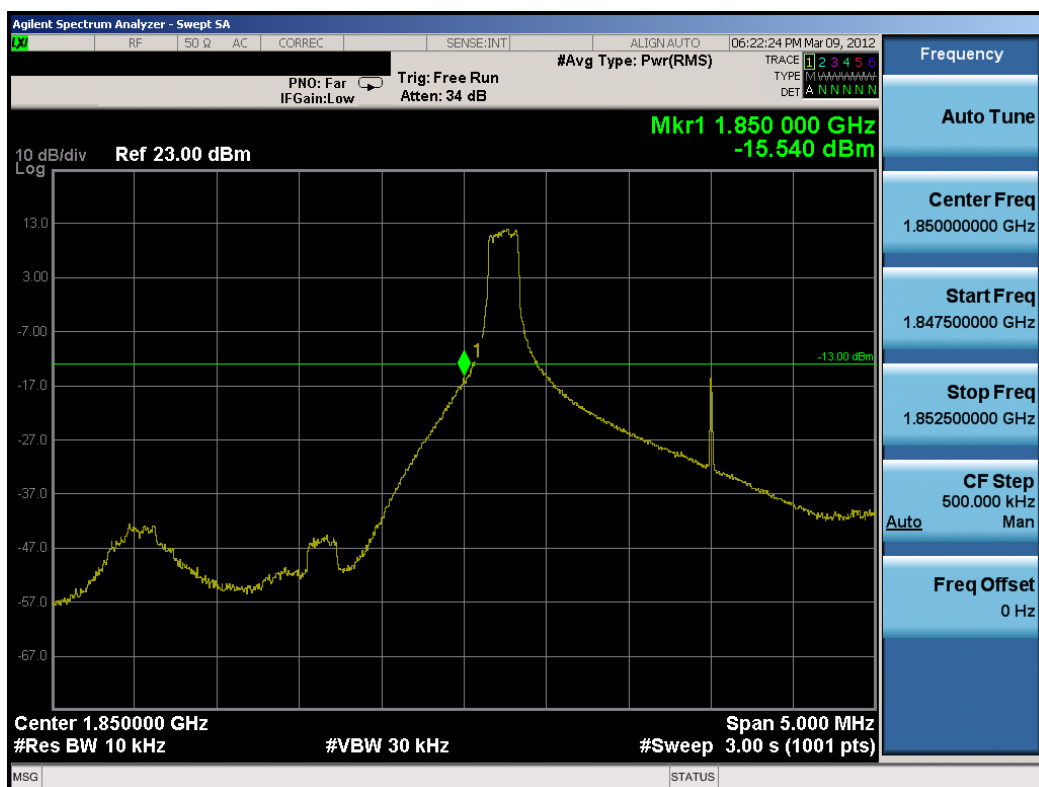


Plot 9-36. Upper Extended Band Edge Plot (10MHz QPSK– RB Size 50, Offset 0)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 103 of 134

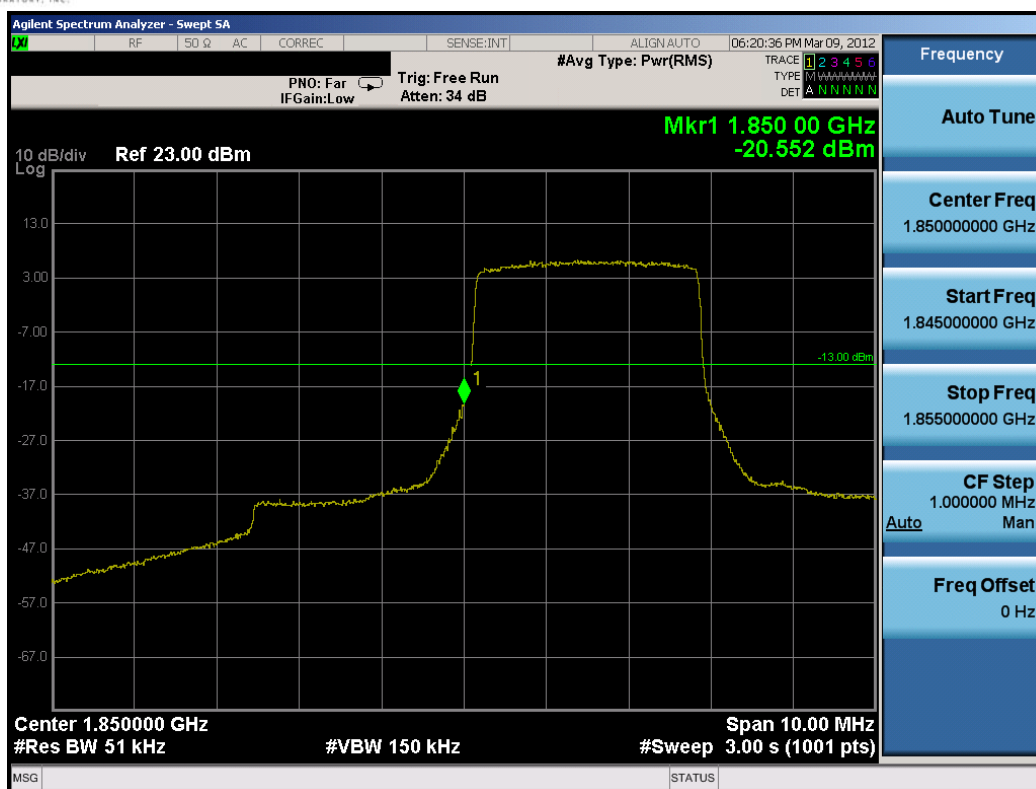


Plot 10-2. Lower Band Edge Plot (1.4MHz QPSK – RB Size 6, Offset 0)

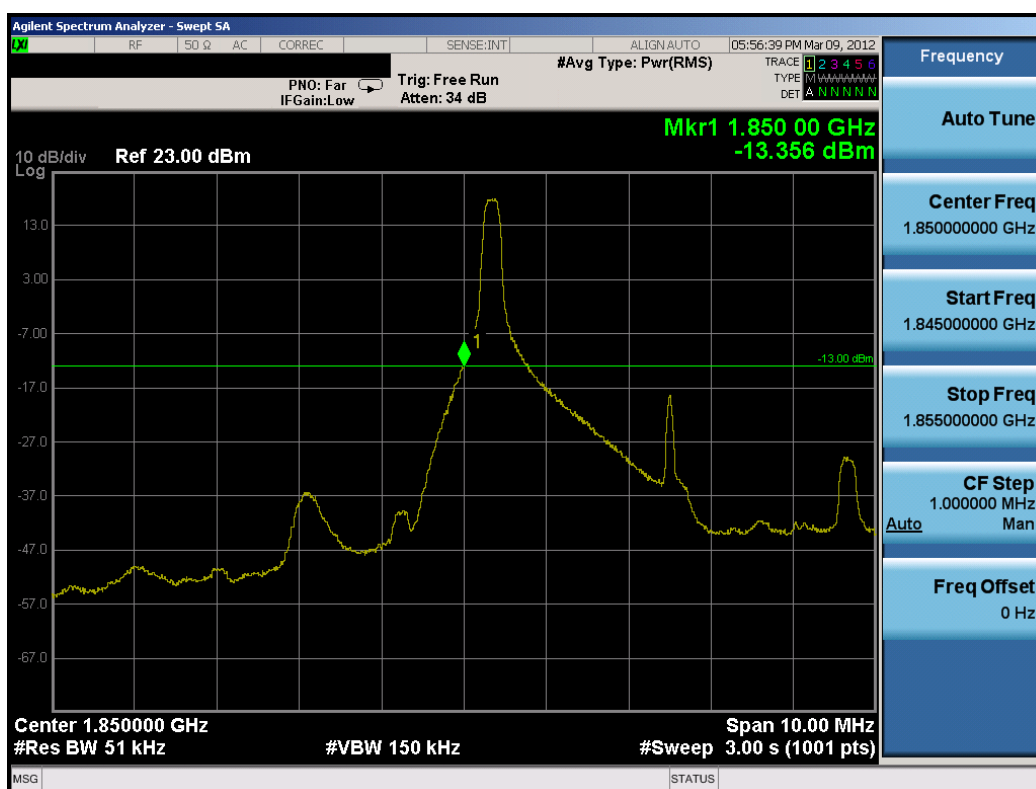


Plot 10-3. Lower Band Edge Plot (3MHz QPSK – RB Size 1, Offset 0)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 105 of 134

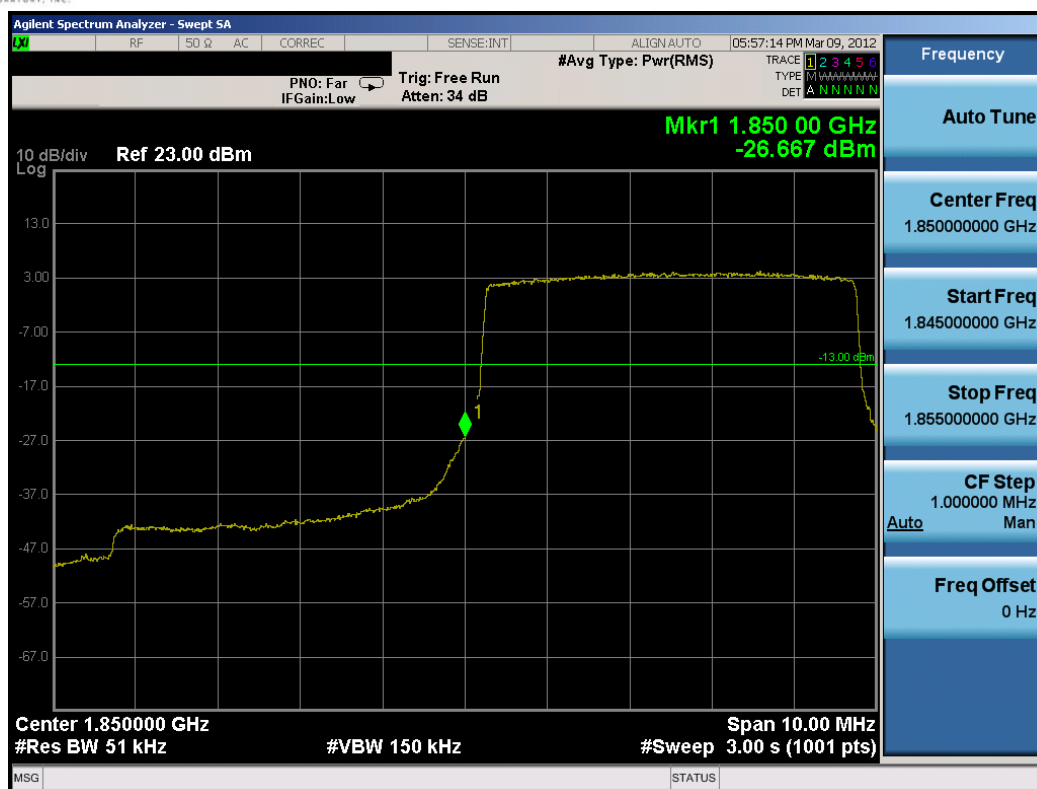


Plot 10-4. Lower Band Edge Plot (3MHz QPSK – RB Size 15, Offset 0)

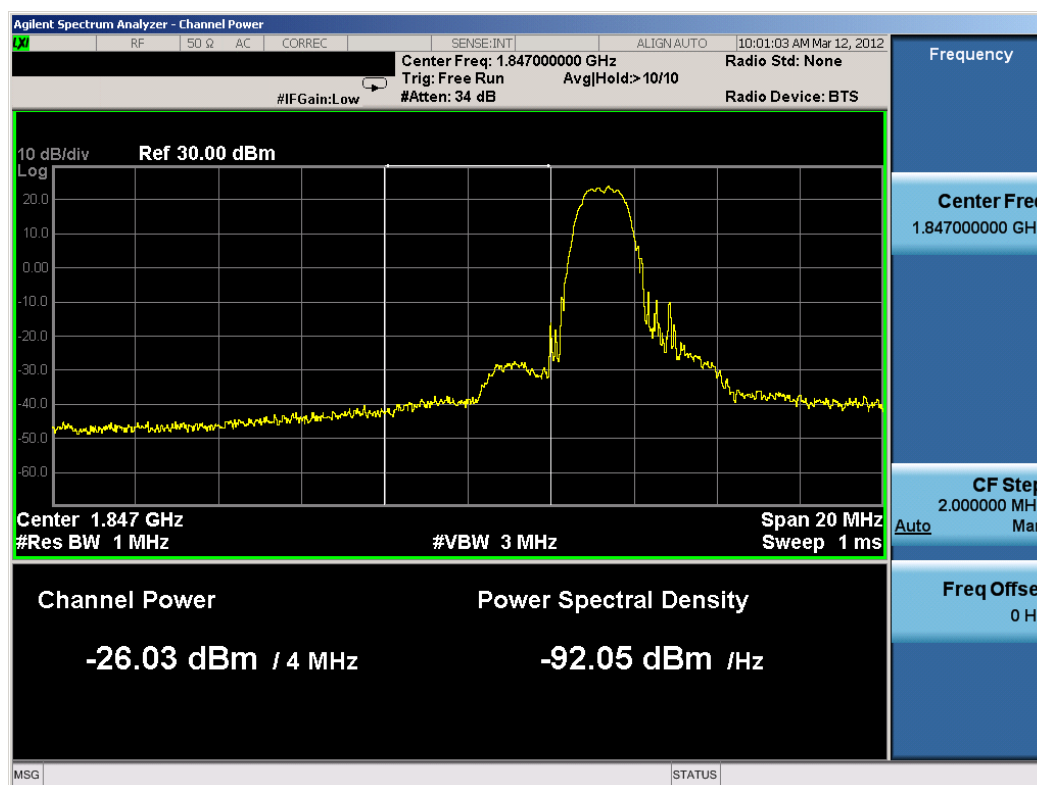


Plot 10-5. Lower Band Edge Plot (5MHz QPSK – RB Size 1, Offset 0)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 106 of 134

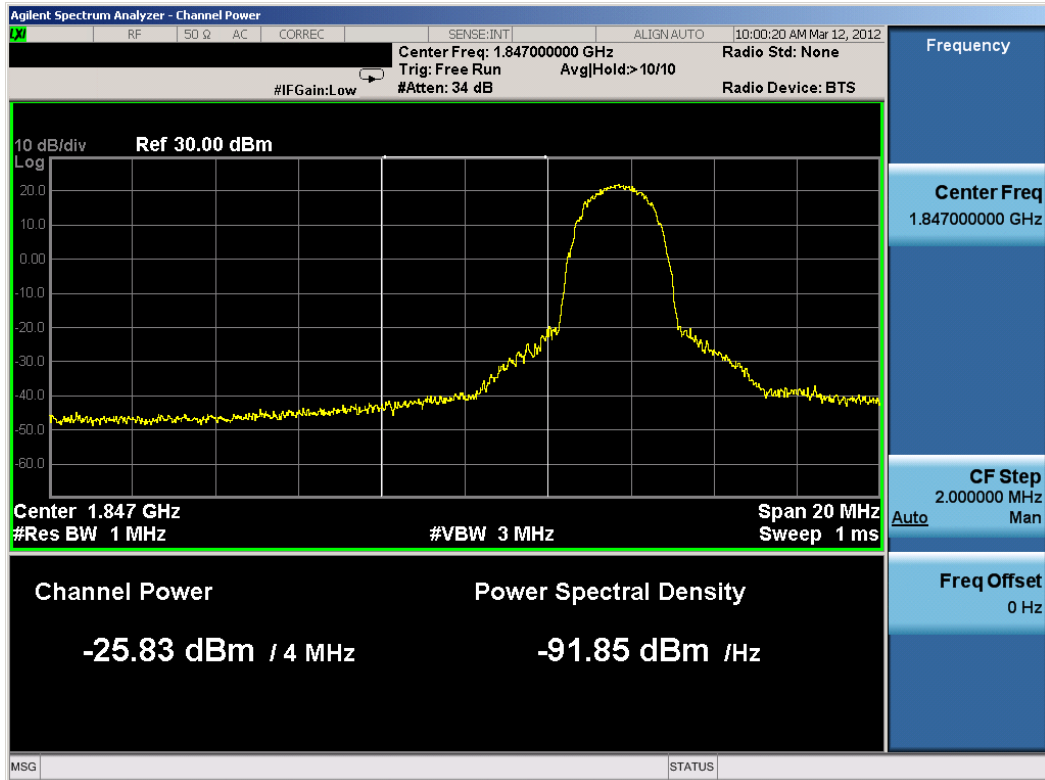


Plot 10-6. Lower Band Edge Plot (5MHz QPSK – RB Size 25, Offset 0)

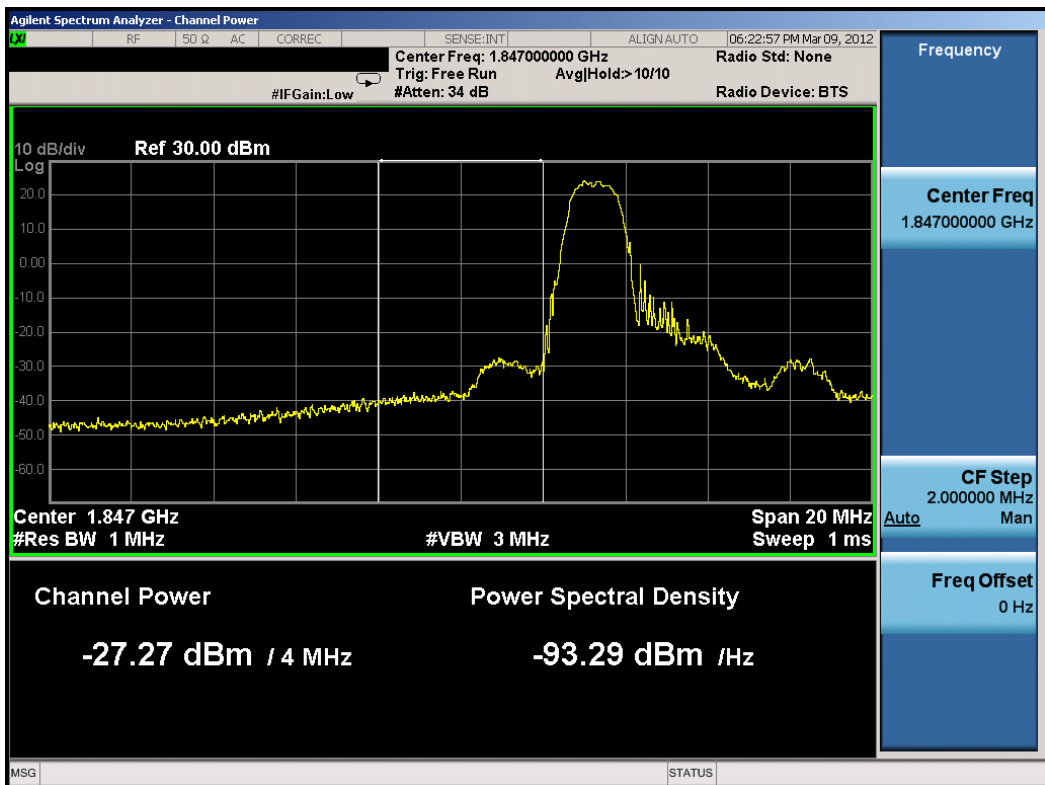


Plot 10-7. Lower Extended Band Edge Plot (1.4MHz QPSK – RB Size 1, Offset 0)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 107 of 134

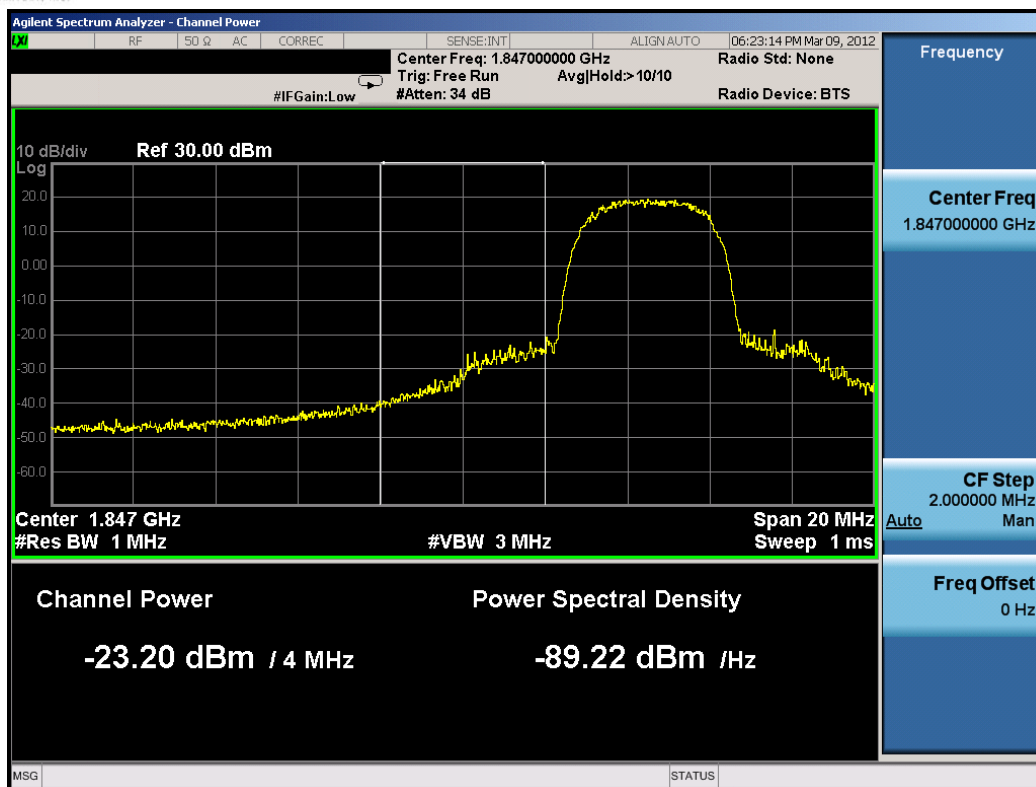


Plot 10-8. Lower Extended Band Edge Plot (1.4MHz QPSK – RB Size 6, Offset 0)

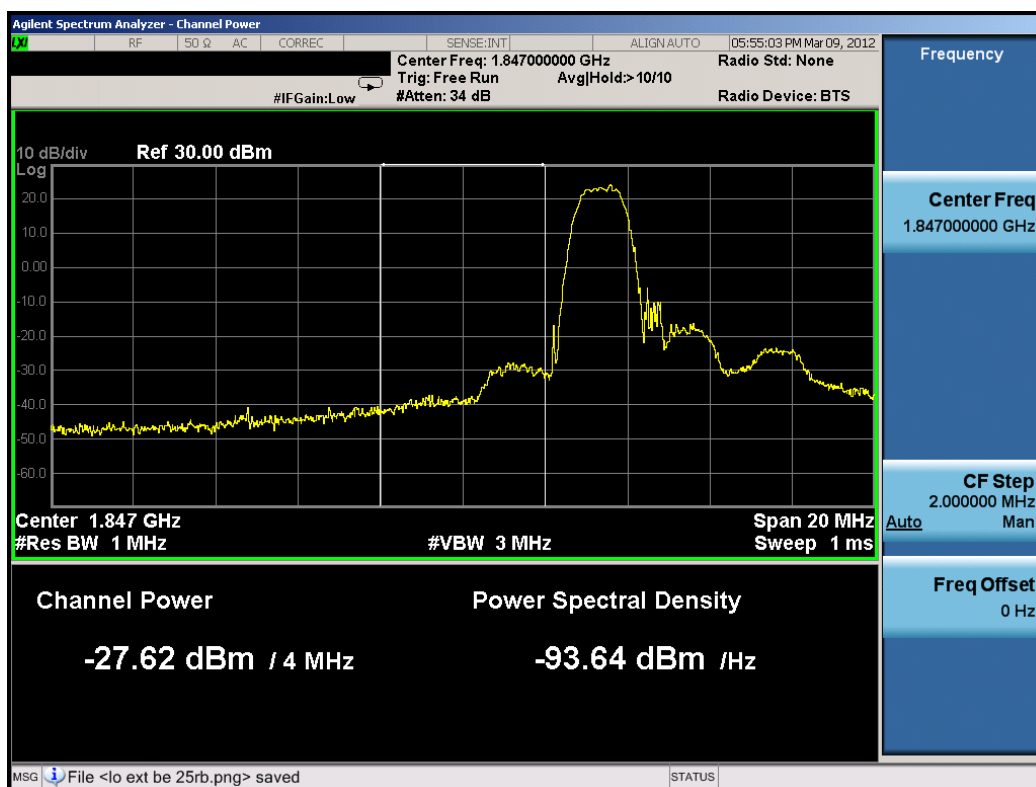


Plot 10-9. Lower Extended Band Edge Plot (3MHz QPSK – RB Size 1, Offset 0)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 108 of 134

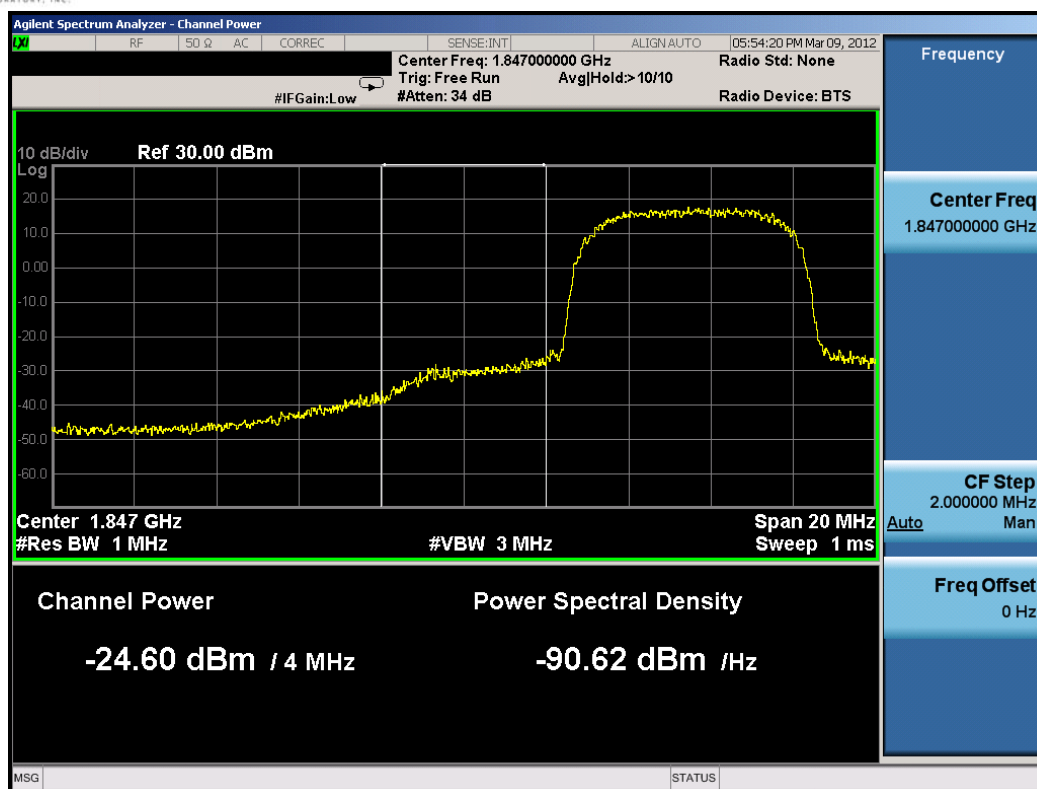


Plot 10-10. Lower Extended Band Edge Plot (3MHz QPSK – RB Size 15, Offset 0)

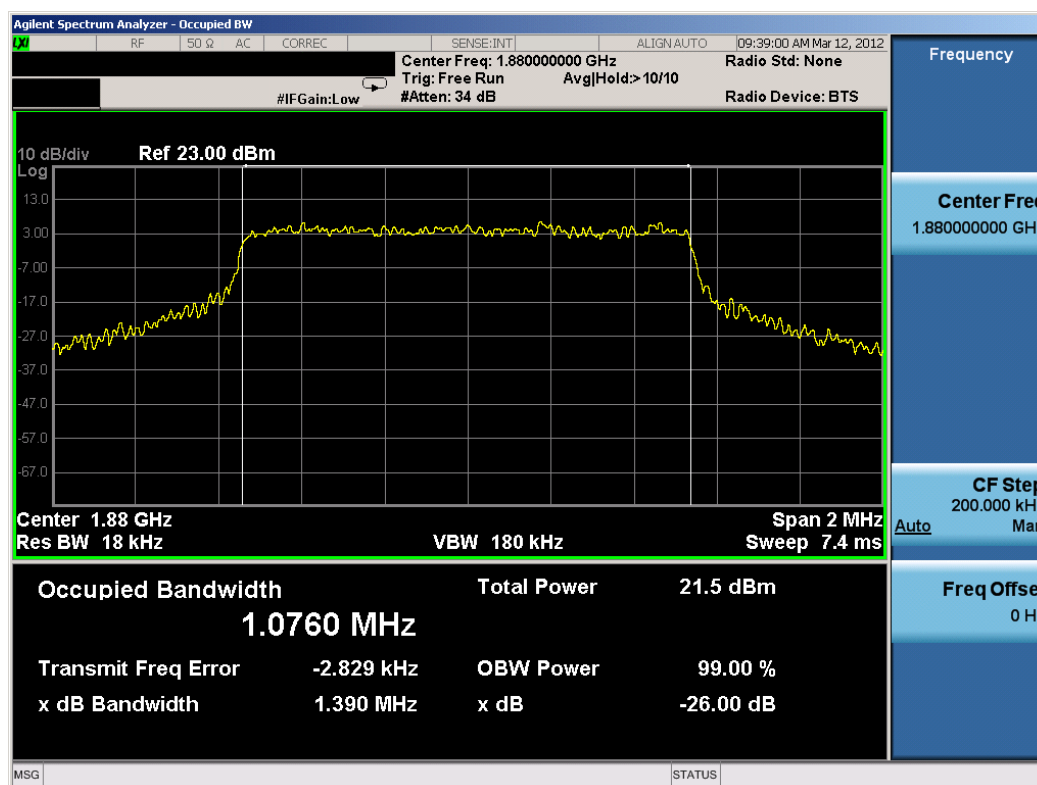


Plot 10-11. Lower Extended Band Edge Plot (5MHz QPSK – RB Size 1, Offset 0)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 109 of 134

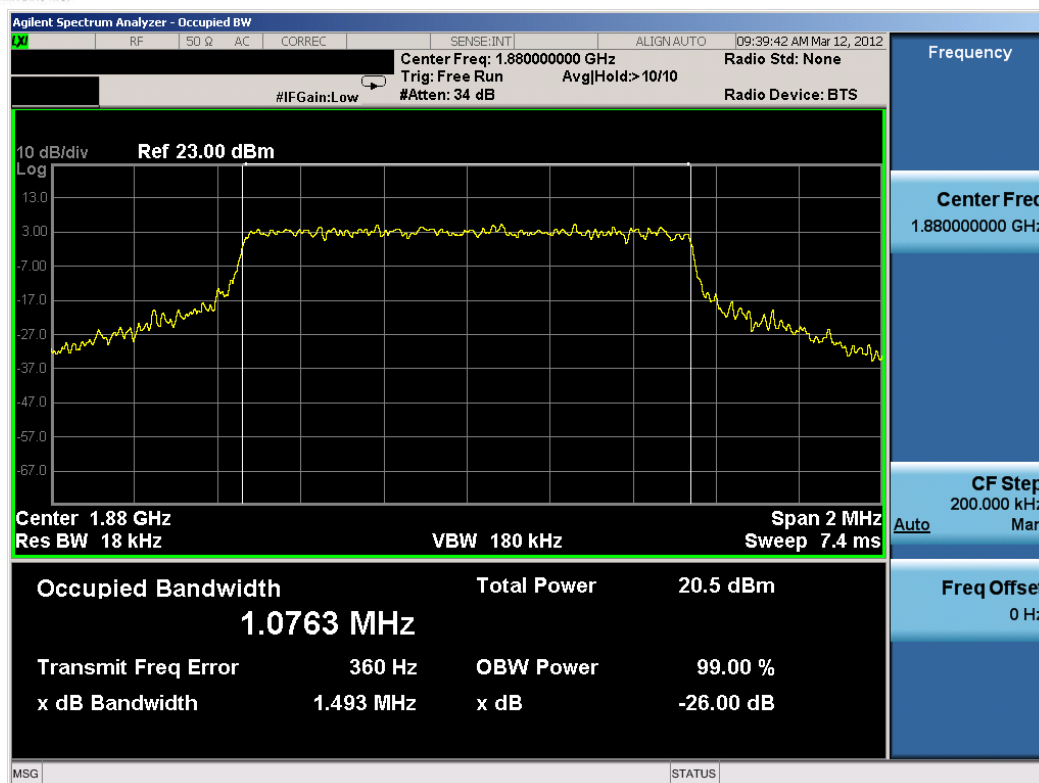


Plot 10-12. Lower Extended Band Edge Plot (5MHz QPSK – RB Size 25, Offset 0)

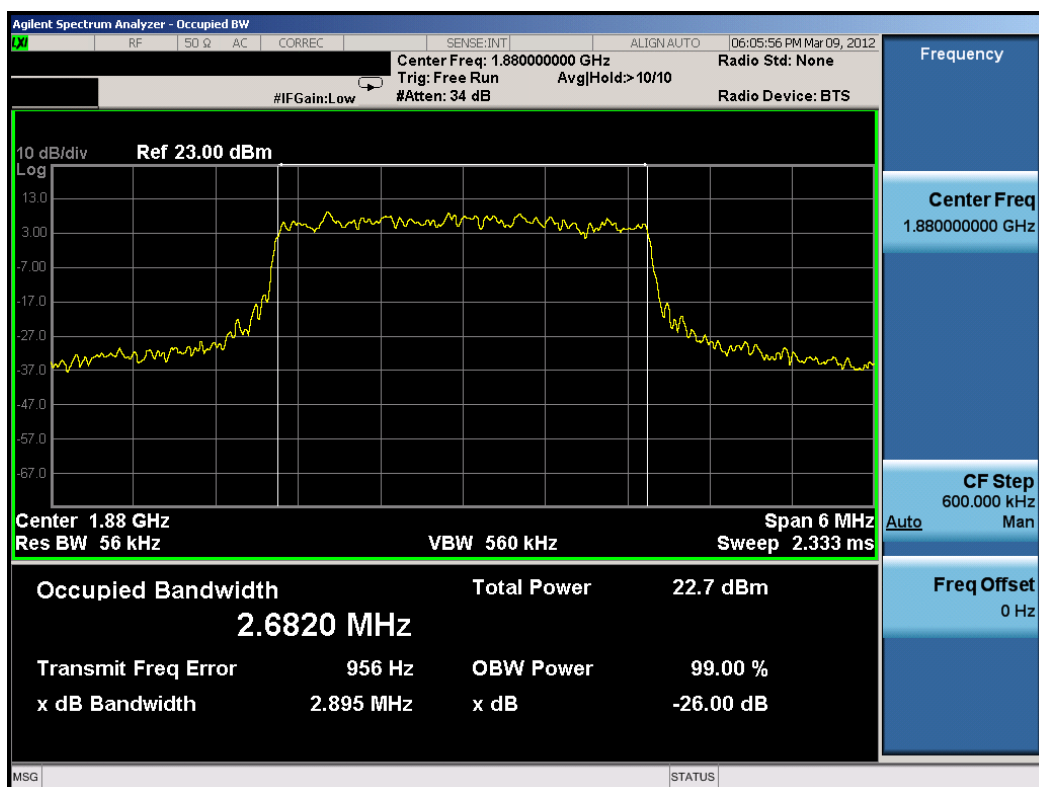


Plot 10-13. Occupied Bandwidth Plot (1.4MHz QPSK – RB Size 6)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 110 of 134

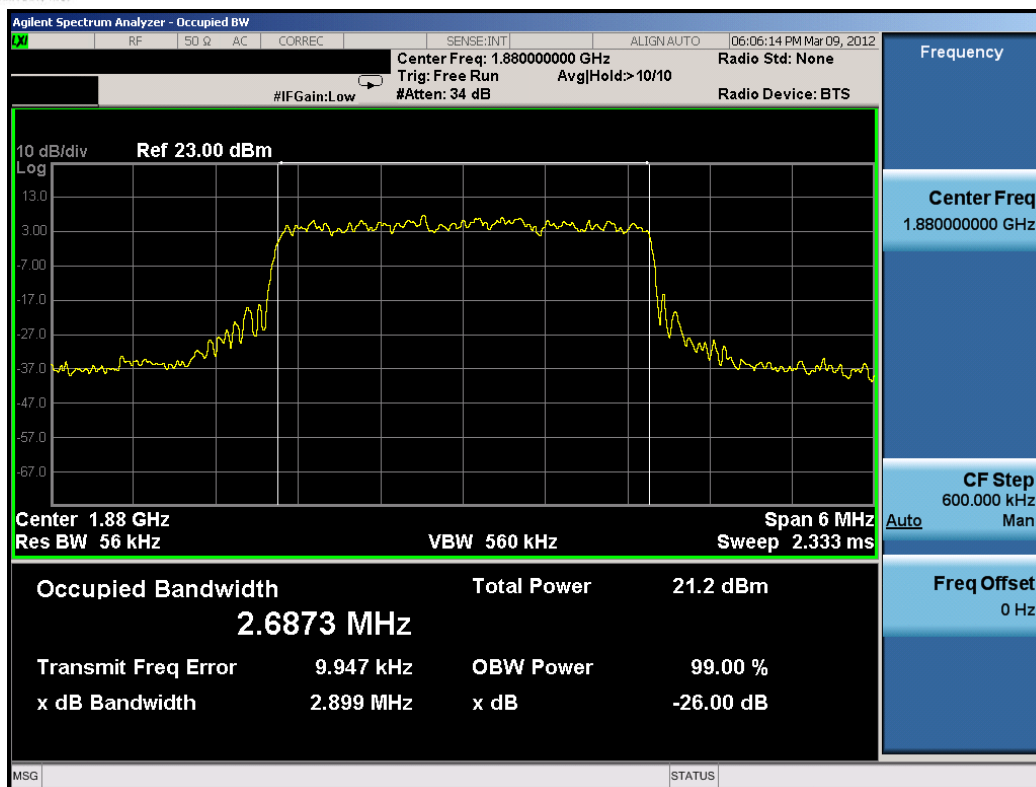


Plot 10-14. Occupied Bandwidth Plot (1.4MHz 16-QAM – RB Size 6)

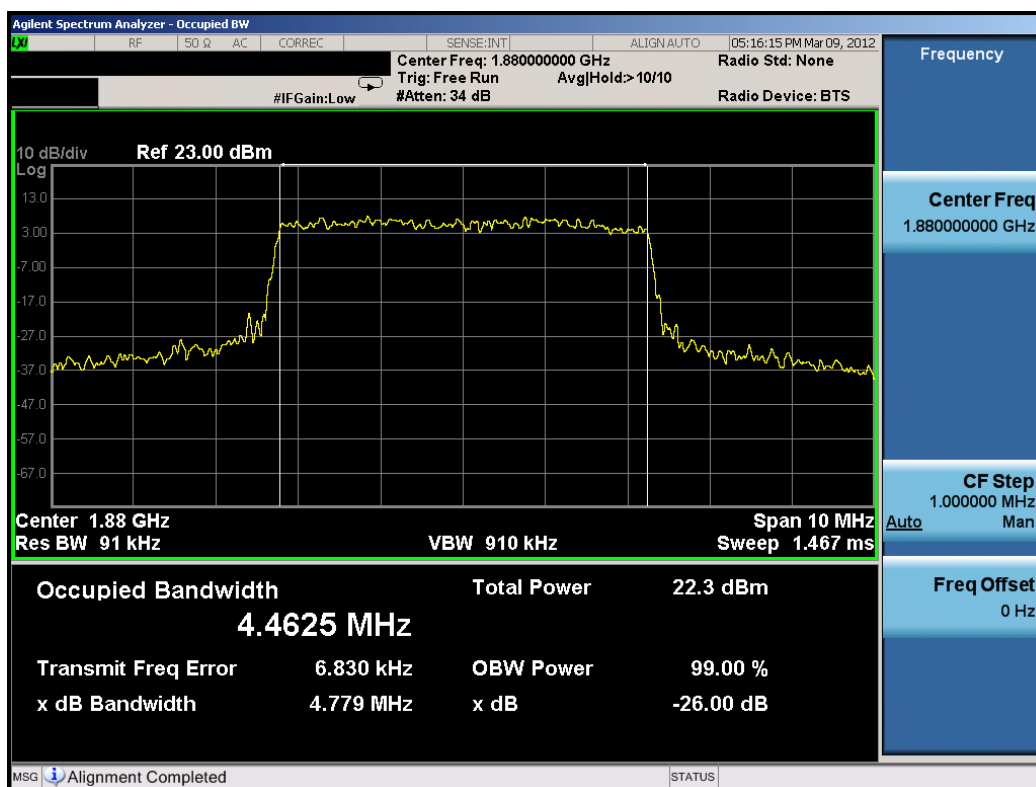


Plot 10-15. Occupied Bandwidth Plot (3MHz QPSK – RB Size 15)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 111 of 134

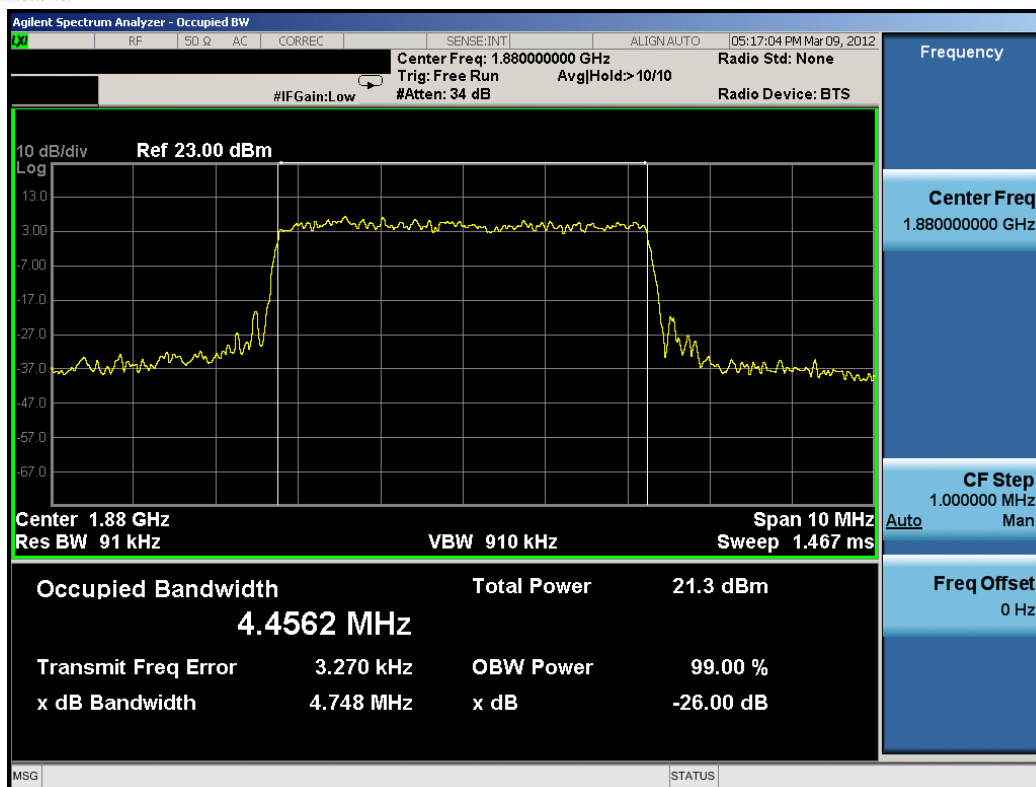


Plot 10-16. Occupied Bandwidth Plot (3MHz 16-QAM – RB Size 15)

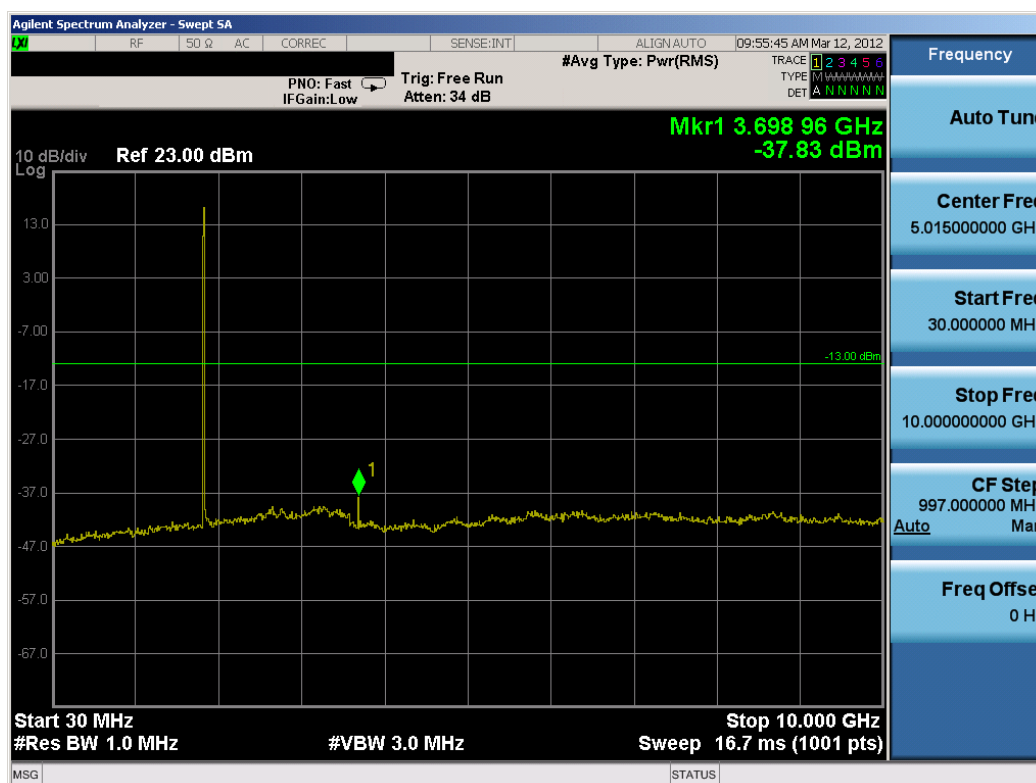


Plot 10-17. Occupied Bandwidth Plot (5MHz QPSK – RB Size 25)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 112 of 134

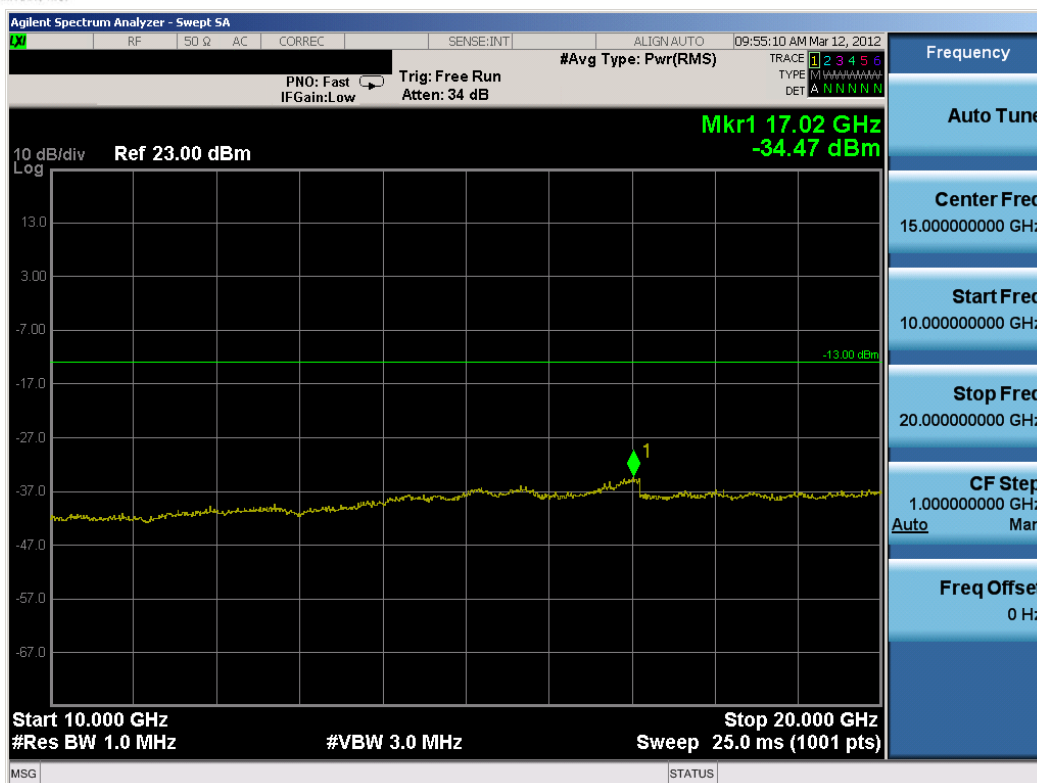


Plot 10-18. Occupied Bandwidth Plot (5MHz 16-QAM – RB Size 25)

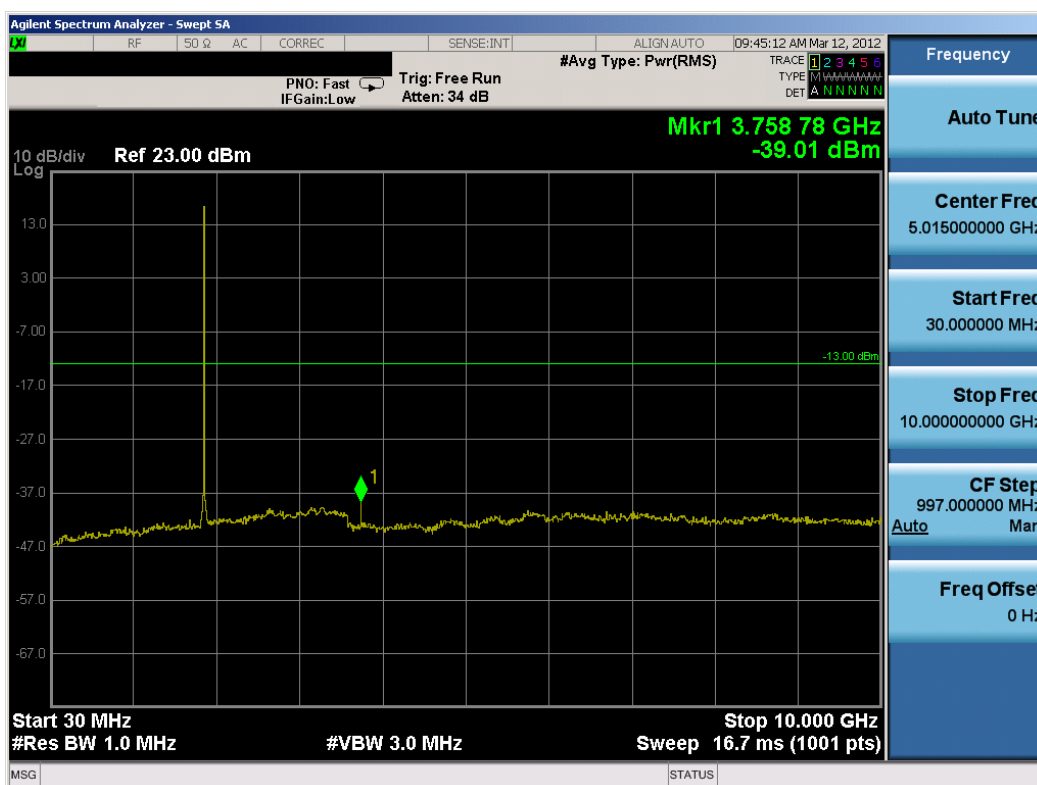


Plot 10-19. Conducted Spurious Plot (1.4MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
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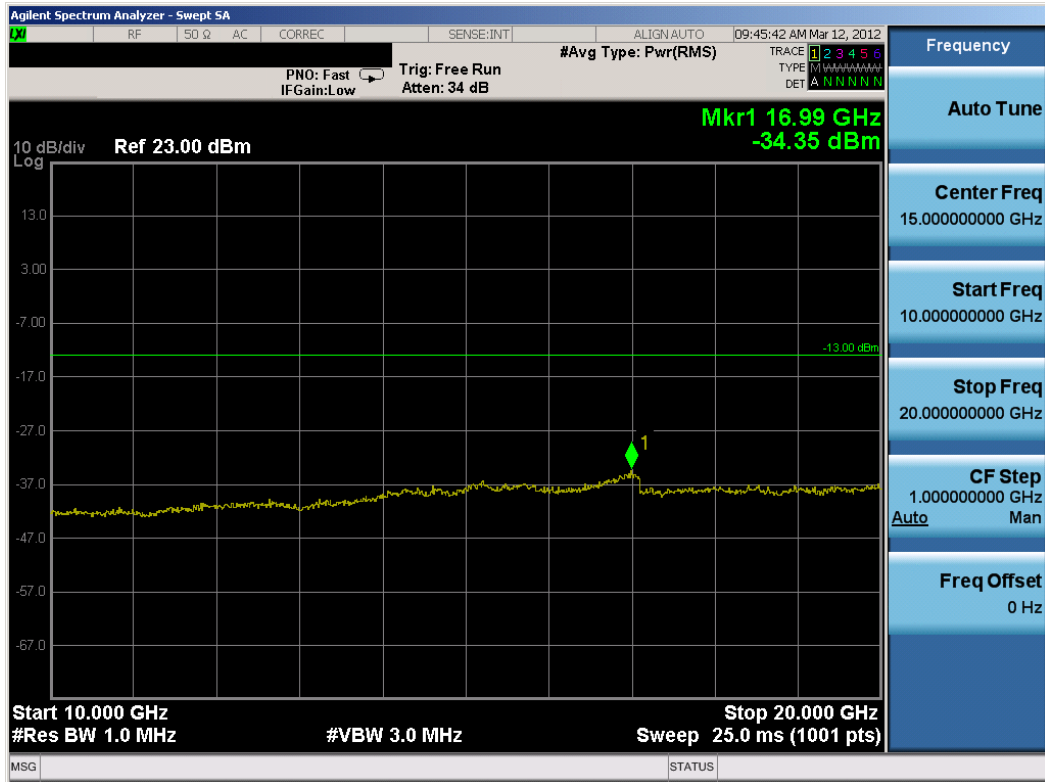


Plot 10-20. Conducted Spurious Plot (1.4MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

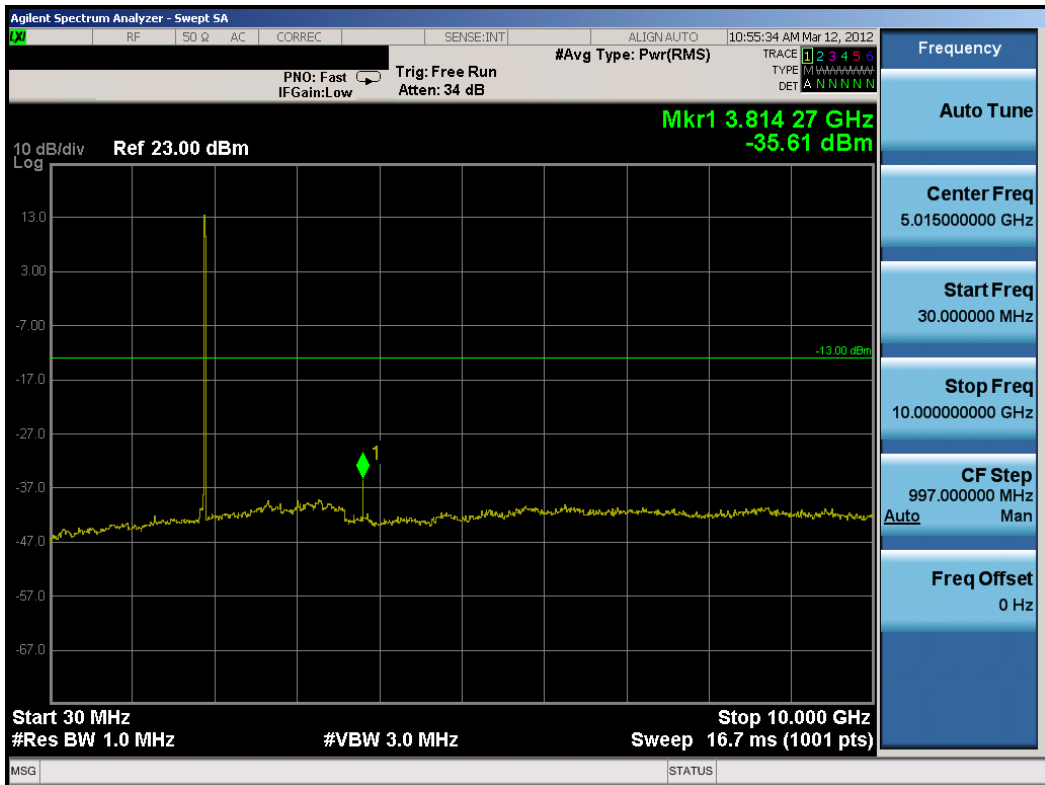


Plot 10-21. Conducted Spurious Plot (1.4MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
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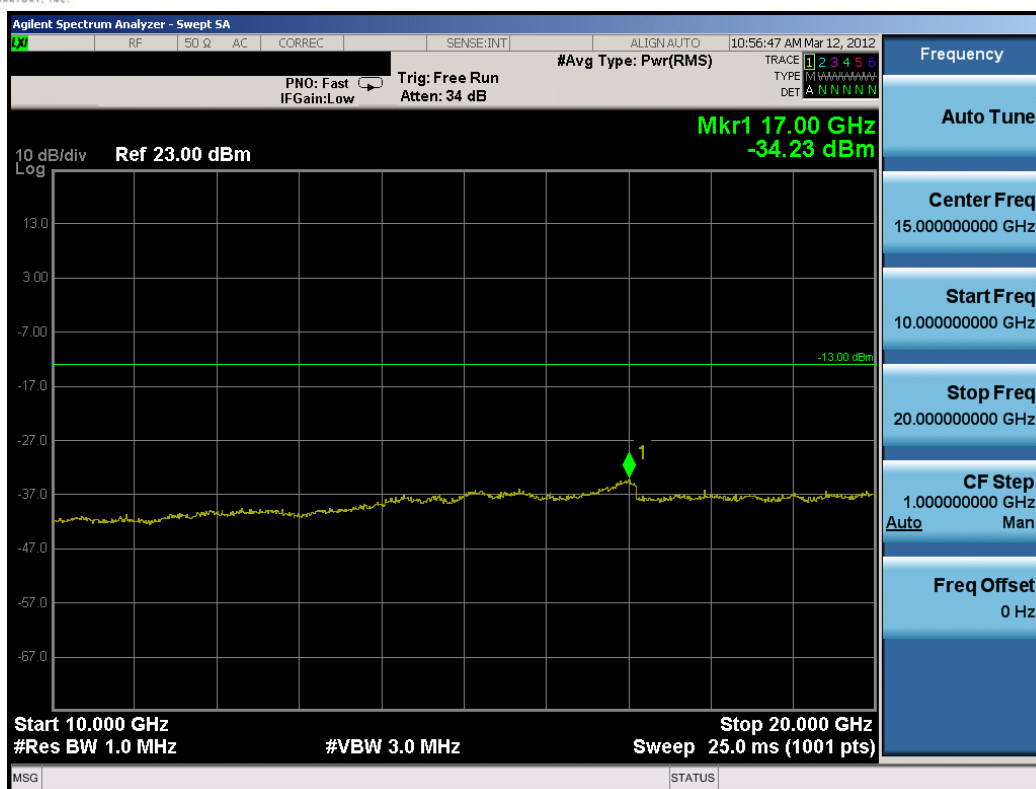


Plot 10-22. Conducted Spurious Plot (1.4MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

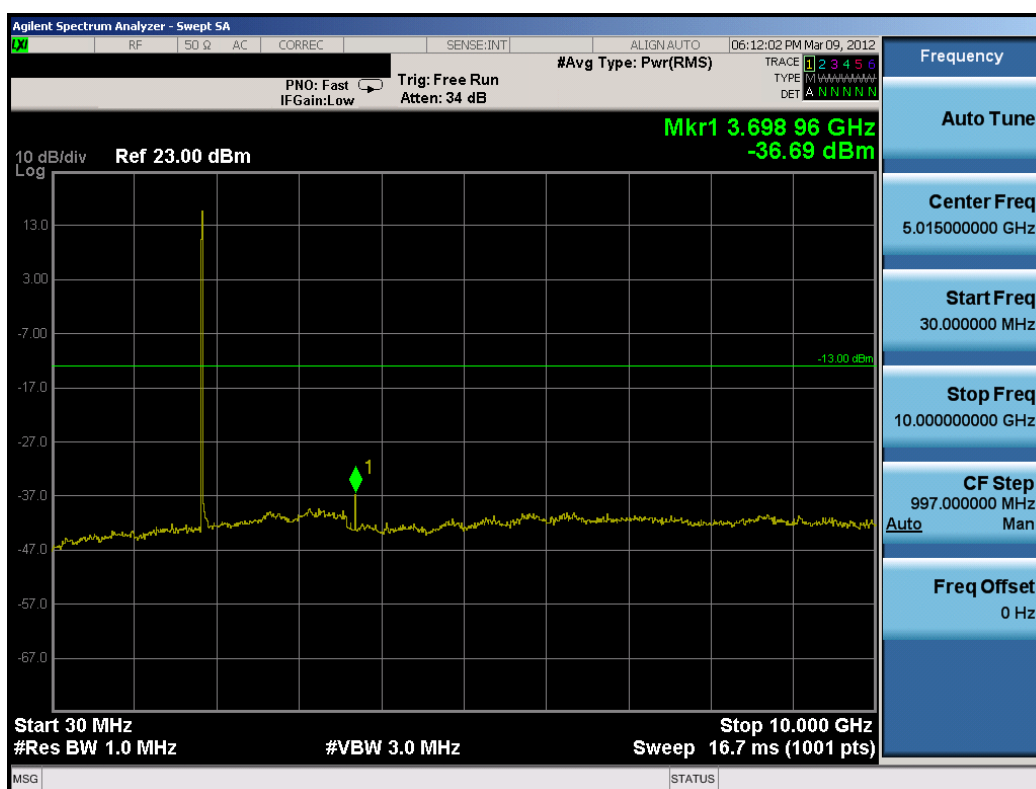


Plot 10-23. Conducted Spurious Plot (1.4MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
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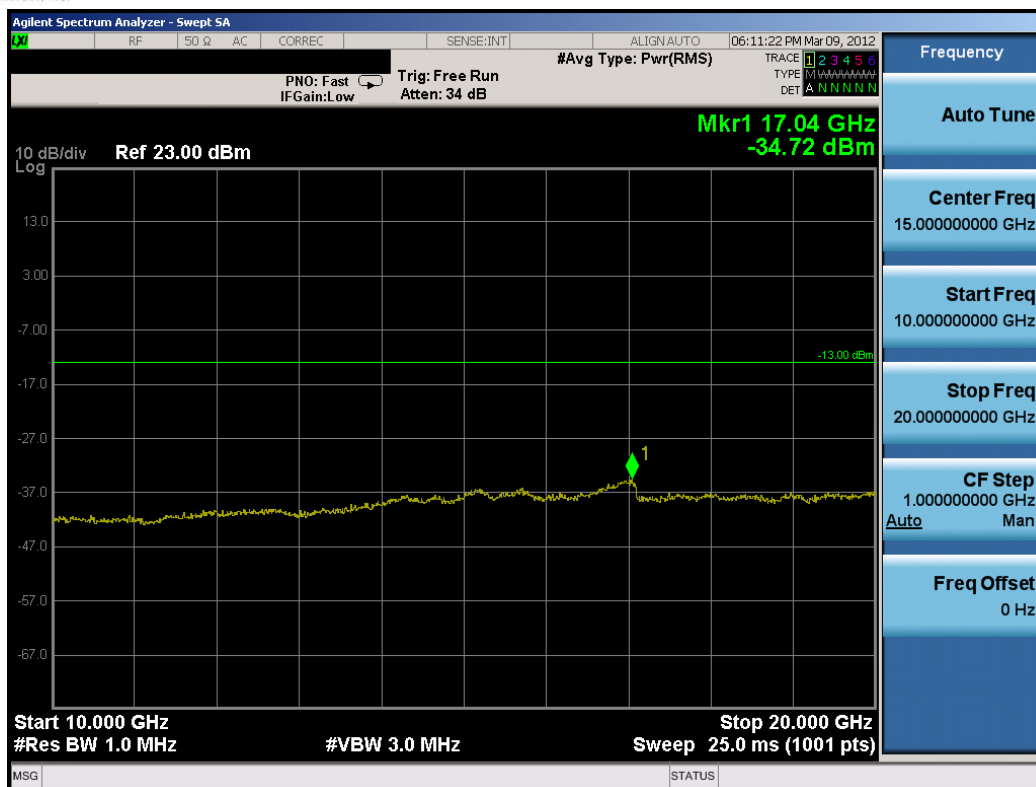


Plot 10-24. Conducted Spurious Plot (1.4MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

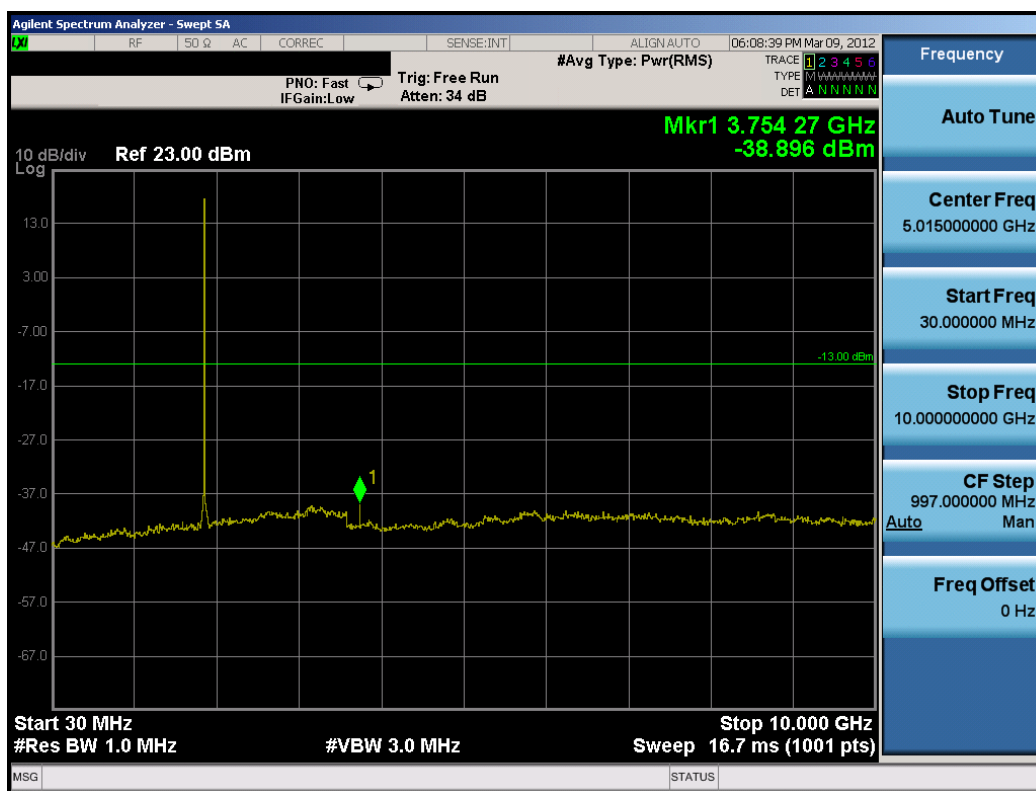


Plot 10-25. Conducted Spurious Plot (3MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
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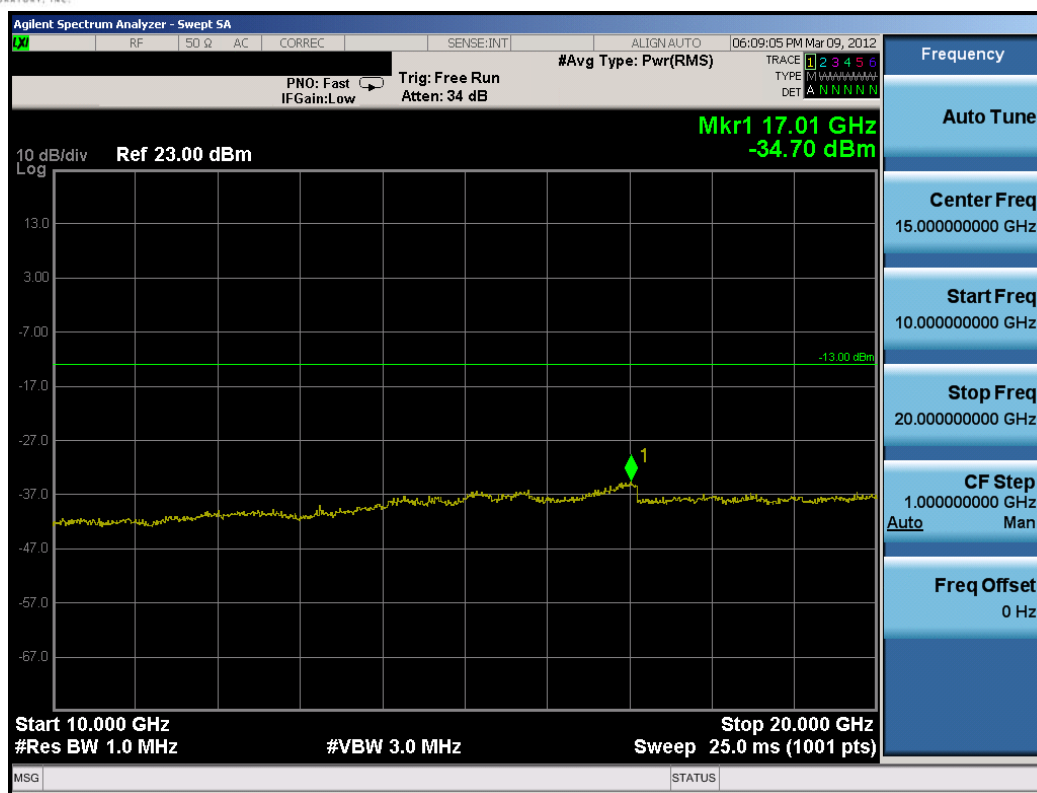


Plot 10-26. Conducted Spurious Plot (3MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

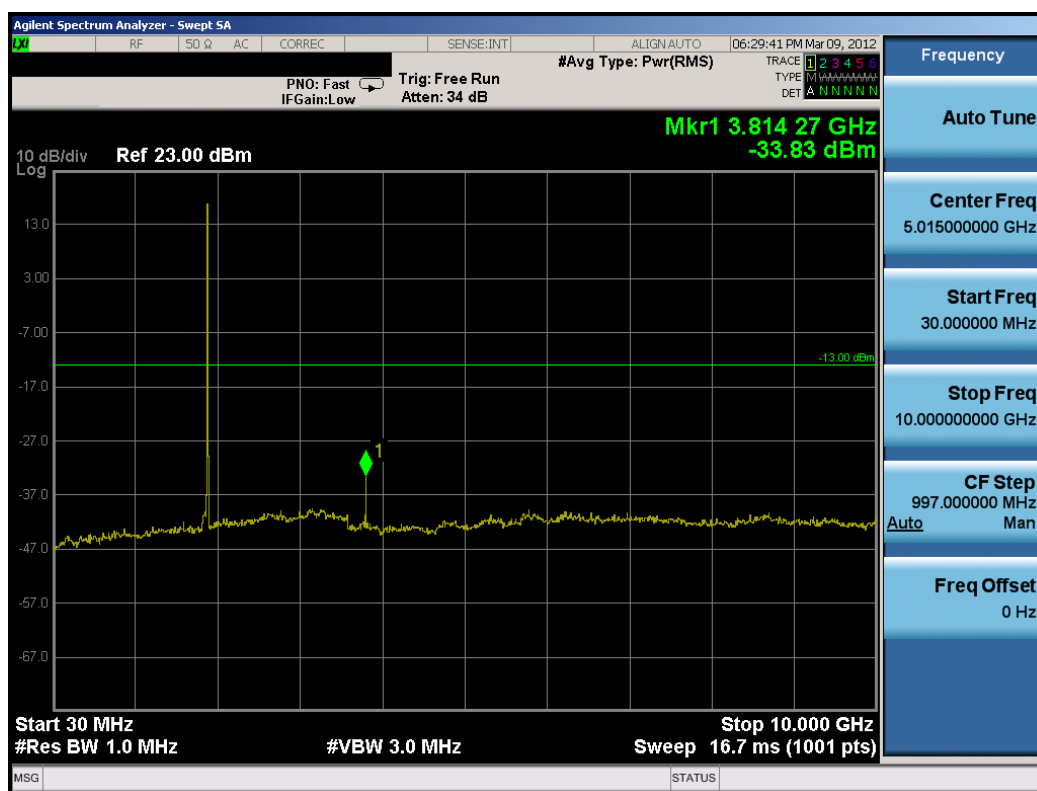


Plot 10-27. Conducted Spurious Plot (3MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 117 of 134

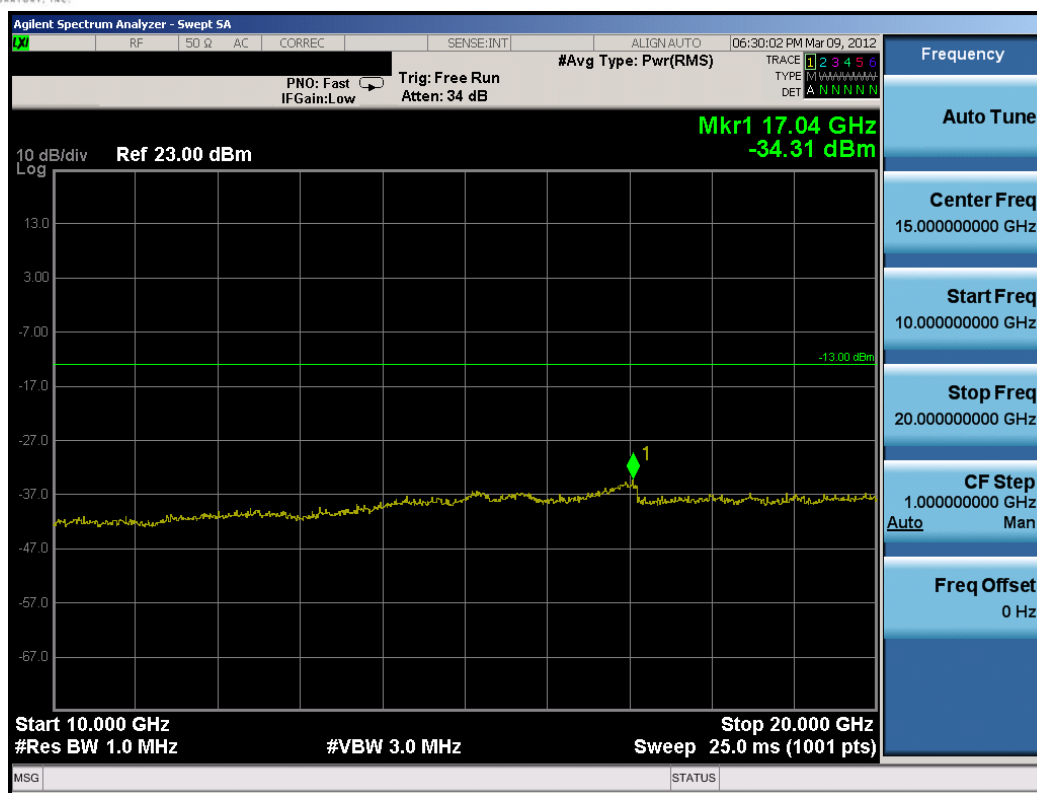


Plot 10-28. Conducted Spurious Plot (3MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

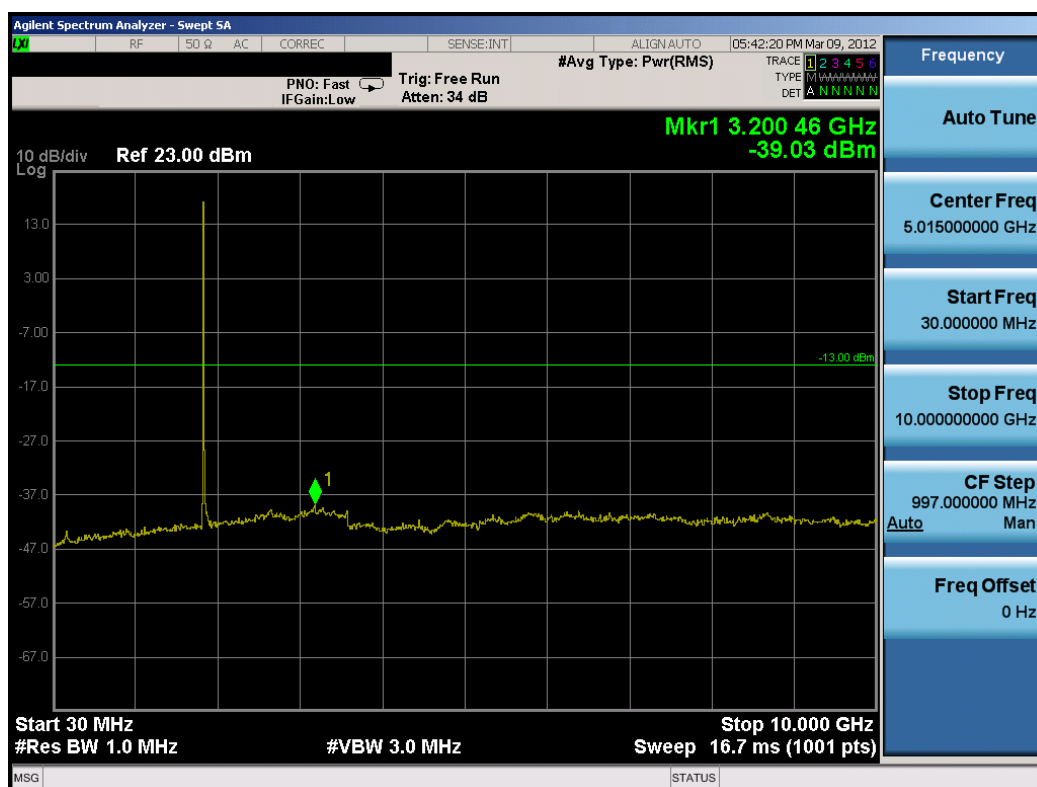


Plot 10-29. Conducted Spurious Plot (3MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
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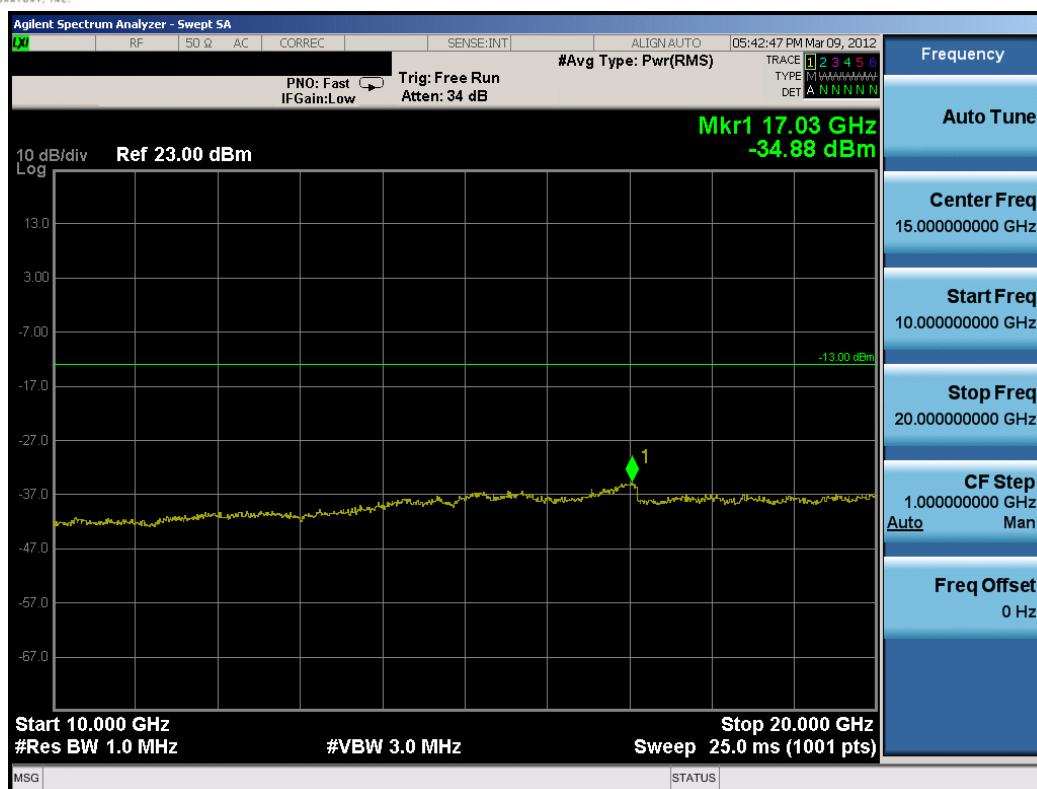


Plot 10-30. Conducted Spurious Plot (3MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

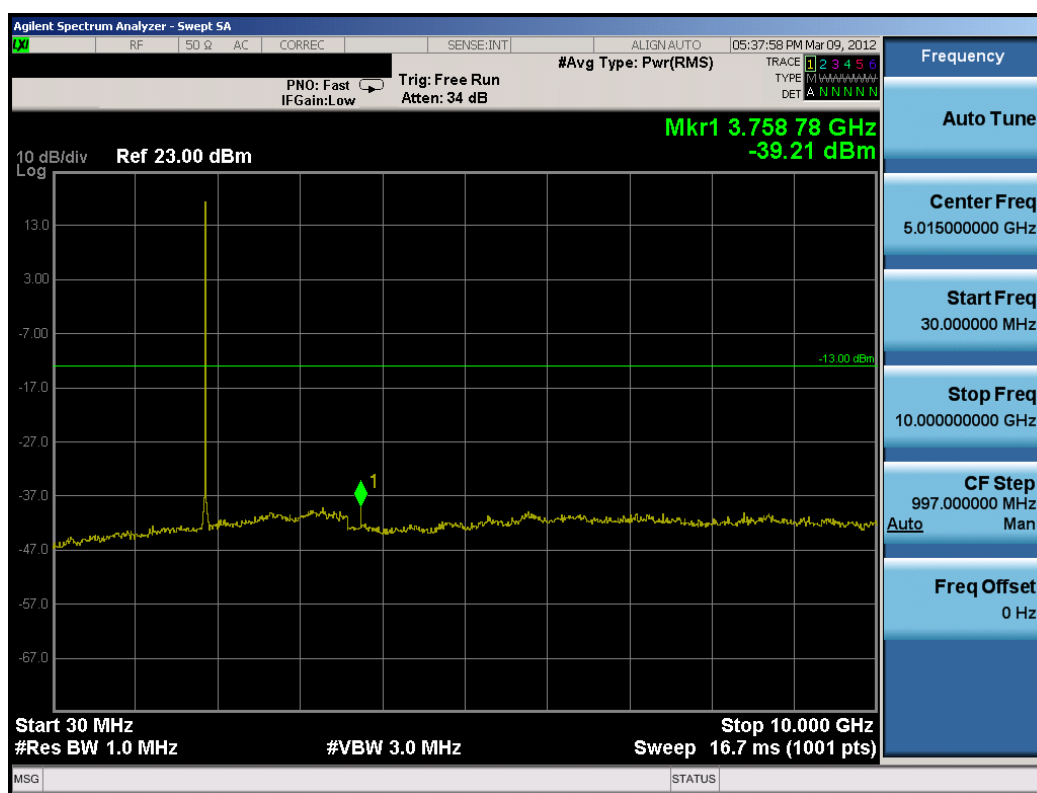


Plot 10-31. Conducted Spurious Plot (5MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 119 of 134

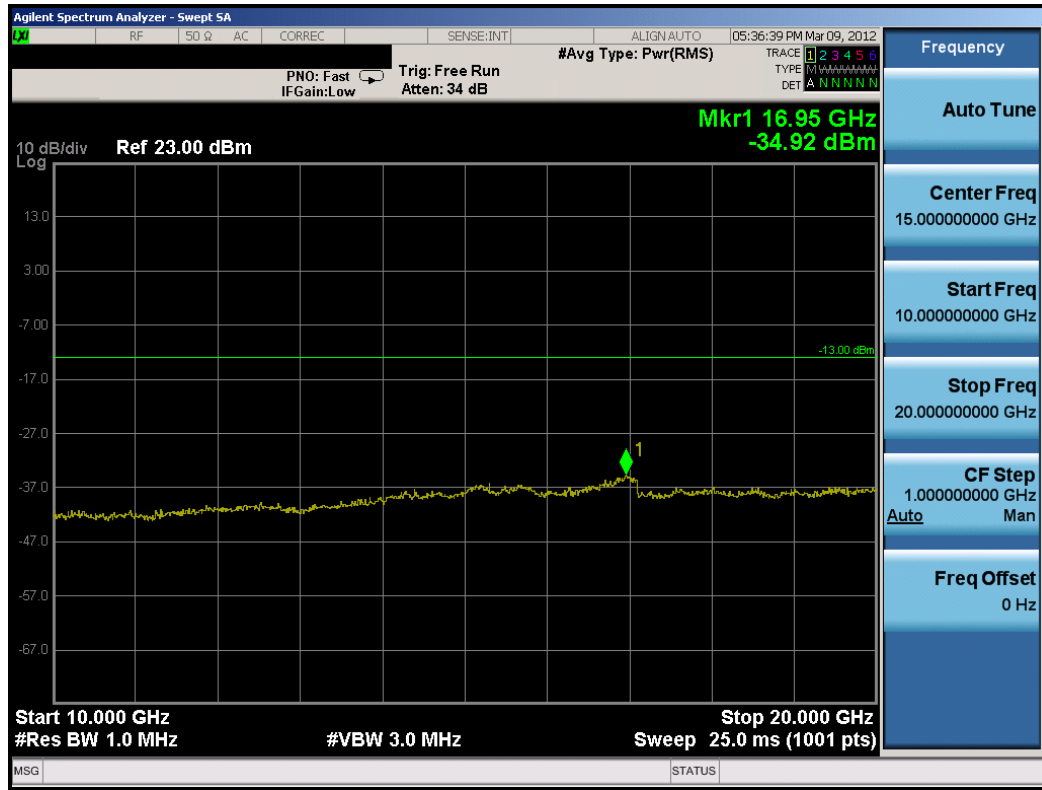


Plot 10-32. Conducted Spurious Plot (5MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

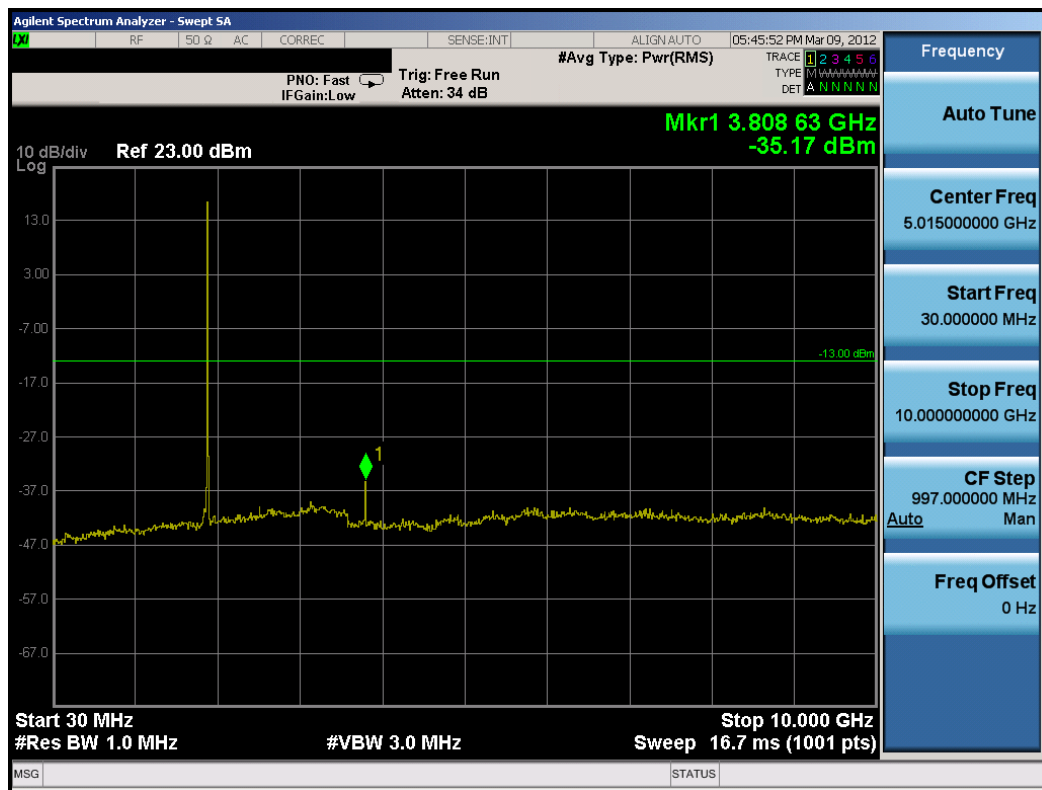


Plot 10-33. Conducted Spurious Plot (5MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 120 of 134

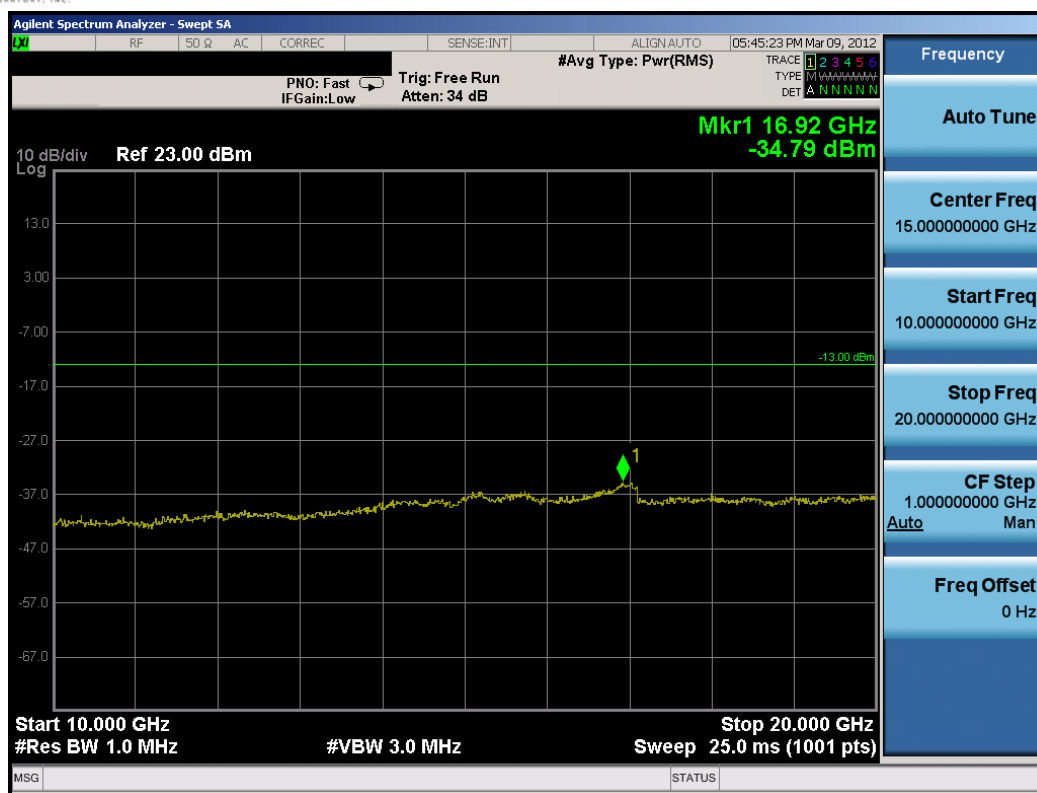


Plot 10-34. Conducted Spurious Plot (5MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

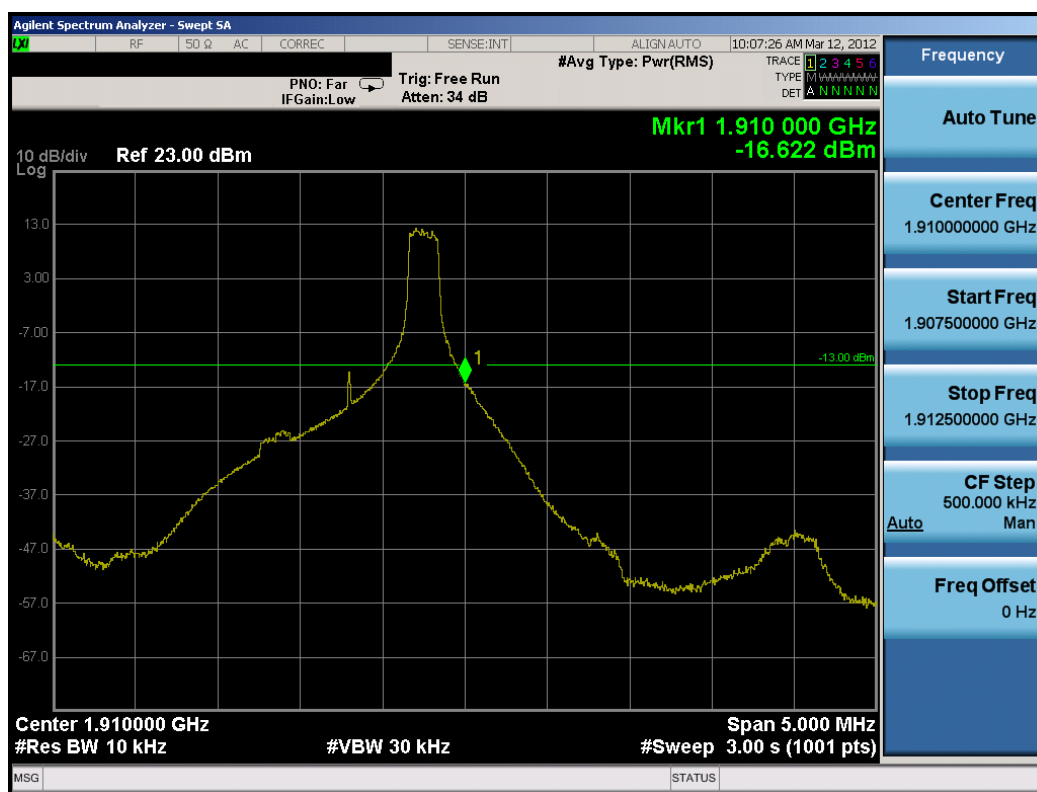


Plot 10-35. Conducted Spurious Plot (5MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 121 of 134

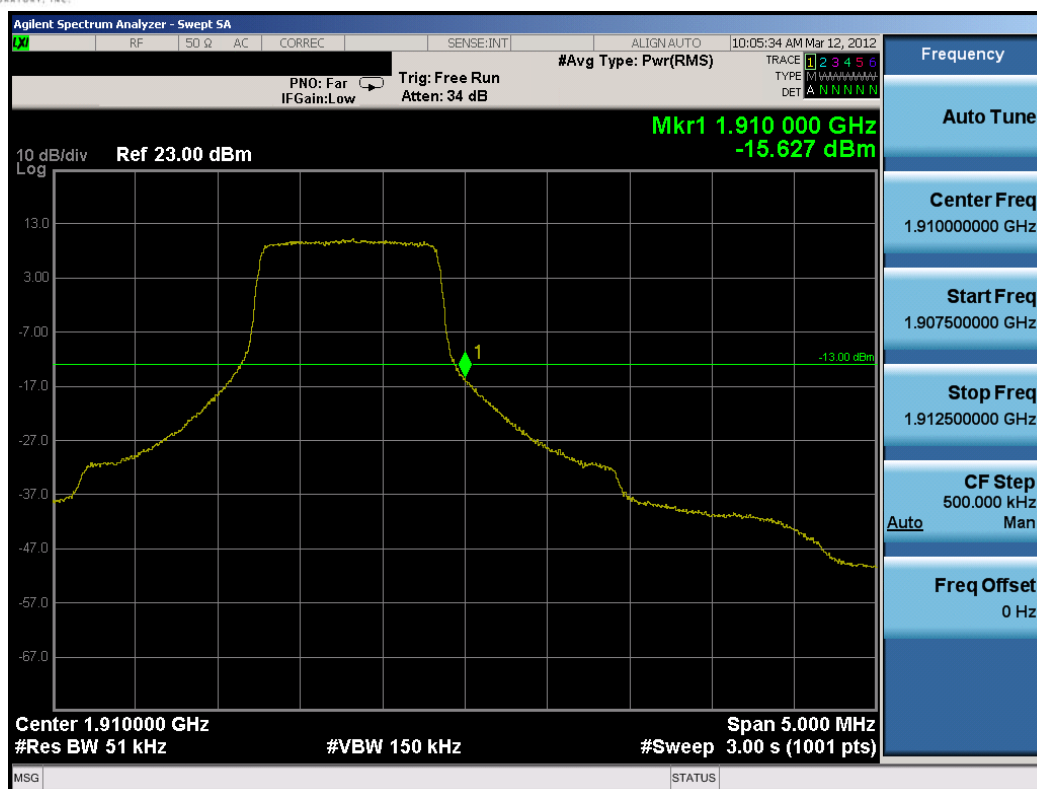


Plot 10-36. Conducted Spurious Plot (5MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

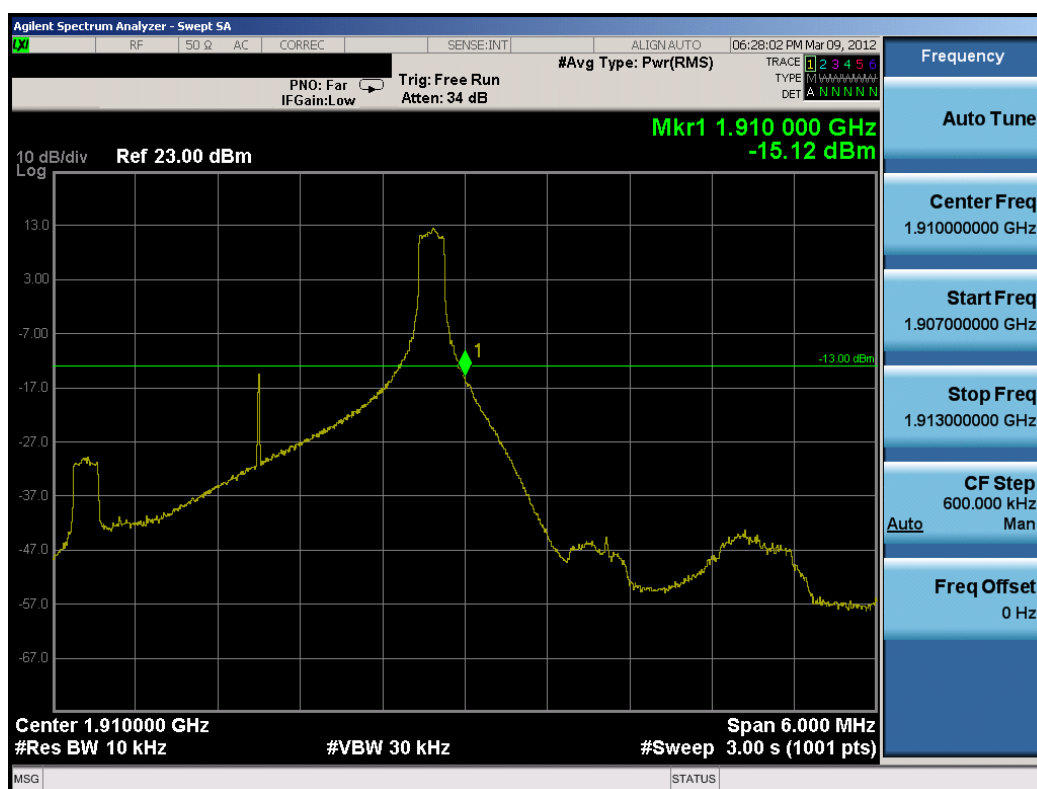


Plot 10-37. Upper Band Edge Plot (1.4MHz QPSK – RB Size 1, Offset 5)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
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Plot 10-38. Upper Band Edge Plot (1.4MHz QPSK – RB Size 6, Offset 0)

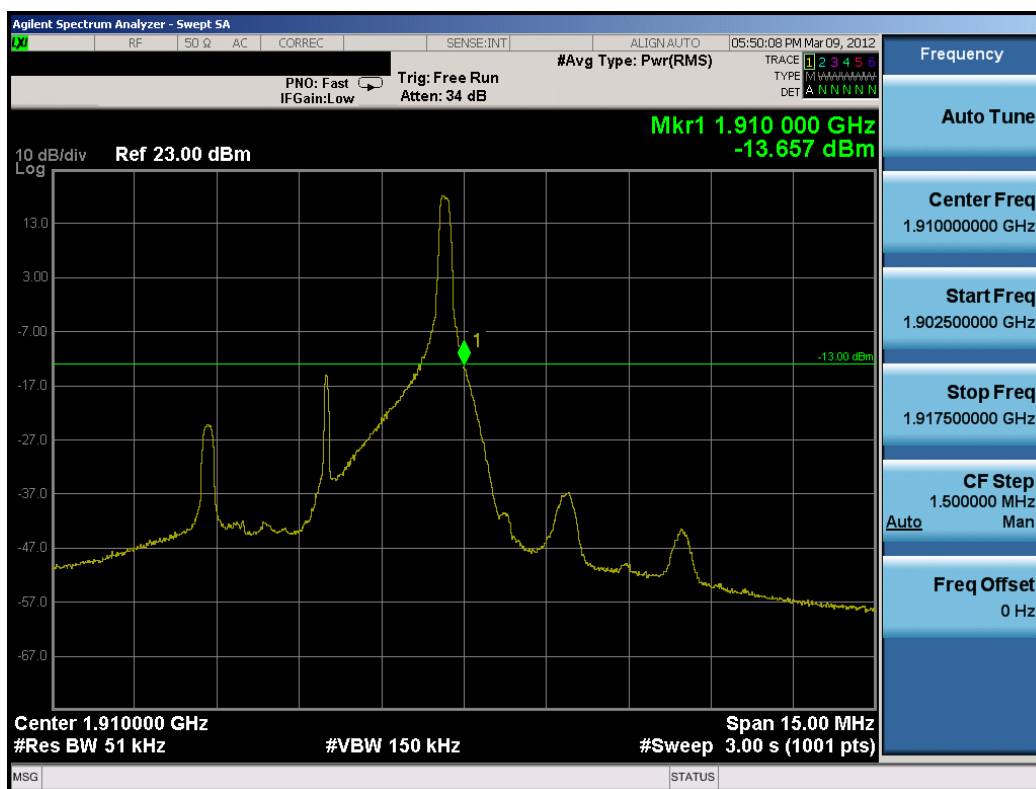


Plot 10-39. Upper Band Edge Plot (3MHz QPSK – RB Size 1, Offset 14)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 123 of 134

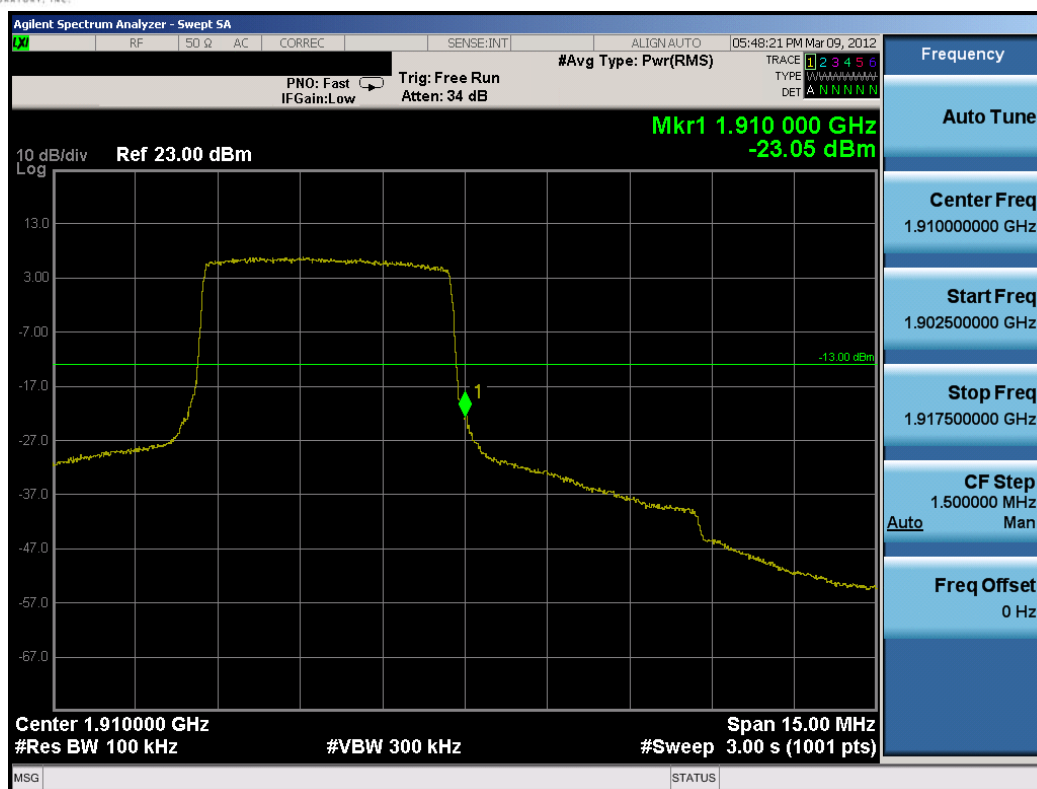


Plot 10-40. Upper Band Edge Plot (3MHz QPSK – RB Size 15, Offset 0)

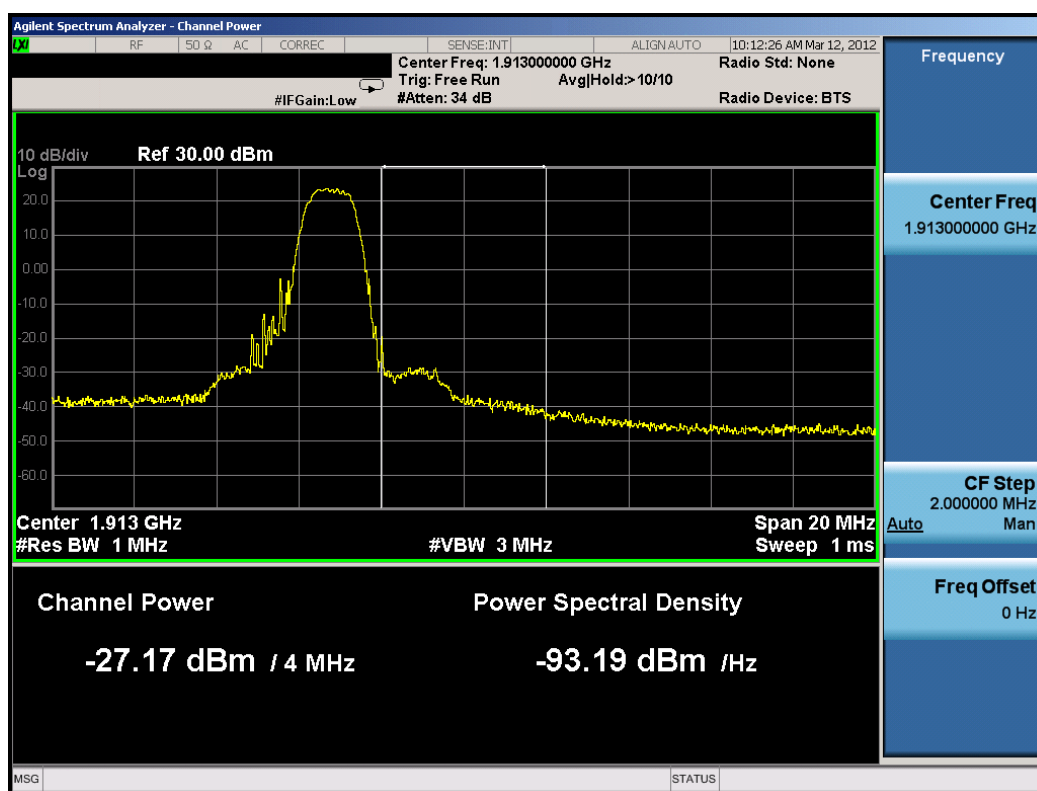


Plot 10-41. Upper Band Edge Plot (5MHz QPSK – RB Size 1, Offset 24)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 124 of 134

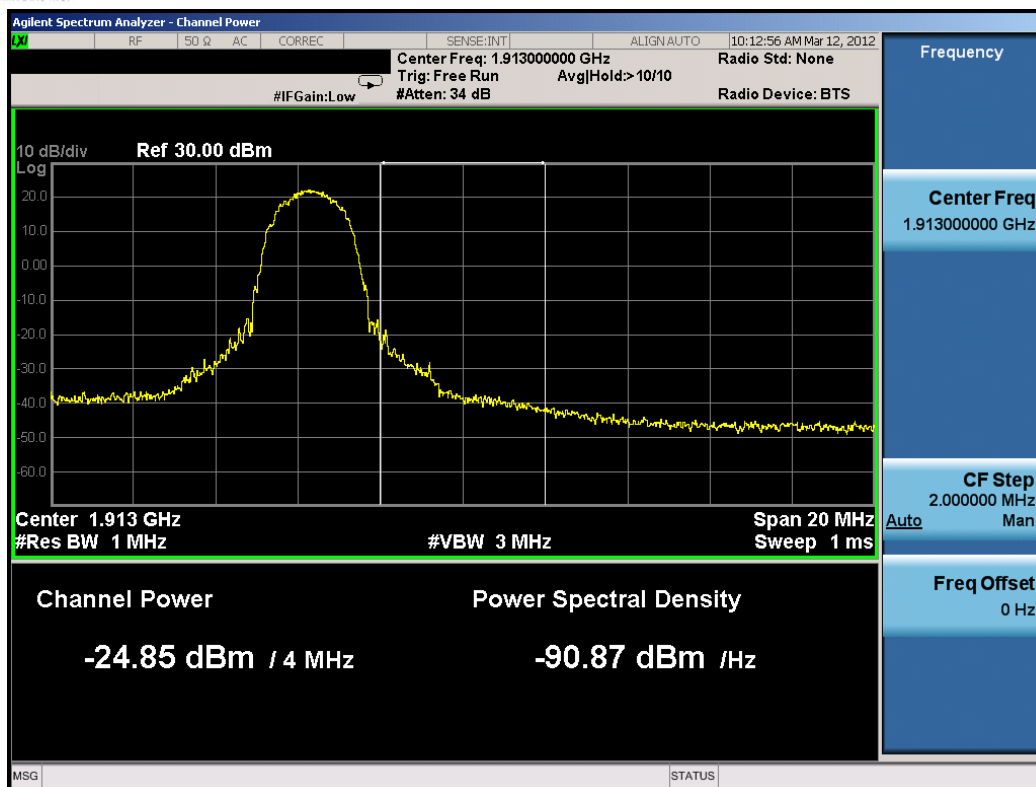


Plot 10-42. Upper Band Edge Plot (5MHz QPSK – RB Size 25, Offset 0)

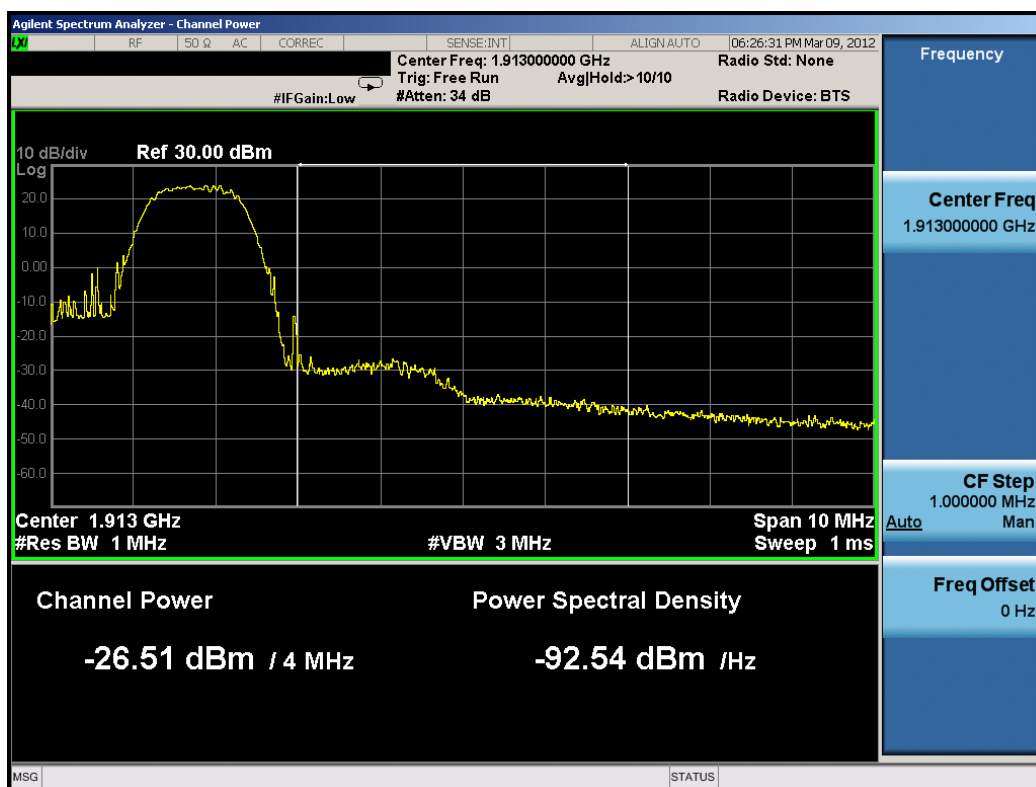


Plot 10-43. Upper Extended Band Edge Plot (1.4MHz QPSK – RB Size 1, Offset 5)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
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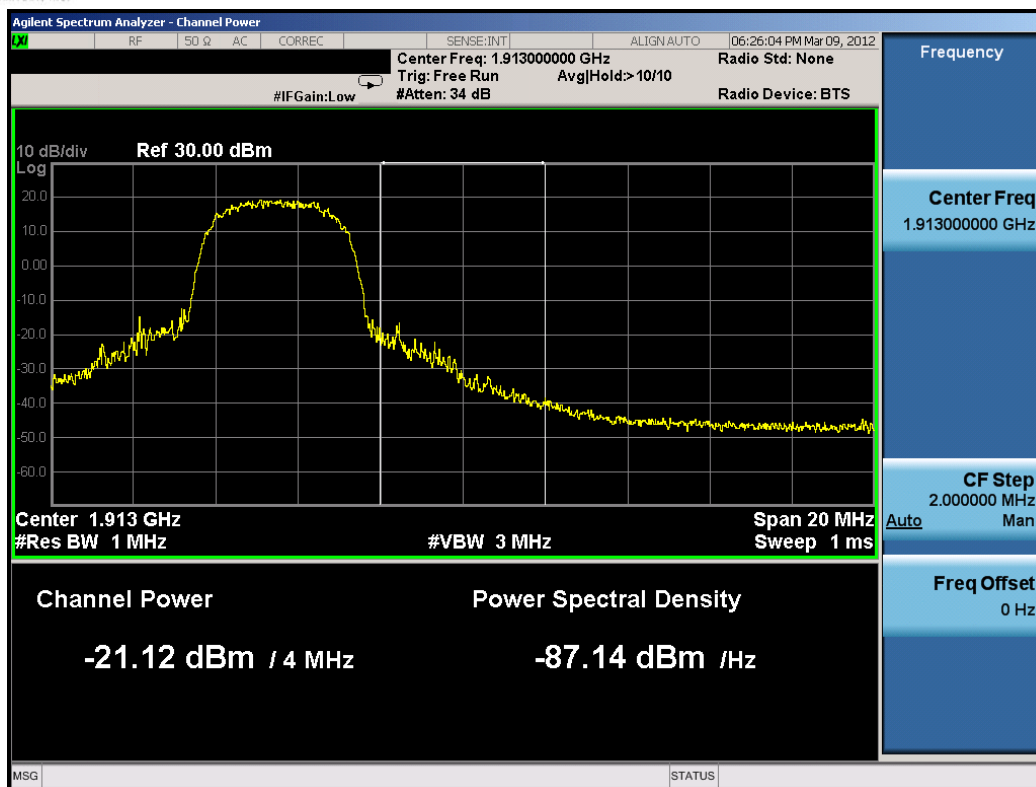


Plot 10-44. Upper Extended Band Edge Plot (1.4MHz QPSK – RB Size 6, Offset 0)

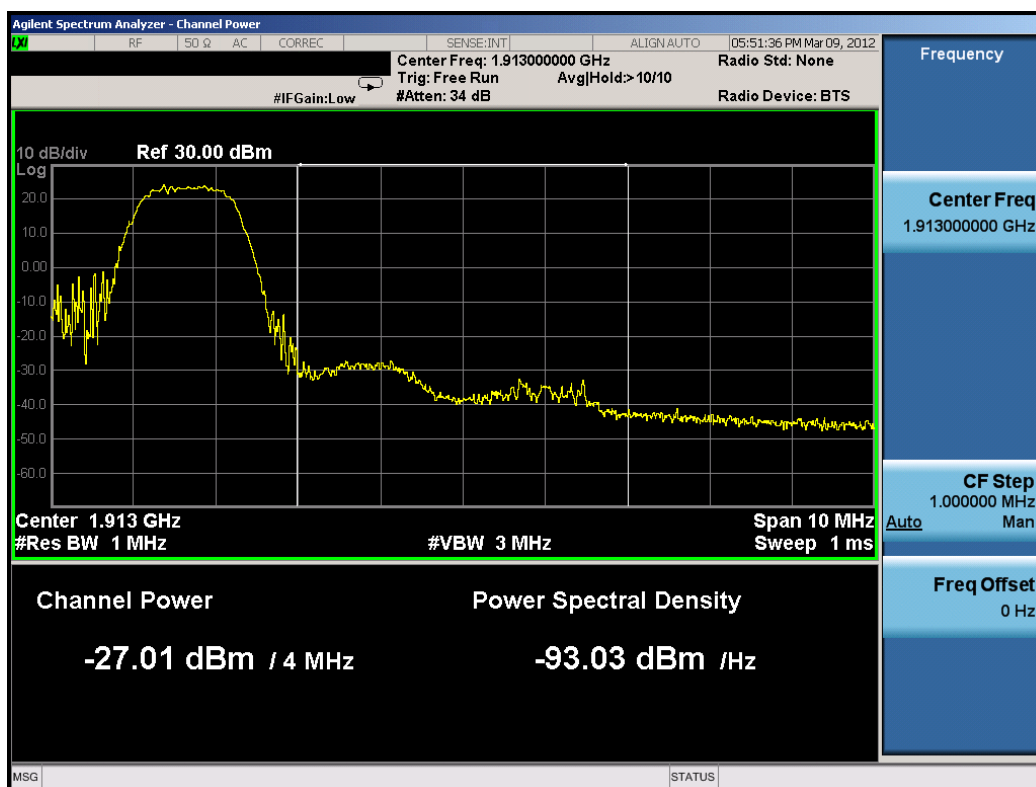


Plot 10-45. Upper Extended Band Edge Plot (3MHz QPSK – RB Size 1, Offset 14)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
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Plot 10-46. Upper Extended Band Edge Plot (3MHz QPSK – RB Size 15, Offset 0)

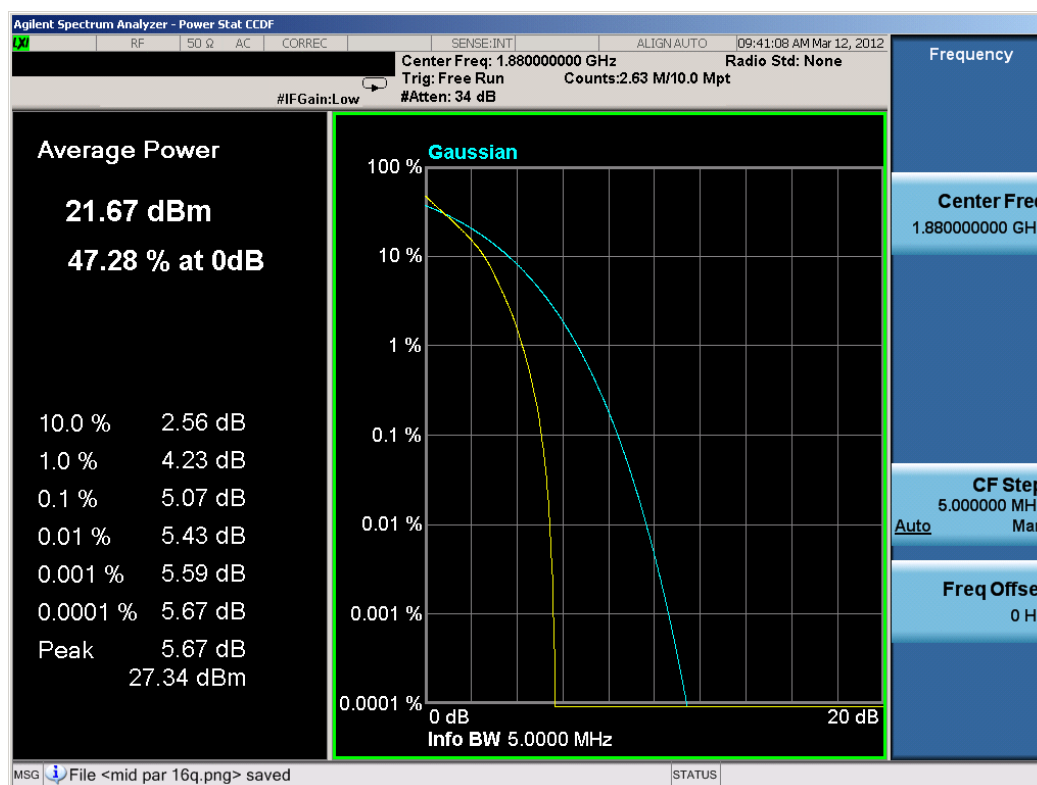


Plot 10-47. Upper Extended Band Edge Plot (5MHz QPSK – RB Size 1, Offset 24)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1203080270.A3L	Test Dates: March 8 - April 9, 2012	EUT Type: Portable Handset		Page 127 of 134

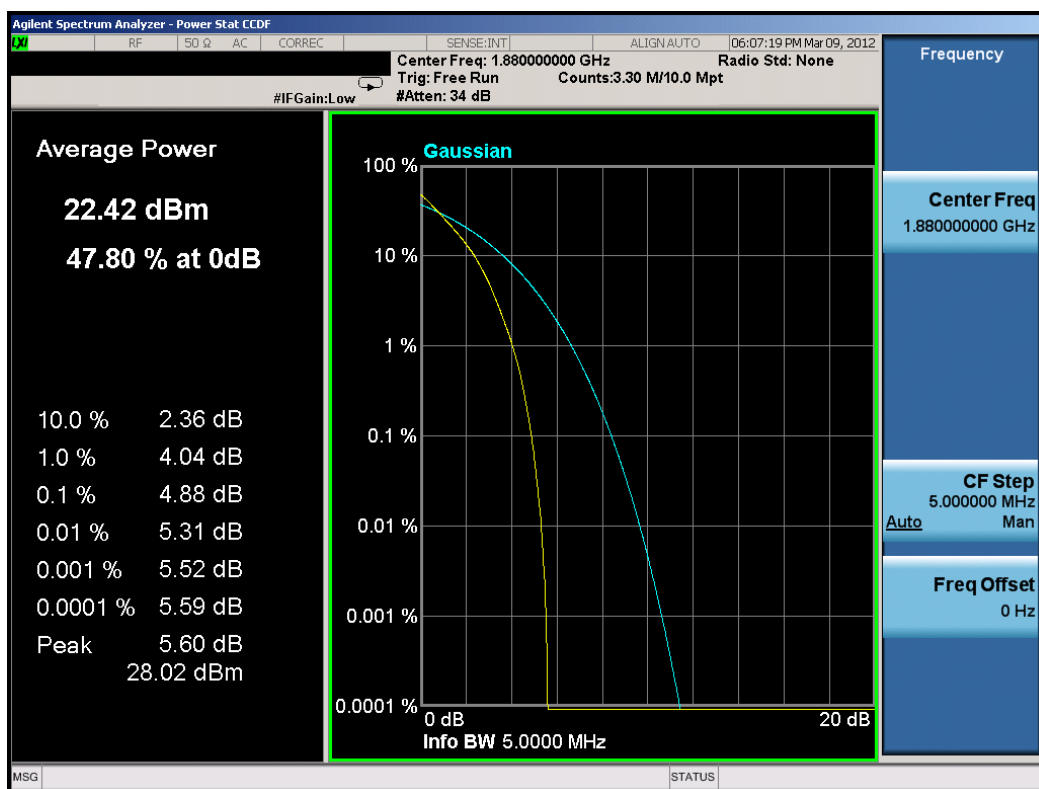
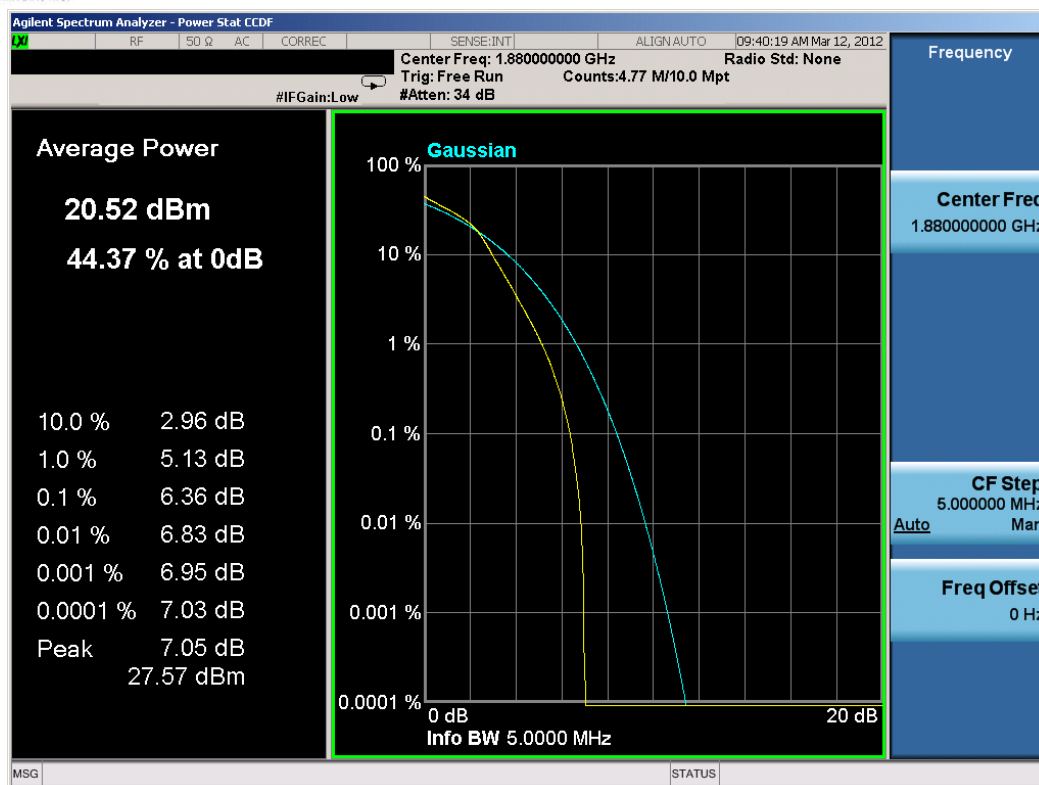


Plot 10-48. Upper Extended Band Edge Plot (5MHz QPSK – RB Size 25, Offset 0)

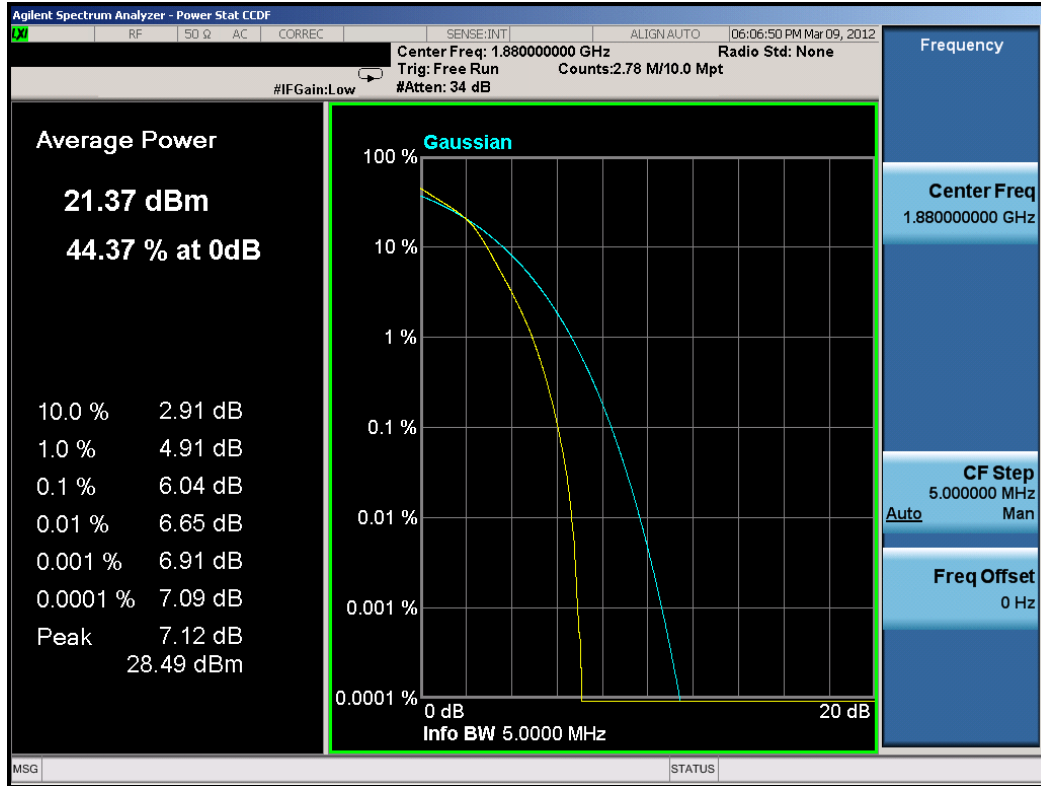


Plot 10-49. PAR Plot (1.4MHz QPSK – RB Size 6)

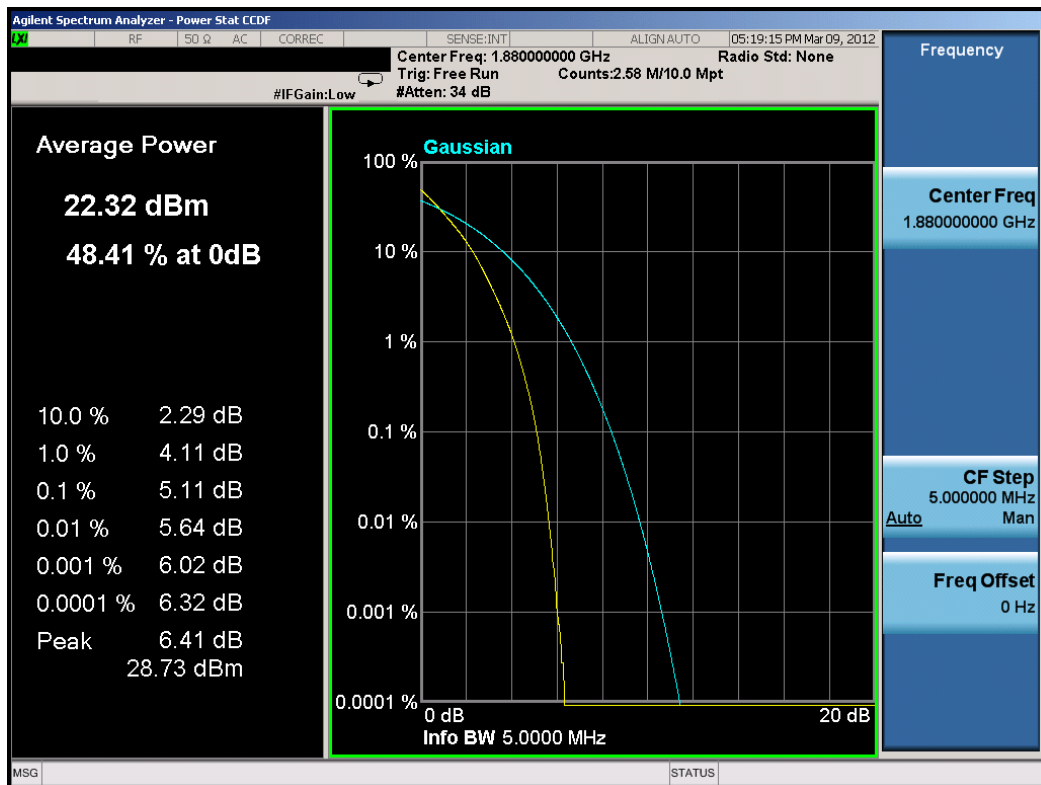
FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
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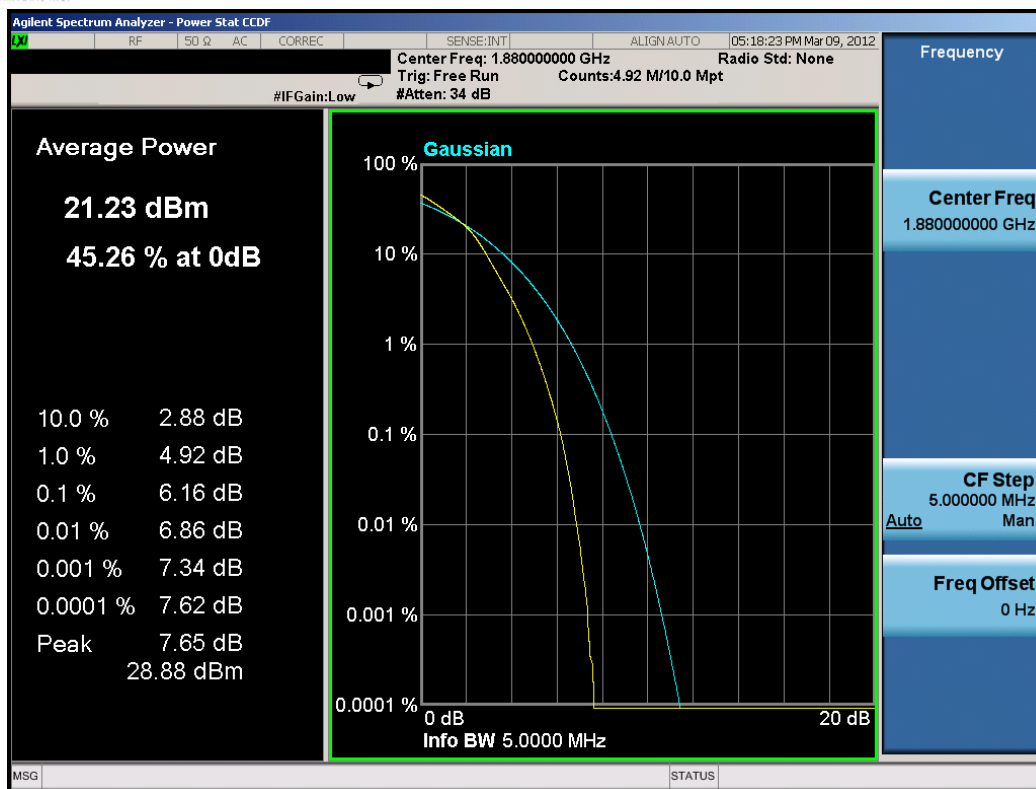


Plot 10-52. PAR Plot (3MHz 16QAM – RB Size 15)



Plot 10-53. PAR Plot (5MHz QPSK – RB Size 25)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
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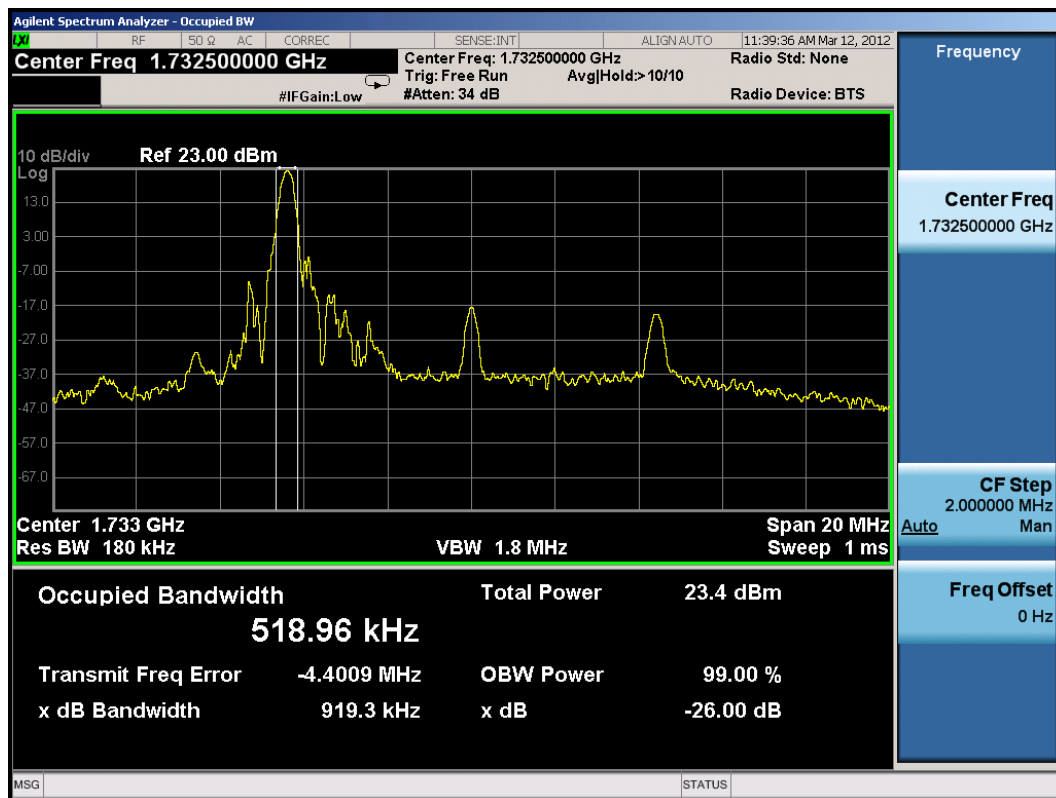


Plot 10-54. PAR Plot (5MHz 16QAM – RB Size 25)

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
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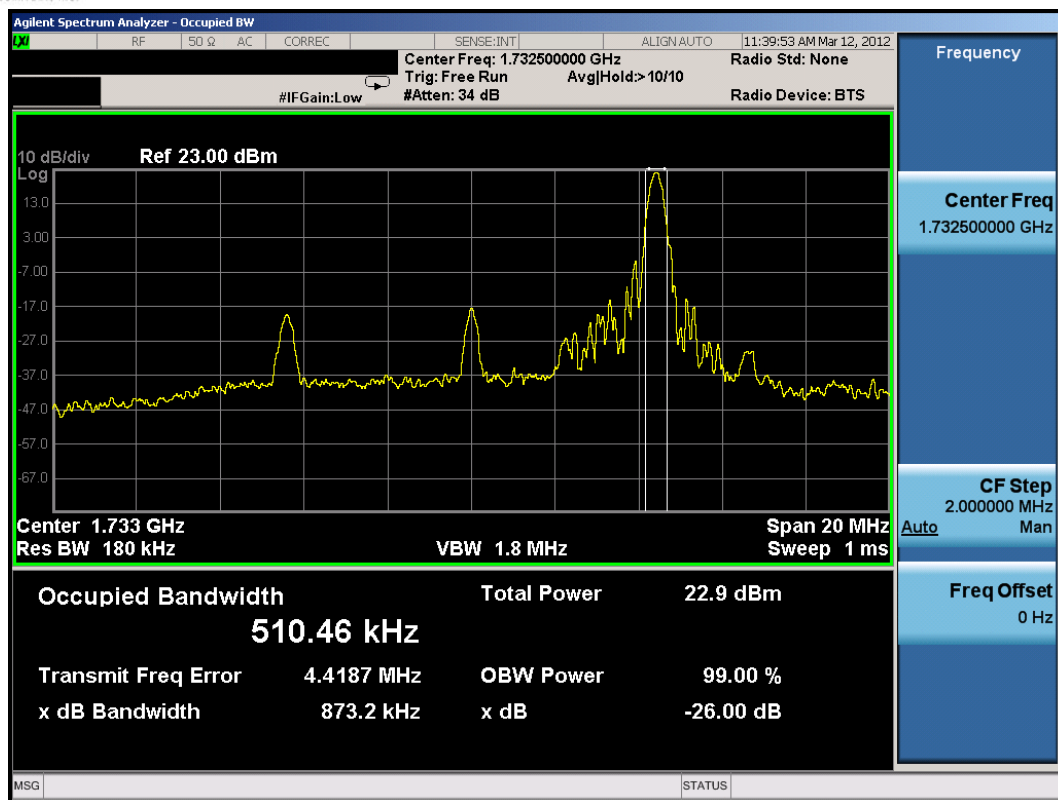
11.0 ADDENDUM - LTE WITH 1RB EMISSION BANDWIDTH

The following plots are representative of the emission bandwidth for LTE operating with 1 RB. Based on Part 27.53(h)(1), Part 22.917(b), and Part 24.238(b), emission bandwidth is the width of the signal between two points, one below the carrier center frequency and one above the carrier center frequency, outside of which all emissions are attenuated at least 26 dB below the transmitter power. Based on the 26 dB emission bandwidth, 1% of the 873.2 kHz (the lesser of the 2 plots below) is approximately 8.73 kHz. Therefore, resolution bandwidth of 10kHz can be appropriately used for measuring band edge plots that is immediately outside and adjacent to the licensee's frequency block where LTE is operating with 1RB.



Plot 11-1 Resource Block size = 1, Resource Block offset = 0

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
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Plot 11-2 Resource Block size = 1, Resource Block offset = 49

FCC ID: A3LSCHI405U	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22-24-27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
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12.0 CONCLUSION

The data collected relate only to the item(s) tested and show that the **Samsung Portable Handset FCC ID: A3LSCHI405U** complies with all the requirements of Parts 2, 22, 24 and 27 of the FCC rules for LTE operation only.

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